RF Test Report

For

Applicant Name:	**Hangzhou Lawaken Technology Co., Ltd.**
Address:	No.1312, Building 19, Shidaitianyuancheng Cangqian St., Yuhang District Hangzhou, Zhejiang
EUT Name:	AR Glass
Brand Name:	Lawaken
Model Number:	LAWK-ML-S3

Issued By

Company Name:	**BTF Testing Lab (Shenzhen) Co., Ltd.**
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Report Number:	BTF240116R00401
Test Standards:	47 CFR Part 15.247
Test Conclusion:	Pass
FCC ID:	2BEOP-LAWKMLS3
Test Date:	2024-01-17 to 2024-01-30
Date of Issue:	2024-01-31

Prepared By: Gavin Cui

Gavin Cui / Project Engineer

Date: 2024-01-31

Approved By: Ryan.CJ

Ryan.CJ / EMC Manager

Date: 2024-01-31

Note: All the test results in this report only related to the testing samples. Which can be duplicated completely for the legal use with approval of applicant; it shall not be reproduced except in full without the written approval of BTF Testing Lab (Shenzhen) Co., Ltd., All the objections should be raised within thirty days from the date of issue. To validate the report, you can contact us.

Revision History		
Version	Issue Date	Revisions Content
R_V0	2024-01-31	Original
Note: Once the revision has been made, then previous versions reports are invalid.		

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Table of Contents

1 INTRODUCTION 5
1.1 Identification of Testing Laboratory 5
1.2 Identification of the Responsible Testing Location 5
1.3 Announcement 5
2 PRODUCT INFORMATION 6
2.1 Application Information 6
2.2 Manufacturer Information 6
2.3 Factory Information 6
2.4 General Description of Equipment under Test (EUT) 6
2.5 Technical Information 6
3 SUMMARY OF TEST RESULTS 7
3.1 Test Standards 7
3.2 Uncertainty of Test 7
3.3 Summary of Test Result 7
4 TEST CONFIGURATION 8
4.1 Test Equipment List 8
4.2 Test Auxiliary Equipment 10
4.3 Test Modes 10
5 EVALUATION RESULTS (EVALUATION) 11
5.1 Antenna requirement 11
6 RADIO SPECTRUM MATTER TEST RESULTS (RF) 12
6.1 Conducted Emission at AC power line 12
6.1.1 E.U.T. Operation: 12
6.1.2 Test Setup Diagram: 12
6.1.3 Test Data: 13
6.2 Occupied Bandwidth 15
6.2.1 E.U.T. Operation: 16
6.2.2 Test Setup Diagram: 16
6.2.3 Test Data: 17
6.3 Maximum Conducted Output Power 18
6.3.1 E.U.T. Operation: 18
6.3.2 Test Setup Diagram: 19
6.3.3 Test Data: 19
6.4 Channel Separation 20
6.4.1 E.U.T. Operation: 20
6.4.2 Test Setup Diagram: 20
6.4.3 Test Data: 21
6.5 Number of Hopping Frequencies 22
6.5.1 E.U.T. Operation: 22
6.5.2 Test Setup Diagram: 22
6.5.3 Test Data: 23
6.6 Dwell Time 24
6.6.1 E.U.T. Operation: 25
6.6.2 Test Setup Diagram: 25
6.6.3 Test Data: 26
6.7 Emissions in non-restricted frequency bands 27
6.7.1 E.U.T. Operation: 28
6.7.2 Test Setup Diagram: 28
6.7.3 Test Data: 28

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.8 Band edge emissions (Radiated) 29
6.8.1 E.U.T. Operation: 29
6.8.2 Test Setup Diagram: 29
6.8.3 Test Data: 30
6.9 Emissions in frequency bands (below 1GHz) 31
6.9.1 E.U.T. Operation: 31
6.9.2 Test Setup Diagram: 31
6.9.3 Test Data: 32
6.10 Emissions in frequency bands (above 1GHz) 34
6.10.1 E.U.T. Operation: 34
6.10.2 Test Setup Diagram: 34
6.10.3 Test Data: 35
7 TEST SETUP PHOTOS 37
8 EUT CONSTRUCTIONAL DETAILS (EUT PHOTOS) 39
APPENDIX 47

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

1 Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130
FCC Registration Number:	518915
Designation Number:	CN1330

1.3 Announcement

(1) The test report reference to the report template version v0.
(2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
(3) The test report is invalid if there is any evidence and/or falsification.
(4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.
(5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
(6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

2 Product Information

2.1 Application Information

Company Name:	Hangzhou Lawaken Technology Co., Ltd.
Address:	No.1312, Building 19, Shidaitianyuancheng Cangqian St., Yuhang District Hangzhou, Zhejiang

2.2 Manufacturer Information

Company Name:	Hangzhou Lawaken Technology Co., Ltd.
Address:	No.1312, Building 19, Shidaitianyuancheng Cangqian St., Yuhang District Hangzhou, Zhejiang

2.3 Factory Information

Company Name:	Tonly Technology Co., Ltd.
Address:	Section 37, Zhongkai High-tech Development Zone, Huizhou City, Guangdong Province, P.R. China

2.4 General Description of Equipment under Test (EUT)

EUT Name:	AR Glass
Test Model Number:	LAWK-ML-S3
Software Version:	lawk_dldtool_user_2700_378_r412_r66_en
Hardware Version:	400802-062118

2.5 Technical Information

Rating:	Input: DC 5V, 1.5A DC 3.85V From Battery
Operation Frequency:	2402MHz to 2480MHz
Number of Channels:	79
Modulation Type:	GFSK, π/4 DQPSK, 8DPSK
Antenna Type:	FPC Antenna
Antenna Gain#:	1.79dBi
Note: #: The antenna gain provided by the applicant, and the laboratory will not be responsible for the accumulated calculation results which covers the information provided by the applicant.	

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

3 Summary of Test Results

3.1 Test Standards

The tests were performed according to following standards:
47 CFR Part 15.247: Operation within the bands 902-928 MHz, 2400-2483.5 MHz, and 5725-5850 MHz

3.2 Uncertainty of Test

Item	Measurement Uncertainty
Conducted Emission (150 kHz-30 MHz)	±2.64dB
Occupied Bandwidth	±69kHz
Transmitter Power, Conducted	±0.87dB
Conducted Spurious Emissions	±0.95dB
Radiated Spurious Emissions (above 1GHz)	1-6GHz: ±3.94dB 6-18GHz: ±4.16dB
Radiated Spurious Emissions (30M - 1GHz)	±4.12dB
The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.	

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Antenna requirement	47 CFR Part 15.247	47 CFR 15.203	Pass
Conducted Emission at AC power line	47 CFR Part 15.247	47 CFR 15.207(a)	Pass
Occupied Bandwidth	47 CFR Part 15.247	47 CFR 15.215(c)	Pass
Maximum Conducted Output Power	47 CFR Part 15.247	47 CFR 15.247(b)(1)	Pass
Channel Separation	47 CFR Part 15.247	47 CFR 15.247(a)(1)	Pass
Number of Hopping Frequencies	47 CFR Part 15.247	47 CFR 15.247(a)(1)(iii)	Pass
Dwell Time	47 CFR Part 15.247	47 CFR 15.247(a)(1)(iii)	Pass
Emissions in non-restricted frequency bands	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass
Band edge emissions (Radiated)	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass
Emissions in frequency bands (below 1GHz)	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass
Emissions in frequency bands (above 1GHz)	47 CFR Part 15.247	47 CFR 15.247(d), 15.209, 15.205	Pass

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

4 Test Configuration

4.1 Test Equipment List

Conducted Emission at AC power line					
Equipment	**Manufacturer**	**Model No**	**Inventory No**	**Cal Date**	**Cal Due Date**
Pulse Limiter	SCHWARZBECK	VTSD 9561-F	00953	/	/
Coaxial Switcher	SCHWARZBECK	CX210	CX210	/	/
V-LISN	SCHWARZBECK	NSLK 8127	01073	2023-11-16	2024-11-15
LISN	AFJ	LS16/110VAC	16010020076	2023-02-23	2024-02-22
EMI Receiver	ROHDE&SCHWARZ	ESCI3	101422	2023-11-15	2024-11-14

Occupied Bandwidth Maximum Conducted Output Power Channel Separation Number of Hopping Frequencies Dwell Time Emissions in non-restricted frequency bands					
Equipment	**Manufacturer**	**Model No**	**Inventory No**	**Cal Date**	**Cal Due Date**
RFTest software	/	V1.00	/	/	/
RF Control Unit	Techy	TR1029-1	/	/	/
RF Sensor Unit	Techy	TR1029-2	/	/	/
Programmable constant temperature and humidity box	ZZCKONG	ZZ-K02A	20210928007	2023-11-16	2024-11-15
Adjustable Direct Current Regulated Power Supply	Dongguan Tongmen Electronic Technology Co., LTD	etm-6050c	20211026123	/	/
WIDEBAND RADIO COMMNUNICATION TESTER	Rohde & Schwarz	CMW500	161997	2023-11-16	2024-11-15
MXA Signal Analyzer	KEYSIGHT	N9020A	MY50410020	2023-11-16	2024-11-15

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Band edge emissions (Radiated) Emissions in frequency bands (below 1GHz) Emissions in frequency bands (above 1GHz)					
Equipment	**Manufacturer**	**Model No**	**Inventory No**	**Cal Date**	**Cal Due Date**
Coaxial cable Multiflex 141	Schwarzbeck	N/SMA 0.5m	517386	2023-03-24	2024-03-23
Preamplifier	SCHWARZBECK	BBV9744	00246	/	/
RE Cable	REBES Talent	UF1-SMASMAM-10m	21101566	/	/
RE Cable	REBES Talent	UF2-NMNM-10m	21101570	/	/
RE Cable	REBES Talent	UF1-SMASMAM-1m	21101568	/	/
RE Cable	REBES Talent	UF2-NMNM-1m	21101576	/	/
RE Cable	REBES Talent	UF2-NMNM-2.5m	21101573	/	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Horn Antenna	SCHWARZBECK	BBHA9170	01157	2023-11-13	2024-11-12
EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCI7	101032	2023-11-16	2024-11-15
SIGNAL ANALYZER	ROHDE&SCHWARZ	FSQ40	100010	2023-11-16	2024-11-15
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Broadband Preamplilifier	SCHWARZBECK	BBV9718D	00008	2023-03-24	2024-03-23
Horn Antenna	SCHWARZBECK	BBHA9120D	2597	2022-05-22	2024-05-21
EZ_EMC	Frad	FA-03A2 RE+	/	/	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	/	/	/
Log periodic antenna	SCHWARZBECK	VULB 9168	01328	2023-11-13	2024-11-12

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

4.2 Test Auxiliary Equipment

The EUT was tested as an independent device.

4.3 Test Modes

No.	Test Modes	Description
TM1	TX-GFSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with GFSK modulation.
TM2	TX-Pi/4DQPSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with Pi/4DQPSK modulation.
TM3	TX-8DPSK (Non-Hopping)	Keep the EUT in continuously transmitting mode (non-hopping) with 8DPSK modulation.
TM4	TX-GFSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with GFSK modulation,.
TM5	TX-Pi/4DQPSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with Pi/4DQPSK modulation.
TM6	TX-8DPSK (Hopping)	Keep the EUT in continuously transmitting mode (hopping) with 8DPSK modulation.

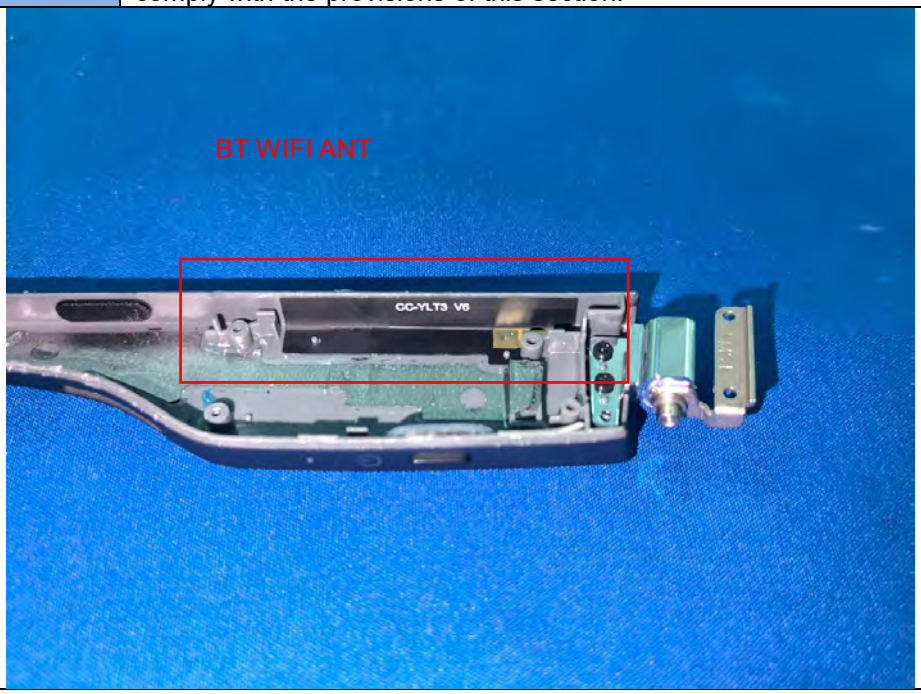
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

5 Evaluation Results (Evaluation)

5.1 Antenna requirement

Test Requirement:	Refer to 47 CFR Part 15.203, an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6 Radio Spectrum Matter Test Results (RF)

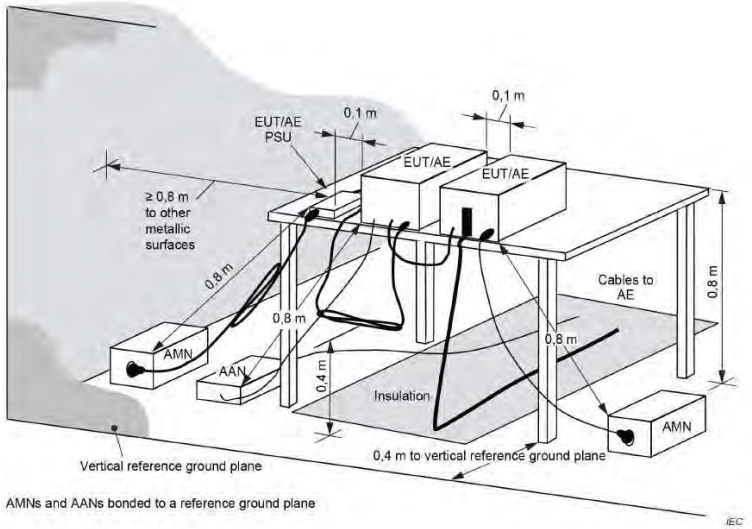
6.1 Conducted Emission at AC power line

Test Requirement:	Refer to 47 CFR 15.207(a), Except as shown in paragraphs (b)and (c)of this section, for an intentional radiator that is designed to be connected to the public utility (AC) power line, the radio frequency voltage that is conducted back onto the AC power line on any frequency or frequencies, within the band 150 kHz to 30 MHz, shall not exceed the limits in the following table, as measured using a 50 μH/50 ohms line impedance stabilization network (LISN).
Test Method:	ANSI C63.10-2013 section 6.2 ANSI C63.10-2020 section 6.2
Test Limit:	Frequency of emission (MHz) / Conducted limit (dBμV): Quasi-peak / Average 0.15-0.5: 66 to 56* / 56 to 46* 0.5-5: 56 / 46 5-30: 60 / 50 *Decreases with the logarithm of the frequency.
Procedure:	Refer to ANSI C63.10-2013 section 6.2, standard test method for ac power-line conducted emissions from unlicensed wireless devices Refer to ANSI C63.10-2020 section 6.2, standard test method for ac power-line conducted emissions from unlicensed wireless devices

6.1.1 E.U.T. Operation:

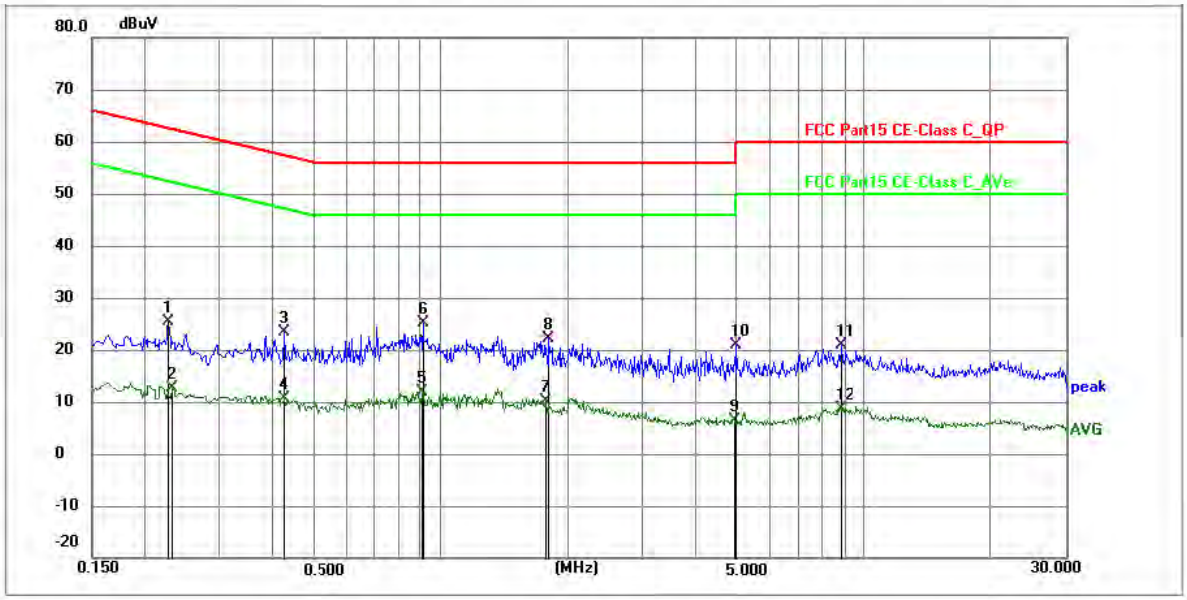
Operating Environment:	
Temperature:	25.3 °C
Humidity:	49 %
Atmospheric Pressure:	1010 mbar

6.1.2 Test Setup Diagram:



6.1.3 Test Data:

TM1 / Line: Line / Band: 2400-2483.5 MHz / BW: 1 / CH: M

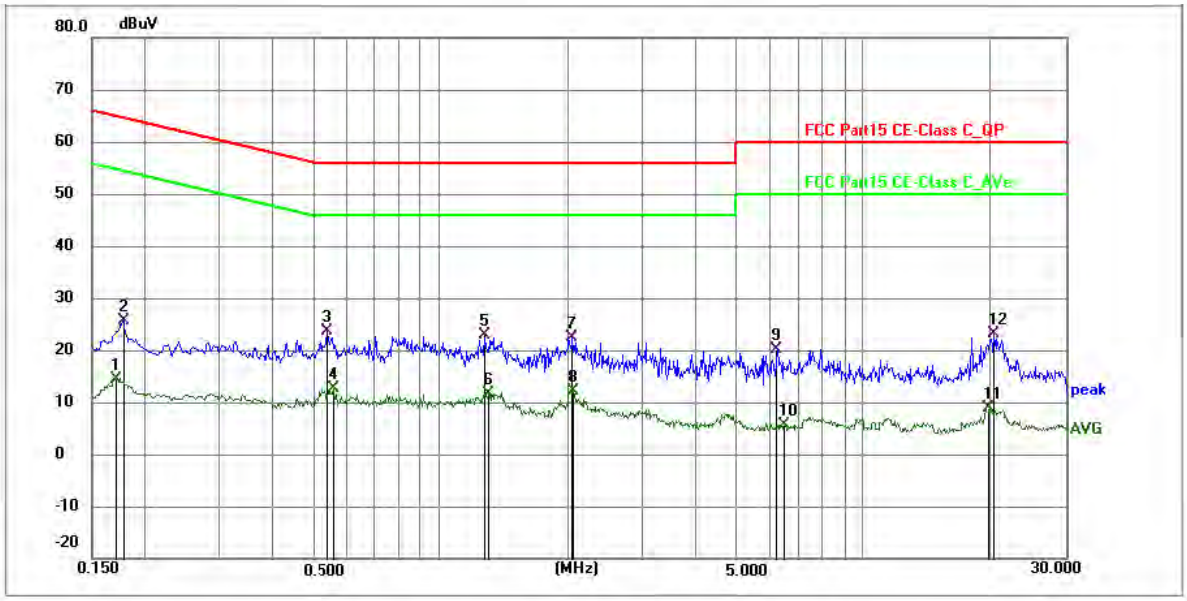


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.2265	14.70	10.56	25.26	62.58	-37.32	QP	P	
2	0.2310	1.96	10.56	12.52	52.41	-39.89	AVG	P	
3	0.4243	12.93	10.57	23.50	57.36	-33.86	QP	P	
4	0.4243	0.00	10.57	10.57	47.36	-36.79	AVG	P	
5	0.9060	1.16	10.67	11.83	46.00	-34.17	AVG	P	
6 *	0.9102	14.52	10.67	25.19	56.00	-30.81	QP	P	
7	1.7790	-0.56	10.67	10.11	46.00	-35.89	AVG	P	
8	1.8015	11.43	10.67	22.10	56.00	-33.90	QP	P	
9	4.9290	-4.42	10.73	6.31	46.00	-39.69	AVG	P	
10	5.0010	10.08	10.73	20.81	60.00	-39.19	QP	P	
11	8.8392	10.10	10.82	20.92	60.00	-39.08	QP	P	
12	8.8392	-2.25	10.82	8.57	50.00	-41.43	AVG	P	

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

TM1 / Line: Neutral / Band: 2400-2483.5 MHz / BW: 1 / CH: M



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1	0.1720	3.94	10.49	14.43	54.86	-40.43	AVG	P	
2	0.1770	15.14	10.51	25.65	64.63	-38.98	QP	P	
3 *	0.5413	12.92	10.60	23.52	56.00	-32.48	QP	P	
4	0.5594	2.01	10.61	12.62	46.00	-33.38	AVG	P	
5	1.2702	12.30	10.66	22.96	56.00	-33.04	QP	P	
6	1.2975	0.95	10.66	11.61	46.00	-34.39	AVG	P	
7	2.0490	11.71	10.68	22.39	56.00	-33.61	QP	P	
8	2.0625	1.44	10.68	12.12	46.00	-33.88	AVG	P	
9	6.2204	9.48	10.77	20.25	60.00	-39.75	QP	P	
10	6.4725	-5.10	10.78	5.68	50.00	-44.32	AVG	P	
11	19.8733	-2.17	11.04	8.87	50.00	-41.13	AVG	P	
12	20.3730	11.96	11.06	23.02	60.00	-36.98	QP	P	

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.2 Occupied Bandwidth

Test Requirement:	47 CFR 15.215(c)
Test Method:	ANSI C63.10-2013, section 7.8.7, For occupied bandwidth measurements, use the procedure in 6.9.2. ANSI C63.10-2020, section 7.8.6, For occupied bandwidth measurements, use the procedure in 6.9.3. Frequency hopping shall be disabled for this test. KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.215(c), intentional radiators operating under the alternative provisions to the general emission limits, as contained in §§ 15.217 through 15.257 and in subpart E of this part, must be designed to ensure that the 20 dB bandwidth of the emission, or whatever bandwidth may otherwise be specified in the specific rule section under which the equipment operates, is contained within the frequency band designated in the rule section under which the equipment is operated.
Procedure:	a) The spectrum analyzer center frequency is set to the nominal EUT channel center frequency. The span range for the EMI receiver or spectrum analyzer shall be between two times and five times the OBW. b) The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW and video bandwidth (VBW) shall be approximately three times RBW, unless otherwise specified by the applicable requirement. c) Set the reference level of the instrument as required, keeping the signal from exceeding the maximum input mixer level for linear operation. In general, the peak of the spectral envelope shall be more than [10 log (OBW/RBW)] below the reference level. Specific guidance is given in 4.1.5.2. d) Steps a) through c) might require iteration to adjust within the specified tolerances. e) The dynamic range of the instrument at the selected RBW shall be more than 10 dB below the target –xx dB down" requirement; that is, if the requirement calls for measuring the −20 dB OBW, the instrument noise floor at the selected RBW shall be at least 30 dB below the reference value. f) Set detection mode to peak and trace mode to max hold. g) Determine the reference value: Set the EUT to transmit an unmodulated carrier or modulated signal, as applicable. Allow the trace to stabilize. Set the spectrum analyzer marker to the highest level of the displayed trace (this is the reference value). h) Determine the —xx dB down amplitude" using [(reference value) − xx]. Alternatively, this calculation may be made by using the marker-delta function of the instrument. i) If the reference value is determined by an unmodulated carrier, then turn the EUT modulation ON, and either clear the existing trace or start a new trace on the spectrum analyzer and allow the new trace to stabilize. Otherwise, the trace from step g) shall be used for step j). j) Place two markers, one at the lowest frequency and the other at the highest frequency of the envelope of the spectral display, such that each marker is at or slightly below the –xx dB down amplitude" determined in step h). If a marker is below this –xx dB down amplitude" value, then it shall be as close as possible to this value. The occupied bandwidth is the frequency difference between the two markers. Alternatively, set a marker at the lowest frequency of the envelope of the spectral display, such that the marker is at or slightly below the –xx dB down amplitude" determined in step h). Reset the marker-delta function and move the marker to the other side of the emission until the delta marker amplitude is at the same level as the reference marker amplitude. The marker-delta frequency reading at this point is the specified emission bandwidth. k) The occupied bandwidth shall be reported by providing plot(s) of the measuring instrument display; the plot axes and the scale units per division shall be clearly

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

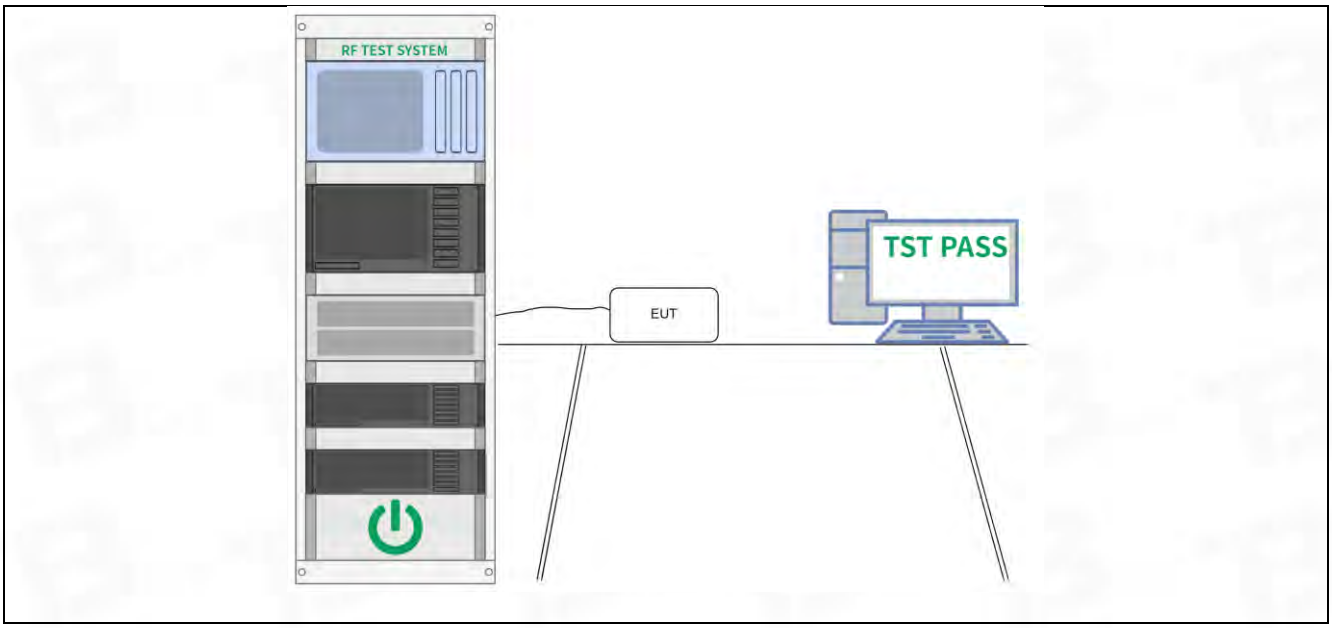
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

	labeled. Tabular data may be reported in addition to the plot(s). The occupied bandwidth is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers are each equal to 0.5% of the total mean power of the given emission. The following procedure shall be used for measuring 99% power bandwidth: a) The instrument center frequency is set to the nominal EUT channel center frequency. The frequency span for the spectrum analyzer shall be between 1.5 times and 5.0 times the OBW. b) The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW, and VBW shall be at least three times the RBW, unless otherwise specified by the applicable requirement. c) Set the reference level of the instrument as required, keeping the signal from exceeding the maximum input mixer level for linear operation. In general, the peak of the spectral envelope shall be more than [10 log (OBW/RBW)] below the reference level. Specific guidance is given in 4.1.6.2. d) Step a) through step c) might require iteration to adjust within the specified range. e) Video averaging is not permitted. Where practical, a sample detection and single sweep mode shall be used. Otherwise, peak detection and max-hold mode (until the trace stabilizes) shall be used. f) Use the 99% power bandwidth function of the instrument (if available) and report the measured bandwidth. g) If the instrument does not have a 99% power bandwidth function, then the trace data points are recovered and directly summed in linear power terms. The recovered amplitude data points, beginning at the lowest frequency, are placed in a running sum until 0.5% of the total is reached; that frequency is recorded as the lower frequency. The process is repeated until 99.5% of the total is reached; that frequency is recorded as the upper frequency. The 99% power bandwidth is the difference between these two frequencies. h) The occupied bandwidth shall be reported by providing spectral plot(s) of the measuring instrument display; the plot axes and the scale units per division shall be clearly labeled. Tabular data may be reported in addition to the plot(s).

6.2.1 E.U.T. Operation:

Operating Environment:	
Temperature:	23.4 °C
Humidity:	46.4 %
Atmospheric Pressure:	1010 mbar

6.2.2 Test Setup Diagram:



6.2.3 Test Data:

Please Refer to Appendix for Details.

6.3 Maximum Conducted Output Power

Test Requirement:	47 CFR 15.247(b)(1)
Test Method:	ANSI C63.10-2013, section 7.8.5 ANSI C63.10-2020, section 7.8.5 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(b)(1), For frequency hopping systems operating in the 2400-2483.5 MHz band employing at least 75 non-overlapping hopping channels, and all frequency hopping systems in the 5725-5850 MHz band: 1 watt. For all other frequency hopping systems in the 2400-2483.5 MHz band: 0.125 watts.
Procedure:	This is an RF-conducted test to evaluate maximum peak output power. Use a direct connection between the antenna port of the unlicensed wireless device and the spectrum analyzer, through suitable attenuation. The hopping shall be disabled for this test: a) Use the following spectrum analyzer settings: 1) Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel. 2) RBW > 20 dB bandwidth of the emission being measured. 3) VBW >= RBW. 4) Sweep: Auto. 5) Detector function: Peak. 6) Trace: Max hold. b) Allow trace to stabilize. c) Use the marker-to-peak function to set the marker to the peak of the emission. d) The indicated level is the peak output power, after any corrections for external attenuators and cables. e) A plot of the test results and setup description shall be included in the test report. NOTE—A peak responding power meter may be used, where the power meter and sensor system video bandwidth is greater than the occupied bandwidth of the unlicensed wireless device, rather than a spectrum analyzer. This is an RF-conducted test to evaluate maximum peak output power. Use a direct connection between the antenna port of the unlicensed wireless device and the spectrum analyzer, through suitable attenuation. Frequency hopping shall be disabled for this test. Use the following spectrum analyzer settings: a) Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel. b) RBW > 20 dB bandwidth of the emission being measured. c) VBW ≥ RBW. d) Sweep: No faster than coupled (auto) time. e) Detector function: Peak. f) Trace: Max-hold. g) Allow trace to stabilize. h) Use the marker-to-peak function to set the marker to the peak of the emission. i) The indicated level is the peak output power, after any corrections for external attenuators and cables. j) A spectral plot of the test results and setup description shall be included in the test report. NOTE—A peak responding power meter may be used, where the power meter and sensor system video bandwidth is greater than the occupied bandwidth of the unlicensed wireless device, rather than a spectrum analyzer.

6.3.1 E.U.T. Operation:

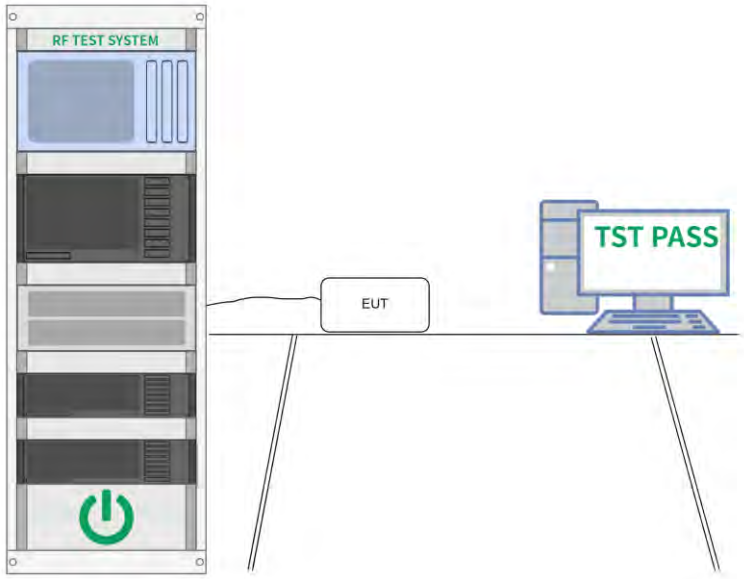
Operating Environment:	
Temperature:	23.4 °C
Humidity:	46.4 %

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Atmospheric Pressure:	1010 mbar

6.3.2 Test Setup Diagram:



6.3.3 Test Data:

Please Refer to Appendix for Details.

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.4 Channel Separation

Test Requirement:	47 CFR 15.247(a)(1)
Test Method:	ANSI C63.10-2013, section 7.8.2 ANSI C63.10-2020, section 7.8.2 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(a)(1), Frequency hopping systems shall have hopping channel carrier frequencies separated by a minimum of 25 kHz or the 20 dB bandwidth of the hopping channel, whichever is greater. Alternatively, frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, whichever is greater, provided the systems operate with an output power no greater than 125 mW.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Wide enough to capture the peaks of two adjacent channels. b) RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel. c) Video (or average) bandwidth (VBW) ≥ RBW. d) Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels. Compliance of an EUT with the appropriate regulatory limit shall be determined. A plot of the data shall be included in the test report. The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Wide enough to capture the peaks of two adjacent channels. b) RBW: Start with the RBW set to approximately 30% of the channel spacing; adjust as necessary to best identify the center of each individual channel. c) Video (or average) bandwidth (VBW) ≥ RBW. d) Sweep: No faster than coupled (auto) time. e) Detector function: Peak. f) Trace: Max-hold. g) Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels. Compliance of an EUT with the appropriate regulatory limit shall be determined. A spectral plot of the data shall be included in the test report.

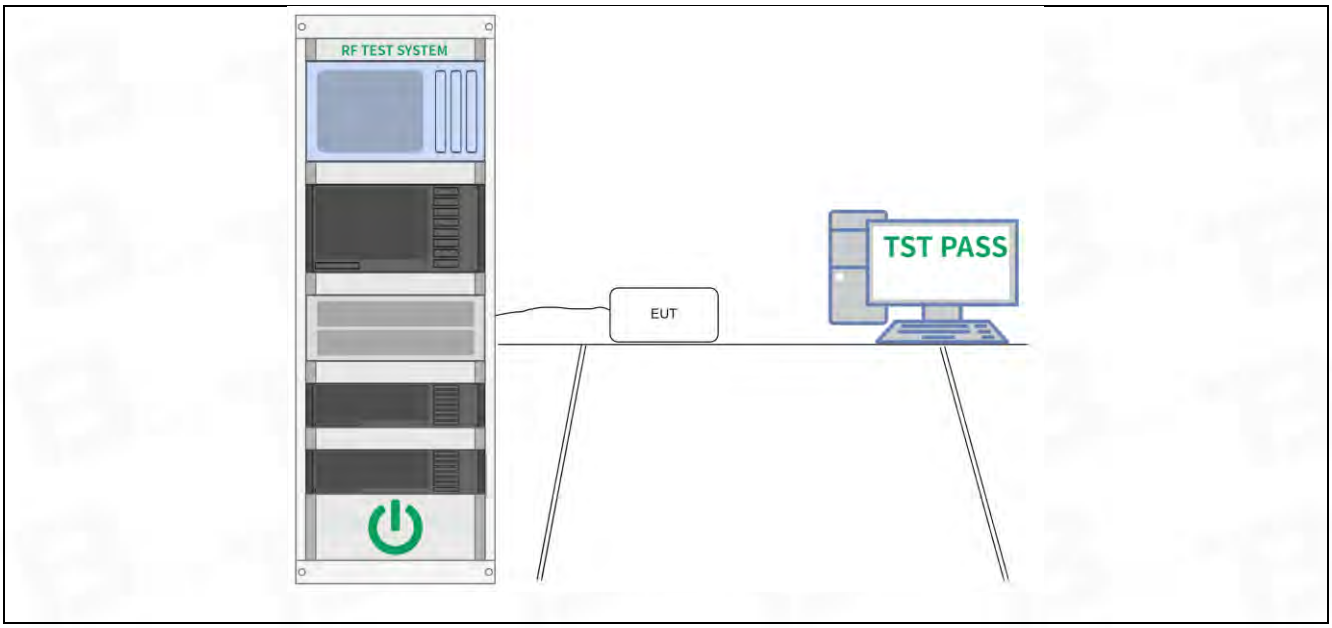
6.4.1 E.U.T. Operation:

Operating Environment:	
Temperature:	23.4 °C
Humidity:	46.4 %
Atmospheric Pressure:	1010 mbar

6.4.2 Test Setup Diagram:

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China



6.4.3 Test Data:

Please Refer to Appendix for Details.

6.5 Number of Hopping Frequencies

Test Requirement:	47 CFR 15.247(a)(1)(iii)
Test Method:	ANSI C63.10-2013, section 7.8.3 ANSI C63.10-2020, section 7.8.3 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(a)(1)(iii), Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: The frequency band of operation. Depending on the number of channels the device supports, it may be necessary to divide the frequency range of operation across multiple spans, to allow the individual channels to be clearly seen. b) RBW: To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller. c) VBW ≥ RBW. d) Sweep: Auto. e) Detector function: Peak. f) Trace: Max hold. g) Allow the trace to stabilize. It might prove necessary to break the span up into subranges to show clearly all of the hopping frequencies. Compliance of an EUT with the appropriate regulatory limit shall be determined for the number of hopping channels. A plot of the data shall be included in the test report. The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: The frequency band of operation. Depending on the number of channels the device supports, it could be necessary to divide the frequency range of operation across multiple spans, to allow the individual channels to be clearly seen. b) RBW: To identify clearly the individual channels, set the RBW to less than 30% of the channel spacing or the 20 dB bandwidth, whichever is smaller. c) VBW ≥ RBW. d) Sweep: No faster than coupled (auto) time. e) Detector function: Peak. f) Trace: Max-hold. g) Allow the trace to stabilize. It might prove necessary to break the span up into subranges to show clearly all of the hopping frequencies. Compliance of an EUT with the appropriate regulatory limit shall be determined for the number of hopping channels. A spectral plot of the data shall be included in the test report.

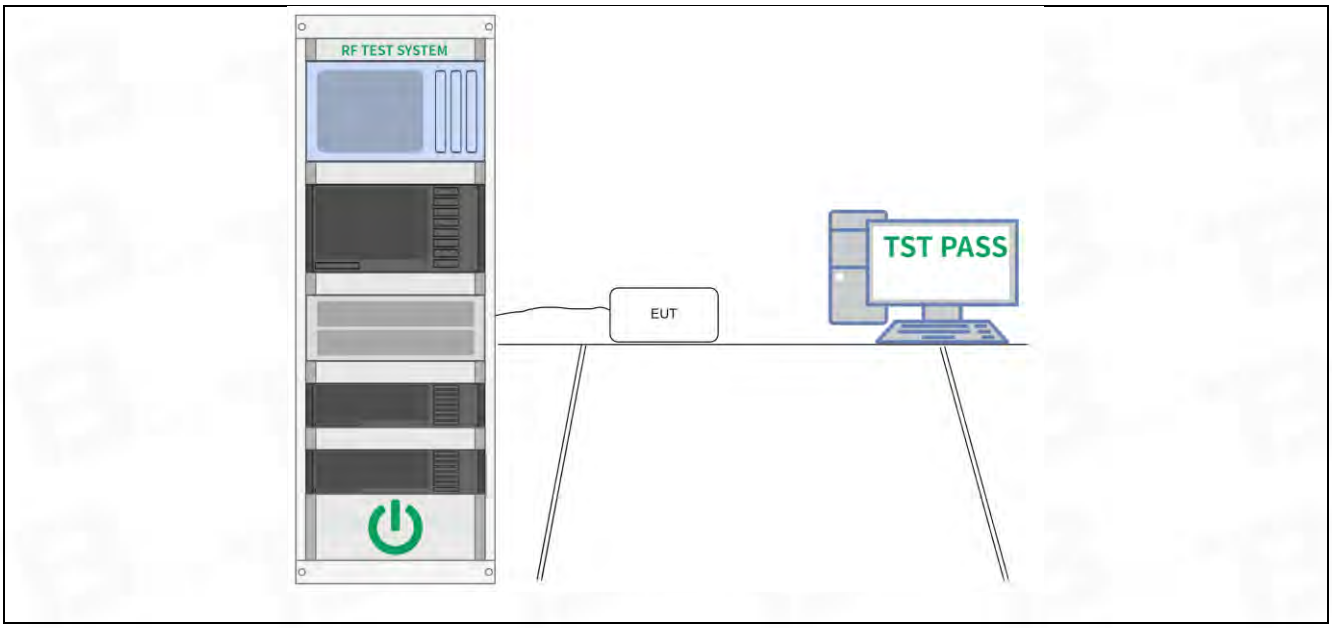
6.5.1 E.U.T. Operation:

Operating Environment:	
Temperature:	23.4 °C
Humidity:	46.4 %
Atmospheric Pressure:	1010 mbar

6.5.2 Test Setup Diagram:

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China



6.5.3 Test Data:

Please Refer to Appendix for Details.

6.6 Dwell Time

Test Requirement:	47 CFR 15.247(a)(1)(iii)
Test Method:	ANSI C63.10-2013, section 7.8.4 ANSI C63.10-2020, section 7.8.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(a)(1)(iii), Fequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed. Frequency hopping systems may avoid or suppress transmissions on a particular hopping frequency provided that a minimum of 15 channels are used.
Procedure:	The EUT shall have its hopping function enabled. Use the following spectrum analyzer settings: a) Span: Zero span, centered on a hopping channel. b) RBW shall be <= channel spacing and where possible RBW should be set >> 1 / T, where T is the expected dwell time per channel. c) Sweep: As necessary to capture the entire dwell time per hopping channel; where possible use a video trigger and trigger delay so that the transmitted signal starts a little to the right of the start of the plot. The trigger level might need slight adjustment to prevent triggering when the system hops on an adjacent channel; a second plot might be needed with a longer sweep time to show two successive hops on a channel. d) Detector function: Peak. e) Trace: Max hold. Use the marker-delta function to determine the transmit time per hop. If this value varies with different modes of operation (data rate, modulation format, number of hopping channels, etc.), then repeat this test for each variation in transmit time. Repeat the measurement using a longer sweep time to determine the number of hops over the period specified in the requirements. The sweep time shall be equal to, or less than, the period specified in the requirements. Determine the number of hops over the sweep time and calculate the total number of hops in the period specified in the requirements, using the following equation: (Number of hops in the period specified in the requirements) = (number of hops on spectrum analyzer) × (period specified in the requirements / analyzer sweep time) The average time of occupancy is calculated from the transmit time per hop multiplied by the number of hops in the period specified in the requirements. If the number of hops in a specific time varies with different modes of operation (data rate, modulation format, number of hopping channels, etc.), then repeat this test for each variation. The measured transmit time and time between hops shall be consistent with the values described in the operational description for the EUT. The dwell time per hop on a channel is the time from the start of the first transmission to the end of the last transmission for that hop. If the device has a single transmission per hop then the dwell time is the duration of that transmission. If the device has a multiple transmissions per hop then the dwell time is measured from the start of the first transmission to the end of the last transmission. The time of occupancy is the total time that the device dwells on a channel over an observation period specified in the regulatory requirement. To determine the time of occupancy the spectrum analyzer will be configured to measure both the dwell time per hop and the number of times the device transmits on a specific channel in a given period.

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

	The EUT shall have its hopping function enabled. Compliance with the requirements shall be made with the minimum and with the maximum number of channels enabled. If the dwell time per channel does not vary with the number of channels than compliance with the requirements may be based on the minimum number of channels. If the device supports different dwell times per channel (example Bluetooth devices can dwell on a channel for 1, 3 or 5 time slots) then measurements can be limited to the longest dwell time with the minimum number of channels. Use the following spectrum analyzer settings to determine the dwell time per hop: a) Span: Zero span, centered on a hopping channel. b) RBW shall be ≤ channel spacing and where possible RBW should be set >> 1 / T, where T is the expected transmission time per hop. c) Sweep time: Set so that the start of the first transmission and end of the last transmission for the hop are clearly captured. Setting the sweep time to be slightly longer than the hopping period per channel (hopping period = 1/hopping rate) should achieve this. d) Use a video trigger, where possible with a trigger delay, so that the start of the transmission is clearly observed. The trigger level might need adjustment to reduce the chance of triggering when the system hops on an adjacent channel. e) Detector function: Peak. f) Trace: Clear-write, single sweep. g) Place markers at the start of the first transmission on the channel and at the end of the last transmission. The dwell time per hop is the time between these two markers. To determine the number of hops on a channel in the regulatory observation period repeat the measurement using a longer sweep time. When the device uses a single hopping sequence the period of measurement should be sufficient to capture at least 2 hops. When the device uses a dynamic hopping sequence, or the sequence varies, the period of measurement may need to capture multiple hops to better determine the average time of occupancy. Count the number of hops on the channel across the sweep time. The average number of hops on the same channel within the regulatory observation period is calculated from the number of hops on the channel divided by the spectrum analyzer sweep time multiplied by the regulatory observation period. For example, if three hops are counted with an analyzer sweep time of 500 ms and the regulatory observation period is 10 s, then the number of hops in that ten seconds is 3 / 0.5 × 10, or 60 hops. The average time of occupancy is calculated by multiplying the dwell time per hop by the number of hops in the observation period.

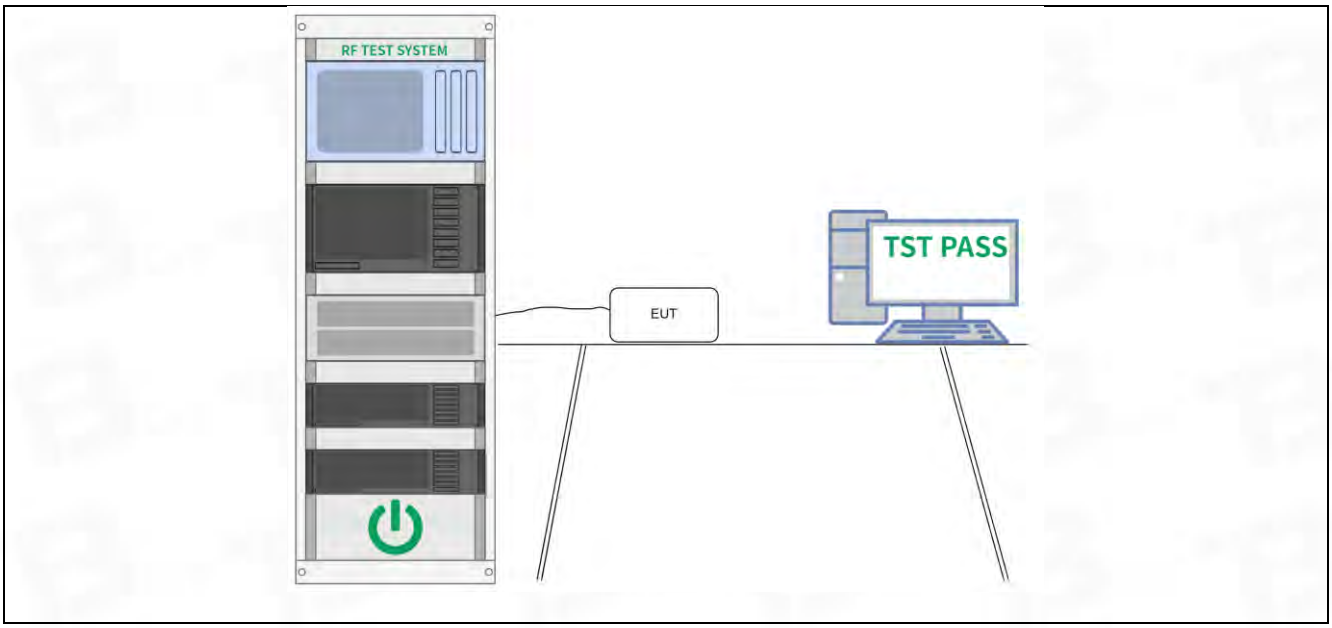
6.6.1 E.U.T. Operation:

Operating Environment:	
Temperature:	23.4 °C
Humidity:	46.4 %
Atmospheric Pressure:	1010 mbar

6.6.2 Test Setup Diagram:

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China



6.6.3 Test Data:

Please Refer to Appendix for Details.

6.7 Emissions in non-restricted frequency bands

Test Requirement:	47 CFR 15.247(d), 15.209, 15.205
Test Method:	ANSI C63.10-2013 section 7.8.8 ANSI C63.10-2020 section 7.8.7 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	Refer to 47 CFR 15.247(d), In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in § 15.209(a) is not required.
Procedure:	Conducted spurious emissions shall be measured for the transmit frequency, per 5.5 and 5.6, and at the maximum transmit powers. Connect the primary antenna port through an attenuator to the spectrum analyzer input; in the results, account for all losses between the unlicensed wireless device output and the spectrum analyzer. The instrument shall span 30 MHz to 10 times the operating frequency in GHz, with a resolution bandwidth of 100 kHz, video bandwidth of 300 kHz, and a coupled sweep time with a peak detector. The band 30 MHz to the highest frequency may be split into smaller spans, as long as the entire spectrum is covered. 7.8.7.1 General considerations To demonstrate compliance with the relative out-of-band emissions requirements conducted spurious emissions shall be measured for the transmit frequencies, per 5.5 and 5.6, and at the maximum transmit powers. Frequency hopping shall be disabled for this test with the exception of measurements at the allocated band-edges which shall be repeated with hopping enabled. Connect the primary antenna port through an attenuator to the spectrum analyzer input; in the results, account for all losses between the unlicensed wireless device output and the spectrum analyzer. The frequency range of testing shall span 30 MHz to 10 times the operating frequency and this may be done in a single sweep or, to aid resolution, across a number of sweeps. The resolution bandwidth shall be 100 kHz, video bandwidth 300 kHz, and a coupled sweep time with a peak detector. The limit is based on the highest in-band level across all channels measured using the same instrument settings (resolution bandwidth of 100 kHz, video bandwidth of 300 kHz, and a coupled sweep time with a peak detector). To help clearly demonstrate compliance a display line may be set at the required offset (typically 20 dB) below the highest in-band level. Where the highest in-band level is not clearly identified in the out-of-band measurements a separate spectral plot showing the in-band level shall be provided. When conducted measurements cannot be made (for example a device with integrated, non-removable antenna) radiated measurements shall be used. The reference level for determining the limit shall be established by maximizing the field strength from the highest power channel and measuring using the resolution and video bandwidth settings and peak detector as described above. The field strength limit for spurious emissions outside of restricted-bands shall then be set at the required offset (typically 20 dB) below the highest in-band level. Radiated

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

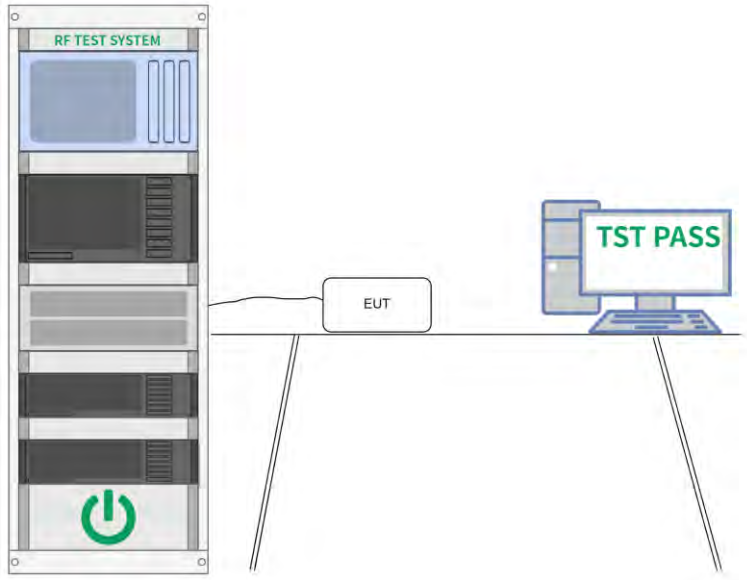
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

	measurements will follow the standards measurement procedures described in Clause 6 with the exception that the resolution bandwidth shall be 100 kHz, video bandwidth 300 kHz, and a coupled sweep time with a peak detector. Note that use of wider measurement bandwidths are acceptable for measuring the spurious emissions provided that the peak detector is used and that the measured value of spurious emissions are compared to the highest in-band level measured with the 100 kHz / 300 kHz bandwidth settings to determine compliance. 7.8.7.2 Band-edges Compliance with a relative limit at the band-edges (e.g., −20 dBc) shall be made on the lowest and on the highest channels with frequency hopping disabled and repeated with frequency hopping enabled. For the latter test the hopping sequence shall include the lowest and highest channels. For measurements with the hopping disabled the analyzer screen shall clearly show compliance with the requirement within 10 MHz of the allocated band-edge. For measurements with the hopping enabled the analyzer screen shall clearly show compliance with the requirement within 10 MHz of both of the allocated band-edges. This could require separate spectral plots for each band-edge.

6.7.1 E.U.T. Operation:

Operating Environment:	
Temperature:	23.4 °C
Humidity:	46.4 %
Atmospheric Pressure:	1010 mbar

6.7.2 Test Setup Diagram:



6.7.3 Test Data:

Please Refer to Appendix for Details.

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.8 Band edge emissions (Radiated)

Test Requirement:	Refer to 47 CFR 15.247(d), In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	ANSI C63.10-2013 section 6.10 ANSI C63.10-2020 section 6.10 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

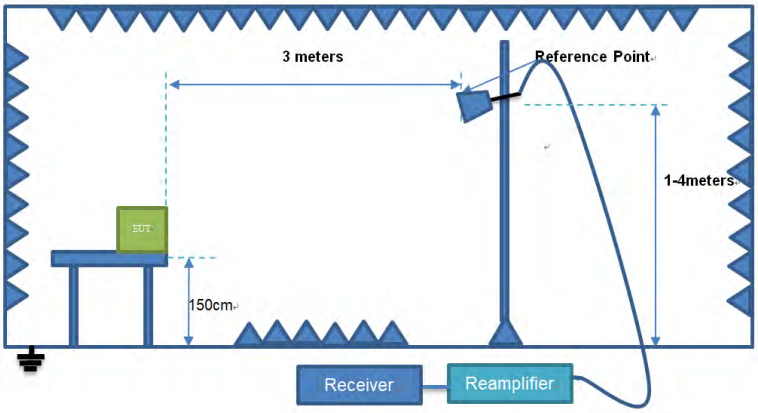
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.
In the emission table above, the tighter limit applies at the band edges.
The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.

Procedure:	ANSI C63.10-2013 section 6.10.5.2 ANSI C63.10-2020 section 6.10.5.2

6.8.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24.7 °C
Humidity:	52 %
Atmospheric Pressure:	1010 mbar

6.8.2 Test Setup Diagram:



6.8.3 Test Data:

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: L

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	2310.000	40.84	-4.39	36.45	74.00	-37.55	peak	P
2 *	2390.000	41.59	-4.29	37.30	74.00	-36.70	peak	P

TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: L

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1 *	2310.000	42.90	-5.79	37.11	74.00	-36.89	peak	P
2	2390.000	42.00	-5.69	36.31	74.00	-37.69	peak	P

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: H

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1 *	2483.500	41.59	-4.19	37.40	74.00	-36.60	peak	P
2	2500.000	38.90	-4.17	34.73	74.00	-39.27	peak	P

TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: H

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1 *	2483.500	43.83	-5.59	38.24	74.00	-35.76	peak	P
2	2500.000	43.09	-5.57	37.52	74.00	-36.48	peak	P

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.9 Emissions in frequency bands (below 1GHz)

Test Requirement:	Refer to 47 CFR 15.247(d), In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	ANSI C63.10-2013 section 6.6.4 ANSI C63.10-2020 section 6.6.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

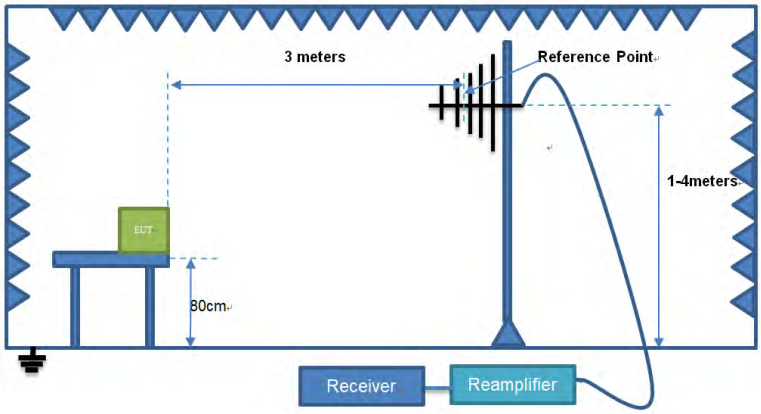
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.
In the emission table above, the tighter limit applies at the band edges.
The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.

Procedure:	ANSI C63.10-2013 section 6.6.4 ANSI C63.10-2020 section 6.6.4

6.9.1 E.U.T. Operation:

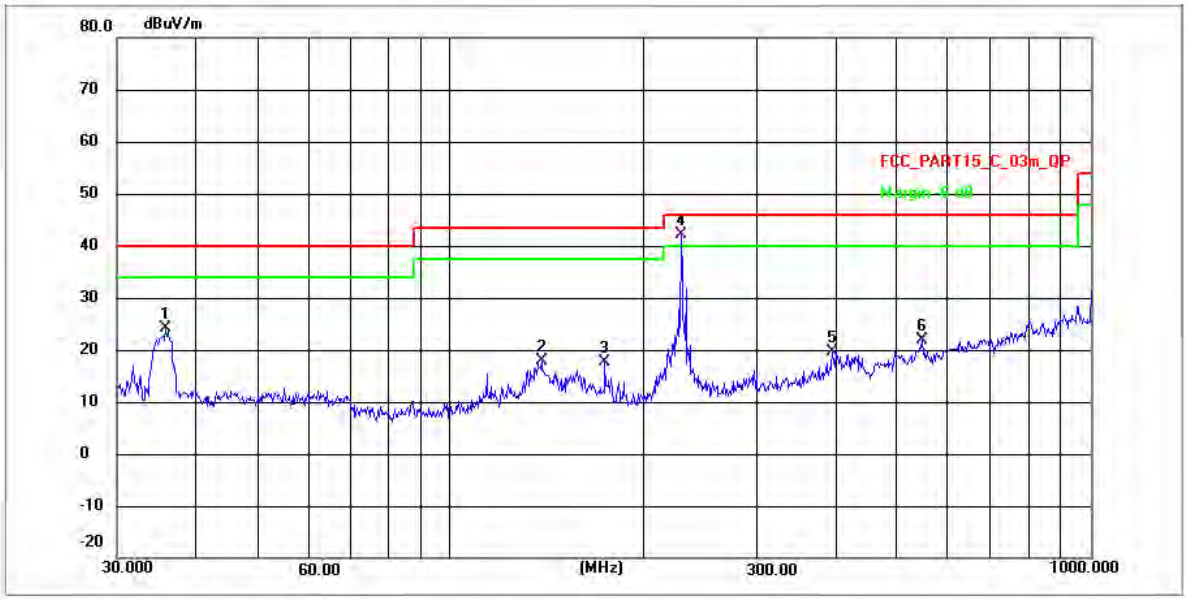
Operating Environment:	
Temperature:	25.3 °C
Humidity:	49 %
Atmospheric Pressure:	1010 mbar

6.9.2 Test Setup Diagram:



6.9.3 Test Data:

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: L

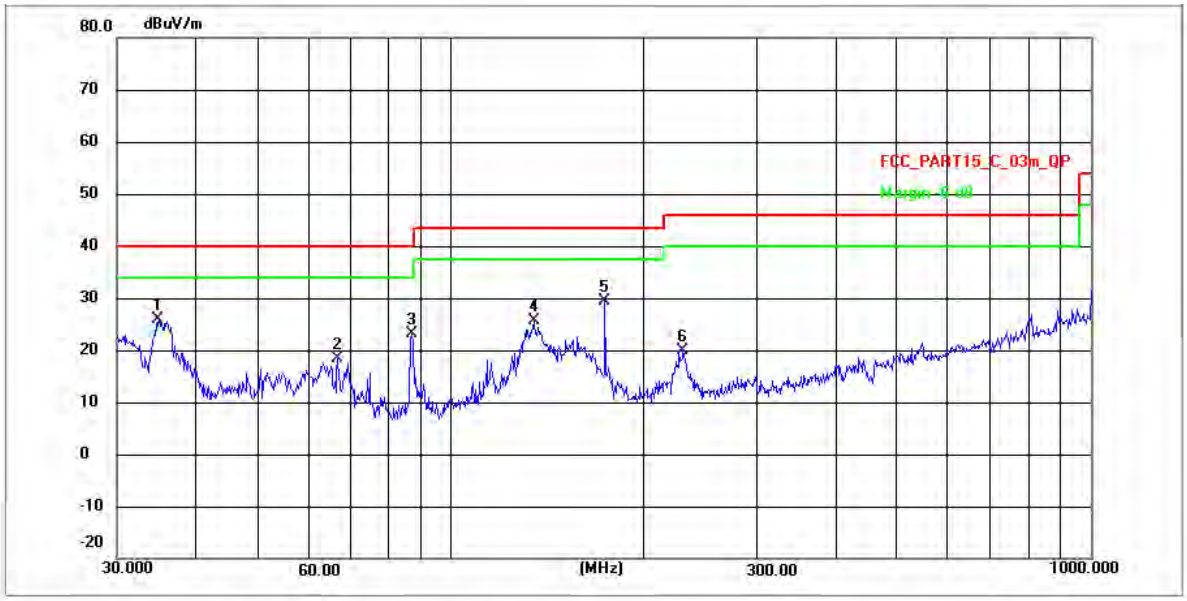


No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	35.7490	39.05	-14.86	24.19	40.00	-15.81	QP	P
2	138.6302	45.30	-27.36	17.94	43.50	-25.56	QP	P
3	174.1184	44.68	-27.11	17.57	43.50	-25.93	QP	P
4 *	229.2931	68.81	-26.72	42.09	46.00	-3.91	QP	P
5	394.8545	45.08	-25.38	19.70	46.00	-26.30	QP	P
6	546.1393	46.40	-24.43	21.97	46.00	-24.03	QP	P

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: L



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1 *	34.9434	43.03	-17.03	26.00	40.00	-14.00	QP	P
2	66.2662	34.89	-16.45	18.44	40.00	-21.56	QP	P
3	86.9591	50.92	-27.82	23.10	40.00	-16.90	QP	P
4	134.7953	53.05	-27.39	25.66	43.50	-17.84	QP	P
5	174.1184	56.55	-27.11	29.44	43.50	-14.06	QP	P
6	230.5023	46.64	-26.72	19.92	46.00	-26.08	QP	P

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.10 Emissions in frequency bands (above 1GHz)

Test Requirement:	In addition, radiated emissions which fall in the restricted bands, as defined in § 15.205(a), must also comply with the radiated emission limits specified in § 15.209(a)(see § 15.205(c)).`
Test Method:	ANSI C63.10-2013 section 6.6.4 ANSI C63.10-2020 section 6.6.4 KDB 558074 D01 15.247 Meas Guidance v05r02
Test Limit:	

Frequency (MHz)	Field strength (microvolts/meter)	Measurement distance (meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

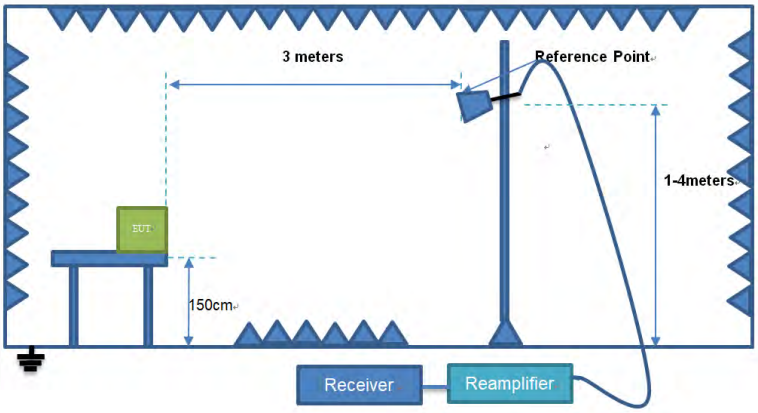
** Except as provided in paragraph (g), fundamental emissions from intentional radiators operating under this section shall not be located in the frequency bands 54-72 MHz, 76-88 MHz, 174-216 MHz or 470-806 MHz. However, operation within these frequency bands is permitted under other sections of this part, e.g., §§ 15.231 and 15.241.
In the emission table above, the tighter limit applies at the band edges.
The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9–90 kHz, 110–490 kHz and above 1000 MHz. Radiated emission limits in these three bands are based on measurements employing an average detector.

Procedure:	ANSI C63.10-2013 section 6.6.4 ANSI C63.10-2020 section 6.6.4

6.10.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24.7 °C
Humidity:	52 %
Atmospheric Pressure:	1010 mbar

6.10.2 Test Setup Diagram:



6.10.3 Test Data:

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: L

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	3772.873	71.85	-29.02	42.83	74.00	-31.17	peak	P
2	5174.560	74.79	-27.23	47.56	74.00	-26.44	peak	P
3	7648.677	71.16	-25.01	46.15	74.00	-27.85	peak	P
4	9607.874	74.38	-23.43	50.95	74.00	-23.05	peak	P
5	11982.023	74.26	-22.22	52.04	74.00	-21.96	peak	P
6 *	13777.163	74.73	-21.03	53.70	74.00	-20.30	peak	P

TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: L

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	3172.166	68.16	-29.36	38.80	74.00	-35.20	peak	P
2	3407.898	77.01	-29.14	47.87	74.00	-26.13	peak	P
3	5335.552	71.01	-27.09	43.92	74.00	-30.08	peak	P
4	5803.738	76.59	-25.97	50.62	74.00	-23.38	peak	P
5	9149.834	74.34	-23.98	50.36	74.00	-23.64	peak	P
6 *	15372.150	73.54	-21.22	52.32	74.00	-21.68	peak	P

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: M

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	3688.766	68.37	-29.03	39.34	74.00	-34.66	peak	P
2	5618.867	69.01	-26.56	42.45	74.00	-31.55	peak	P
3	8080.467	71.89	-25.50	46.39	74.00	-27.61	peak	P
4	10179.648	74.92	-24.37	50.55	74.00	-23.45	peak	P
5 *	13481.718	72.09	-20.98	51.11	74.00	-22.89	peak	P
6	15243.838	70.11	-20.93	49.18	74.00	-24.82	peak	P

TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: M

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	3891.380	70.31	-29.01	41.30	74.00	-32.70	peak	P
2	6052.144	70.41	-25.33	45.08	74.00	-28.92	peak	P
3	8802.227	70.17	-24.71	45.46	74.00	-28.54	peak	P
4	10791.685	71.94	-23.88	48.06	74.00	-25.94	peak	P
5	12340.533	70.32	-21.80	48.52	74.00	-25.48	peak	P
6 *	15134.085	71.43	-20.70	50.73	74.00	-23.27	peak	P

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

TM1 / Polarization: Horizontal / Band: 2400-2483.5 MHz / BW: 1 / CH: H

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	3535.318	70.03	-29.05	40.98	74.00	-33.02	peak	P
2	5560.704	71.16	-26.75	44.41	74.00	-29.59	peak	P
3	6258.502	68.34	-25.35	42.99	74.00	-31.01	peak	P
4	8794.598	70.46	-24.73	45.73	74.00	-28.27	peak	P
5 *	12629.207	71.25	-21.55	49.70	74.00	-24.30	peak	P
6	15663.683	69.96	-21.53	48.43	74.00	-25.57	peak	P

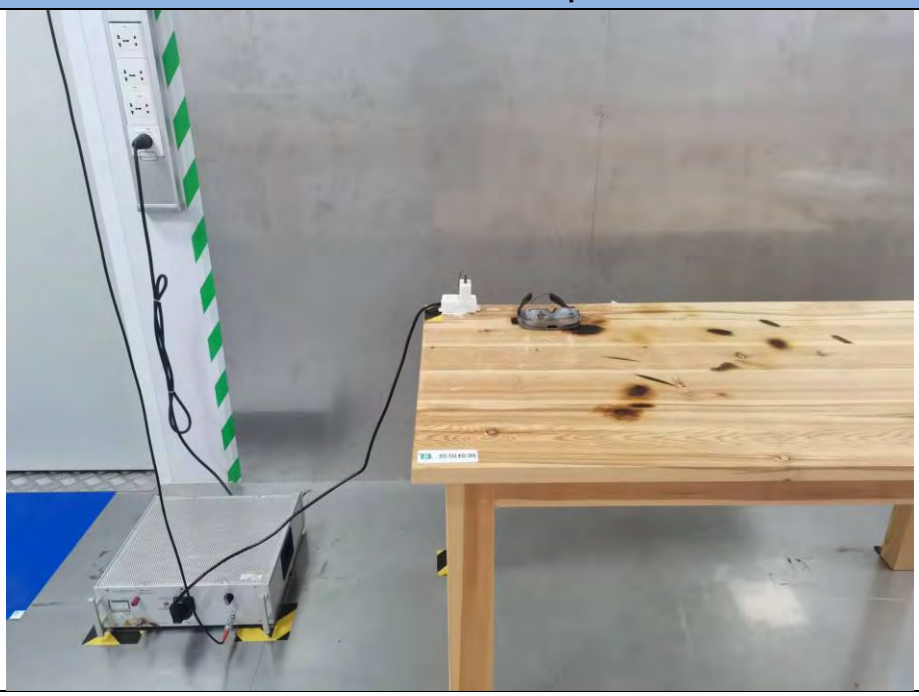
TM1 / Polarization: Vertical / Band: 2400-2483.5 MHz / BW: 1 / CH: H

No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	5284.902	70.47	-27.13	43.34	74.00	-30.66	peak	P
2	6052.144	71.41	-25.33	46.08	74.00	-27.92	peak	P
3	6930.770	68.91	-24.99	43.92	74.00	-30.08	peak	P
4	9472.759	70.12	-23.26	46.86	74.00	-27.14	peak	P
5	13654.269	69.31	-21.00	48.31	74.00	-25.69	peak	P
6 *	15713.564	71.69	-21.54	50.15	74.00	-23.85	peak	P

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

7 Test Setup Photos

Conducted Emission at AC power line


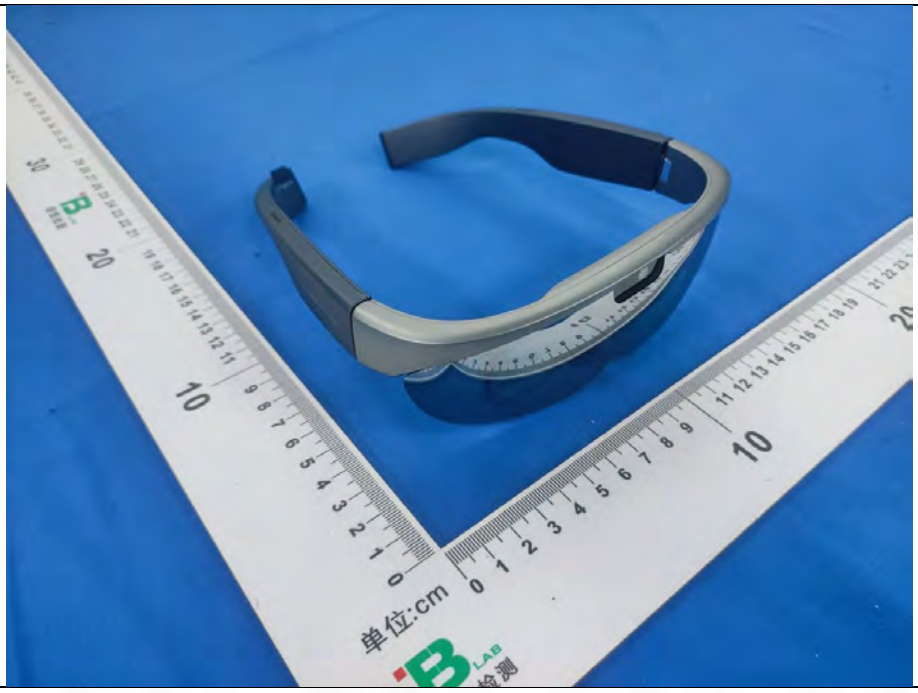
Band edge emissions (Radiated) Emissions in frequency bands (above 1GHz)

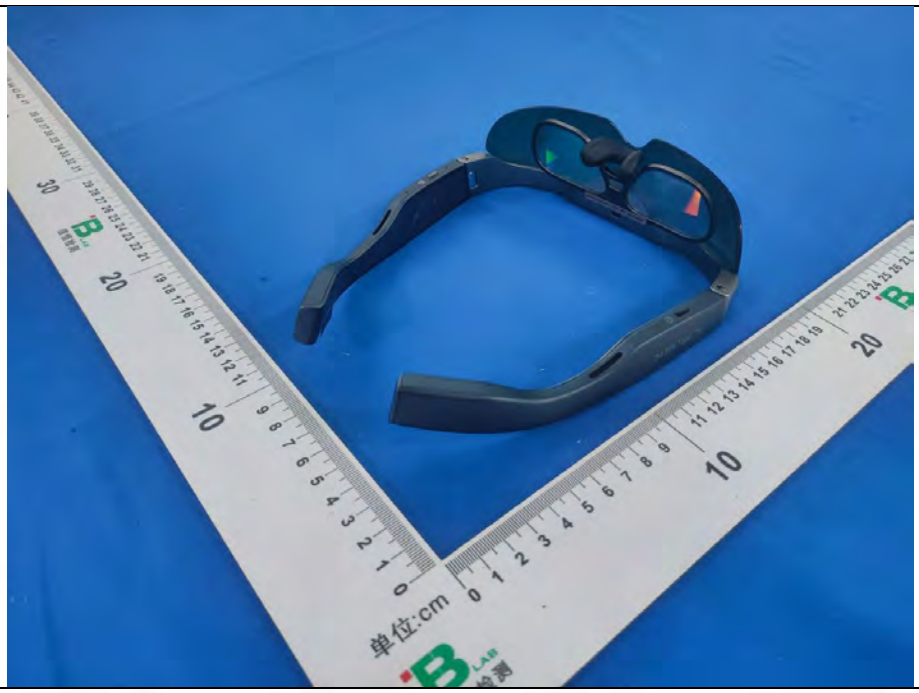
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Emissions in frequency bands (below 1GHz)

8 EUT Constructional Details (EUT Photos)

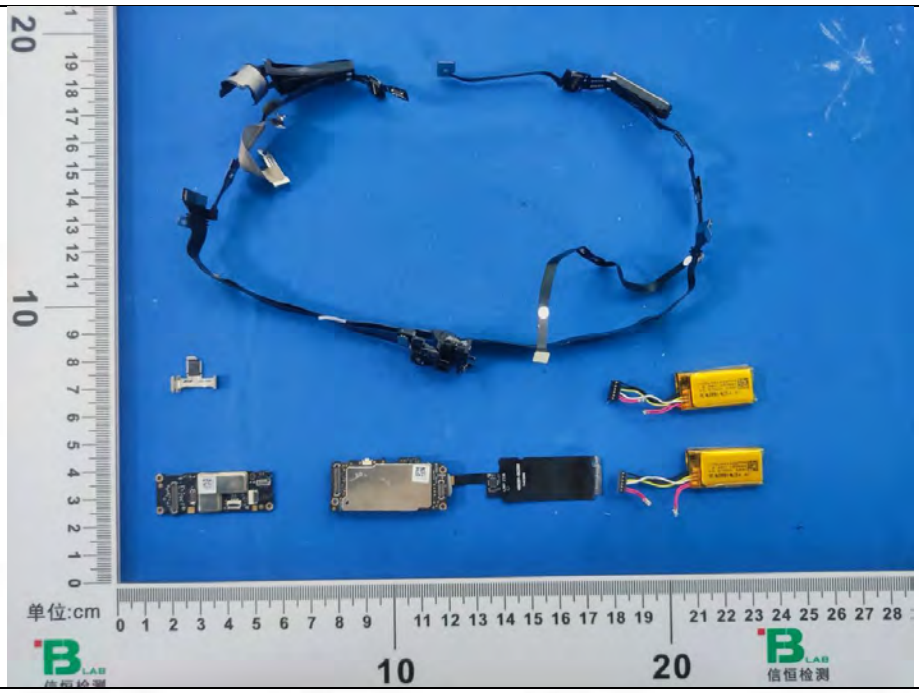
External


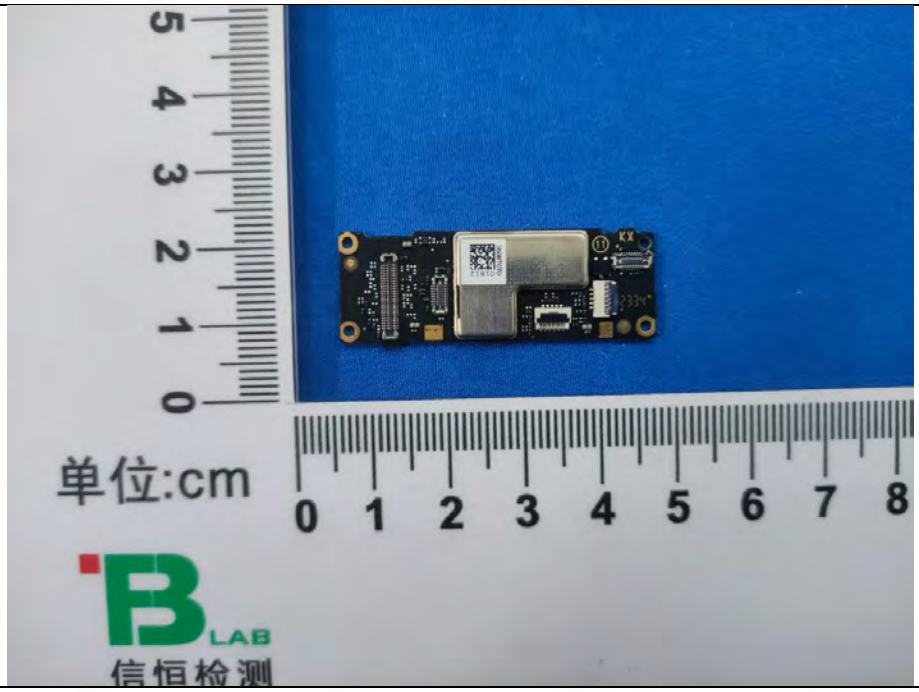


Internal

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

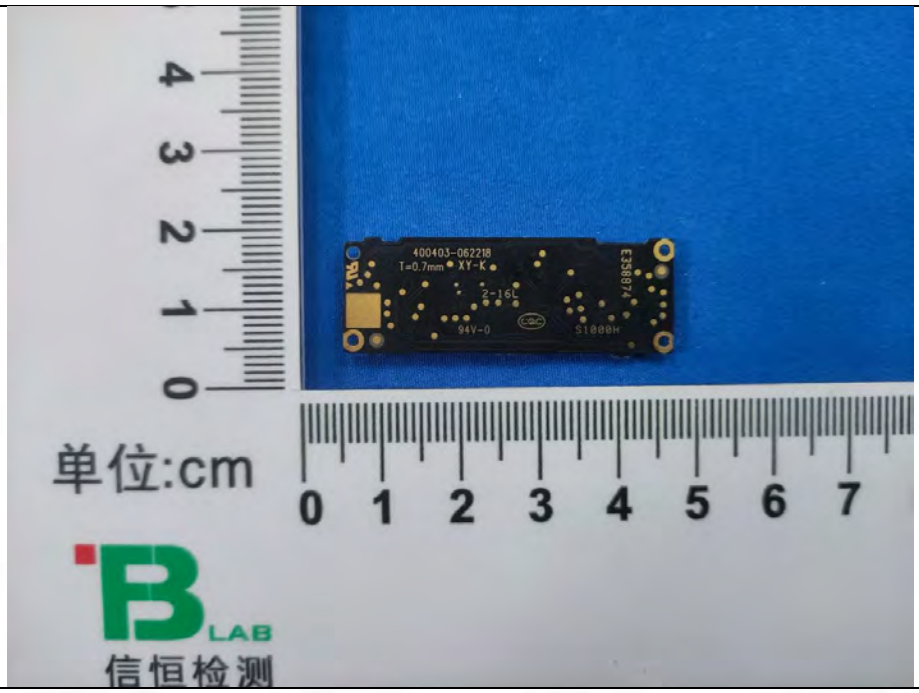
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

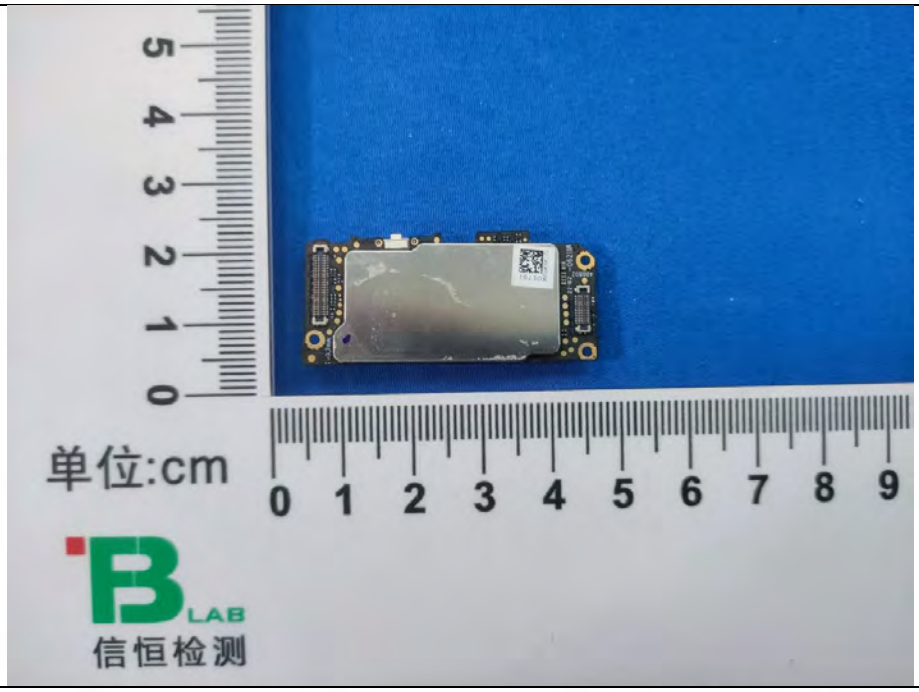




Total or partial reproduction of this document without permission of the Laboratory is not allowed.

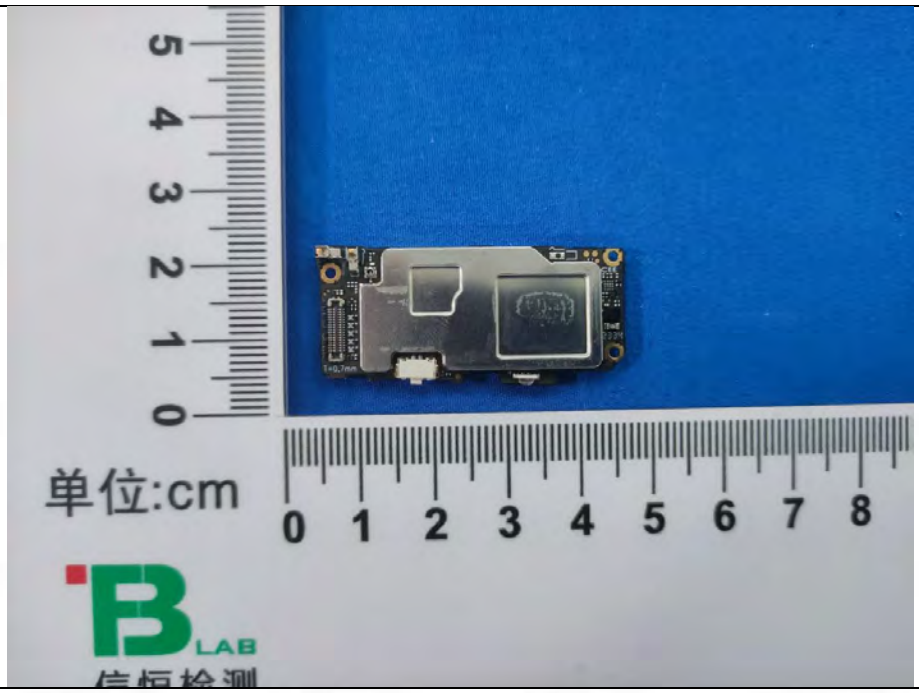
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

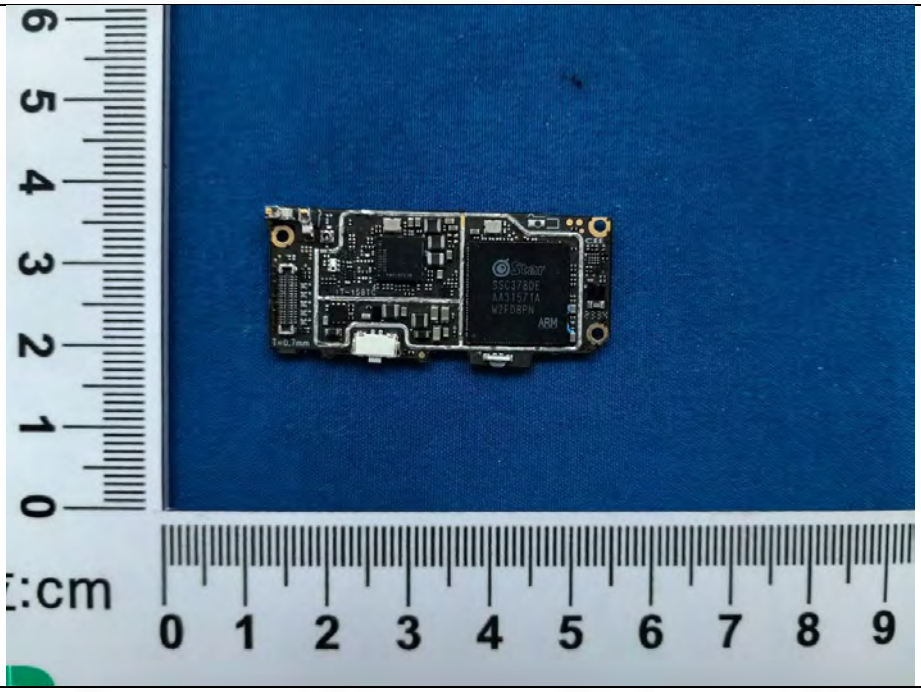




Total or partial reproduction of this document without permission of the Laboratory is not allowed.

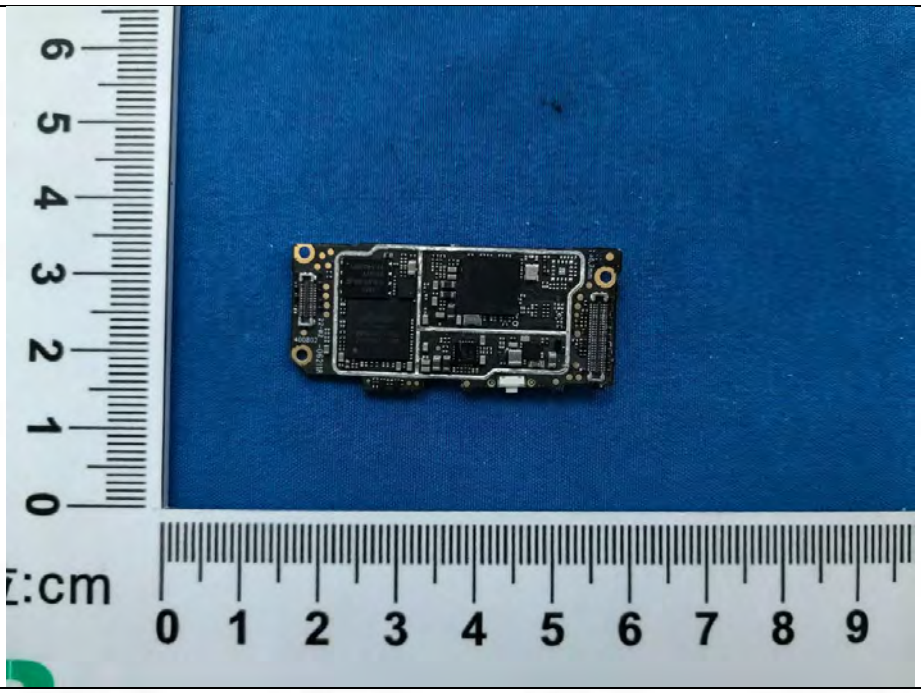
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

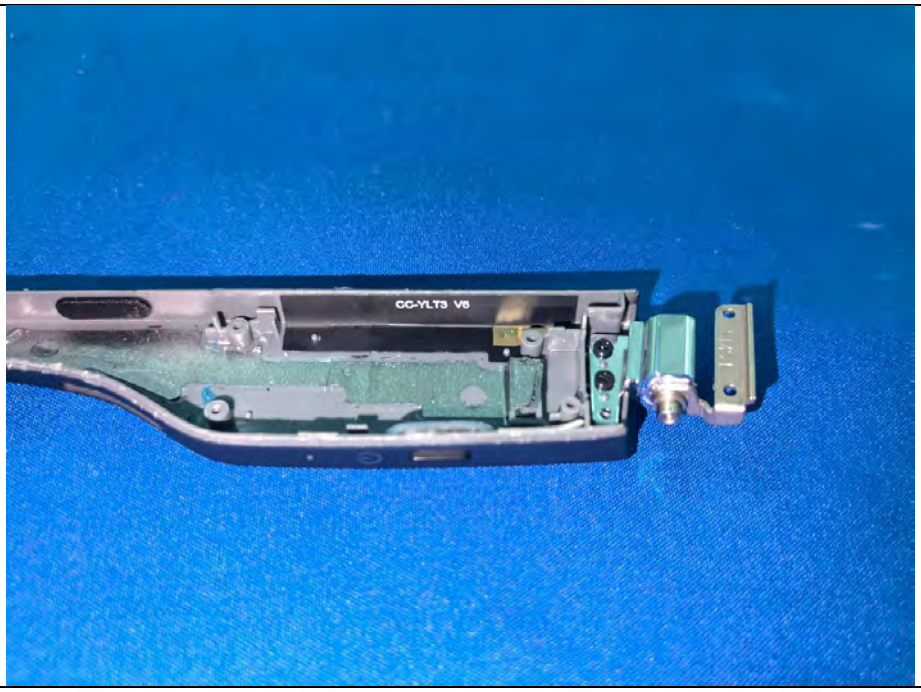




Total or partial reproduction of this document without permission of the Laboratory is not allowed.

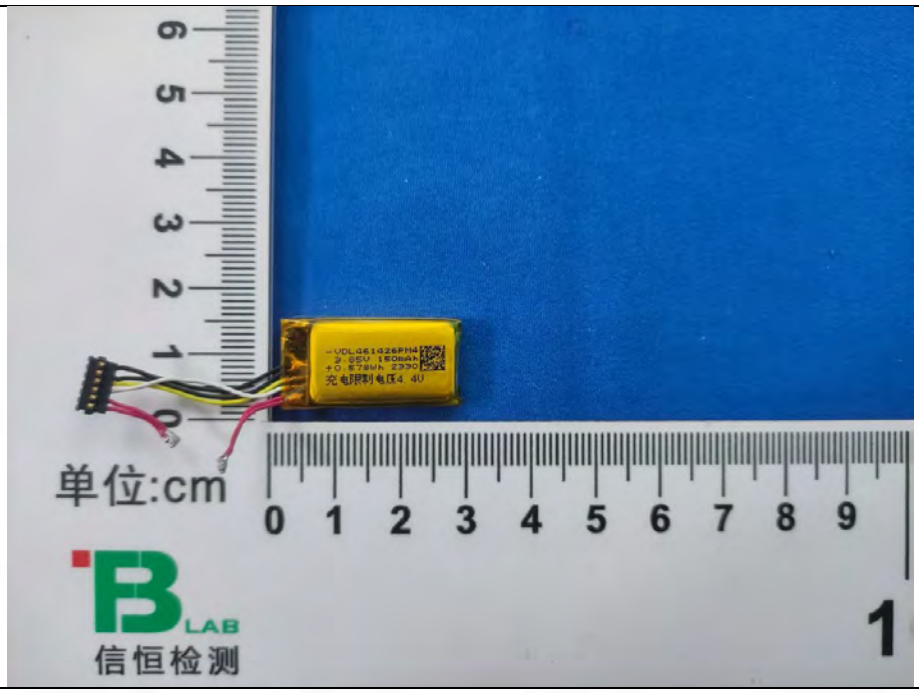
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China





Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China


单位:cm
信恒检测

Appendix

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

1. Bandwidth

1.1 OBW

1.1.1 Test Result

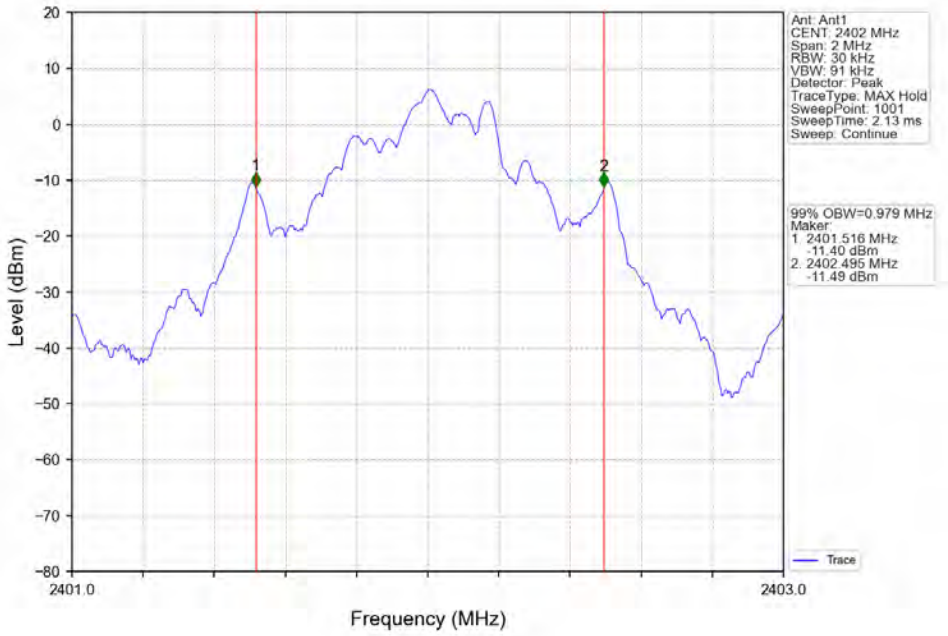
Mode	TX Type	Frequency (MHz)	Packet Type	ANT	99% Occupied Bandwidth (MHz)		Verdict
					Result	Limit	
GFSK	SISO	2402	DH5	1	0.979	/	Pass
		2441	DH5	1	0.979	/	Pass
		2480	DH5	1	0.980	/	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	1.058	/	Pass
		2441	2DH5	1	1.054	/	Pass
		2480	2DH5	1	1.058	/	Pass
8DPSK	SISO	2402	3DH5	1	1.102	/	Pass
		2441	3DH5	1	1.101	/	Pass
		2480	3DH5	1	1.098	/	Pass

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

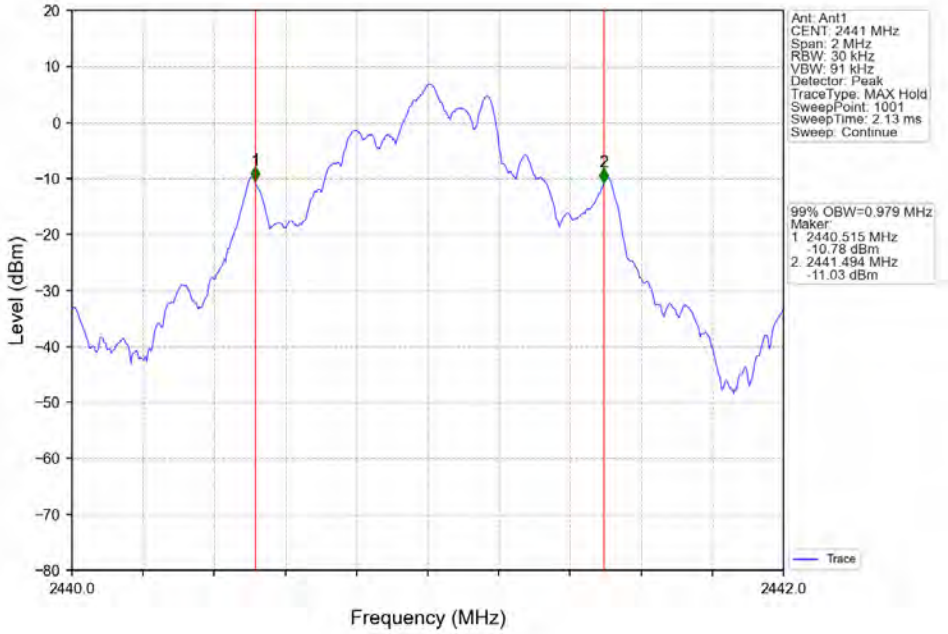
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

1.1.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV

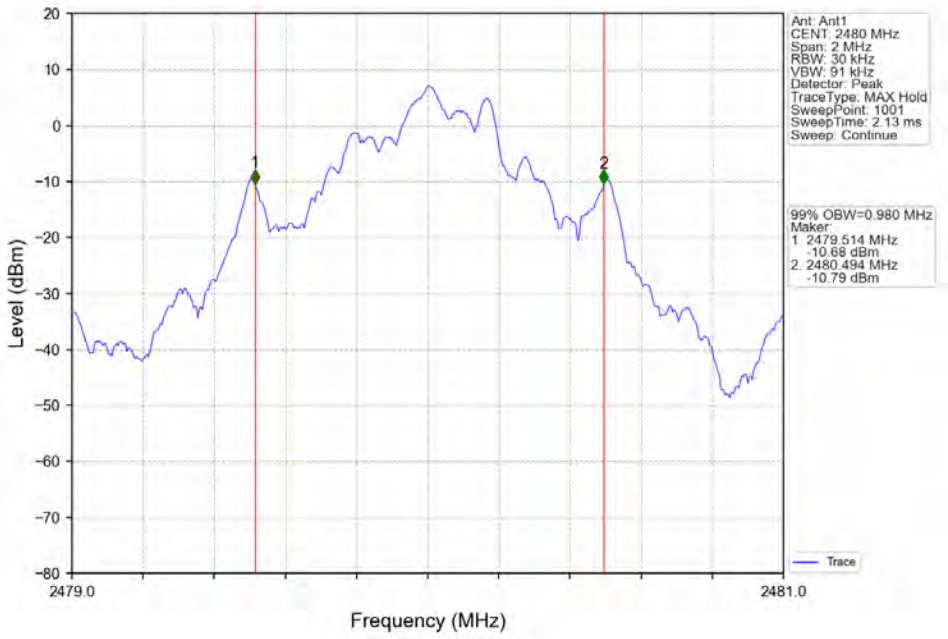


GFSK_DH5_MCH_2441MHz_Ant1_NTNV

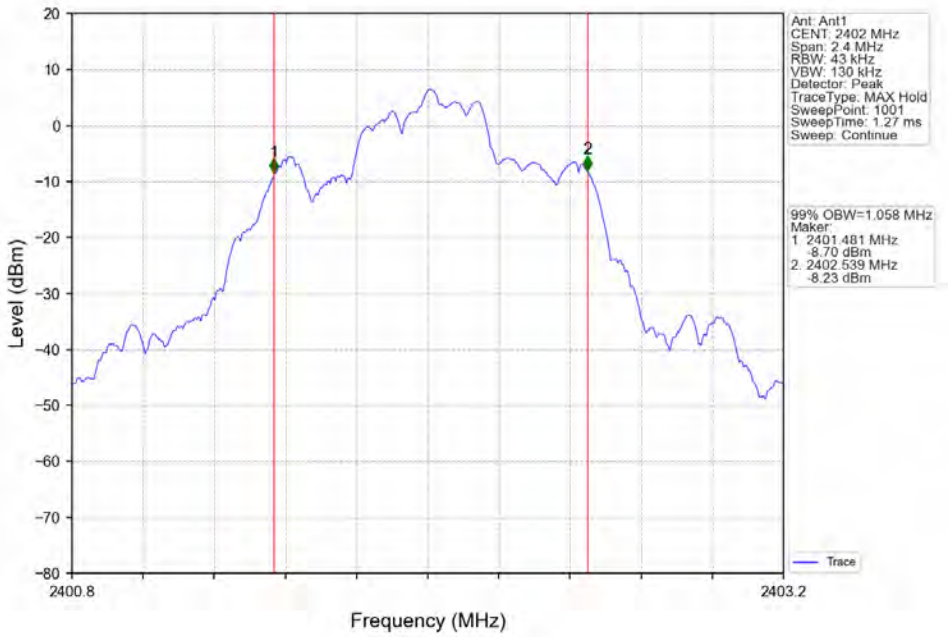


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HCH_2480MHz_Ant1_NTNV



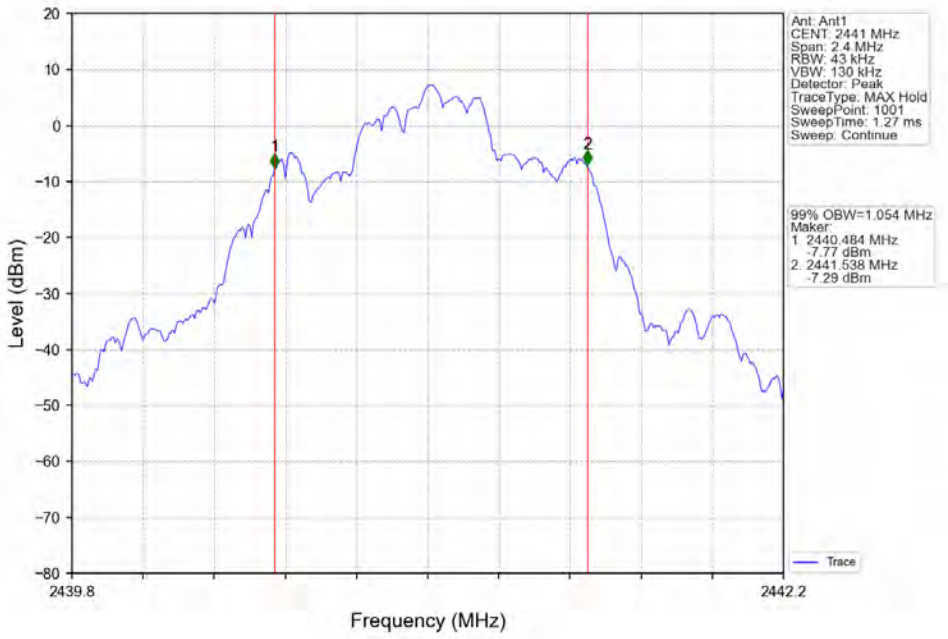
Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



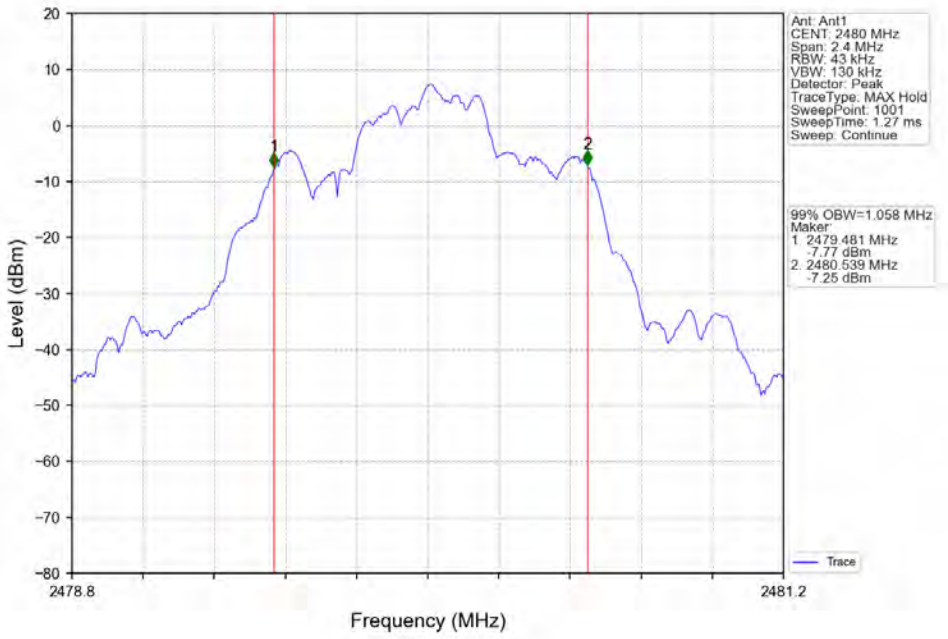
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



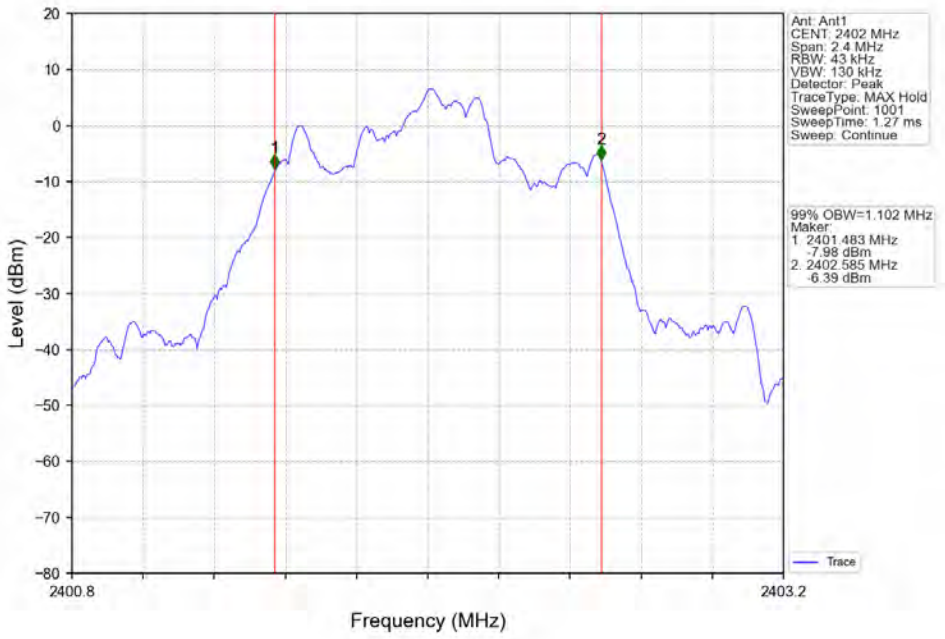
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



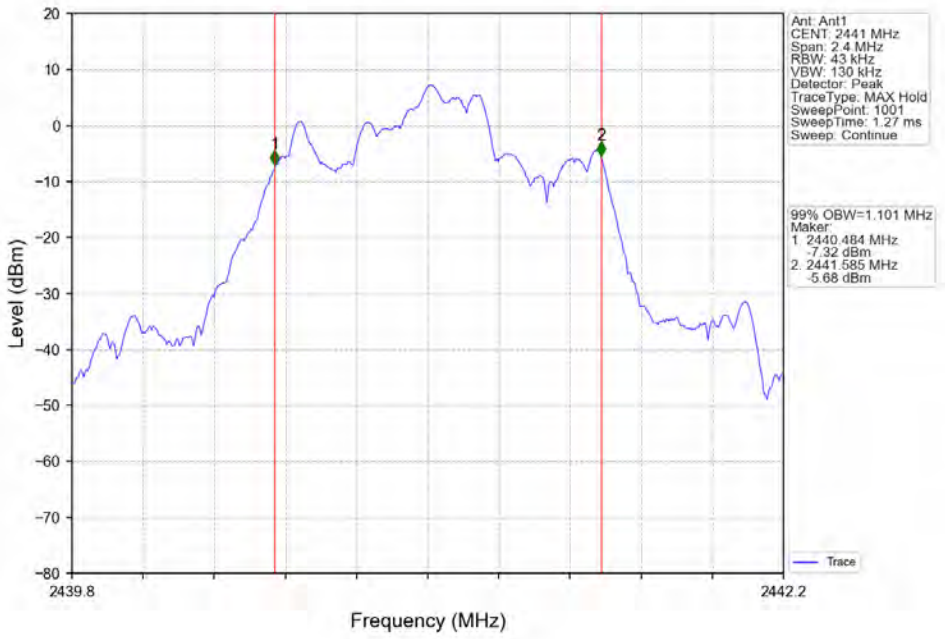
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



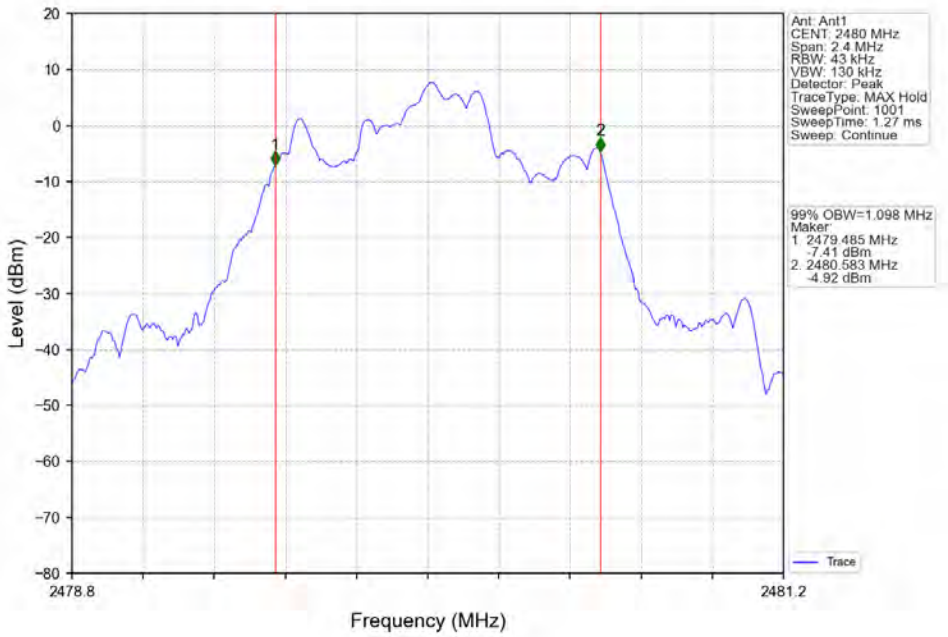
8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



1.2 20dB BW

1.2.1 Test Result

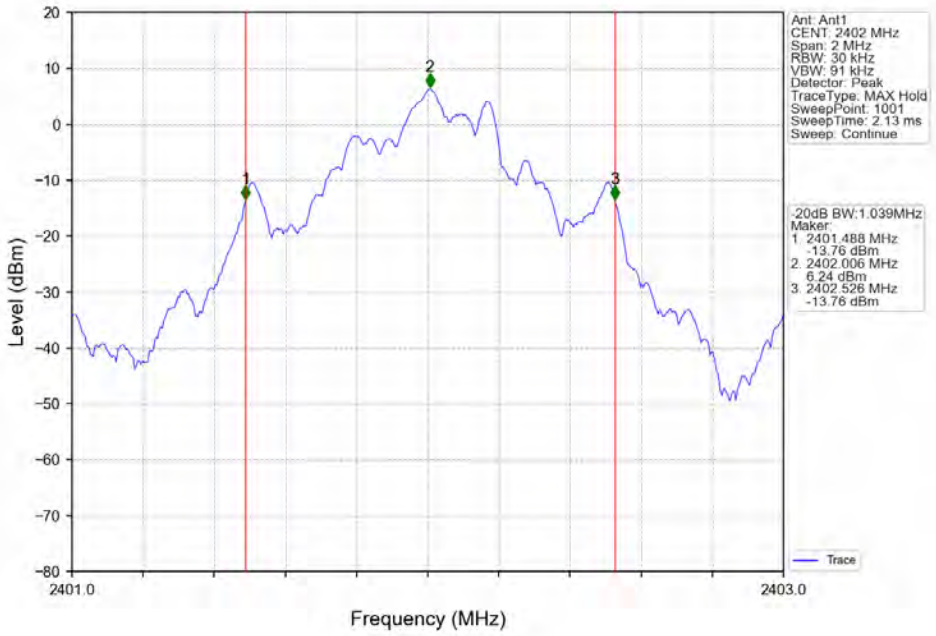
Mode	TX Type	Frequency (MHz)	Packet Type	ANT	20dB Bandwidth (MHz)		Verdict
					Result	Limit	
GFSK	SISO	2402	DH5	1	1.039	/	Pass
		2441	DH5	1	1.037	/	Pass
		2480	DH5	1	1.038	/	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	1.137	/	Pass
		2441	2DH5	1	1.132	/	Pass
		2480	2DH5	1	1.136	/	Pass
8DPSK	SISO	2402	3DH5	1	1.175	/	Pass
		2441	3DH5	1	1.173	/	Pass
		2480	3DH5	1	1.174	/	Pass

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

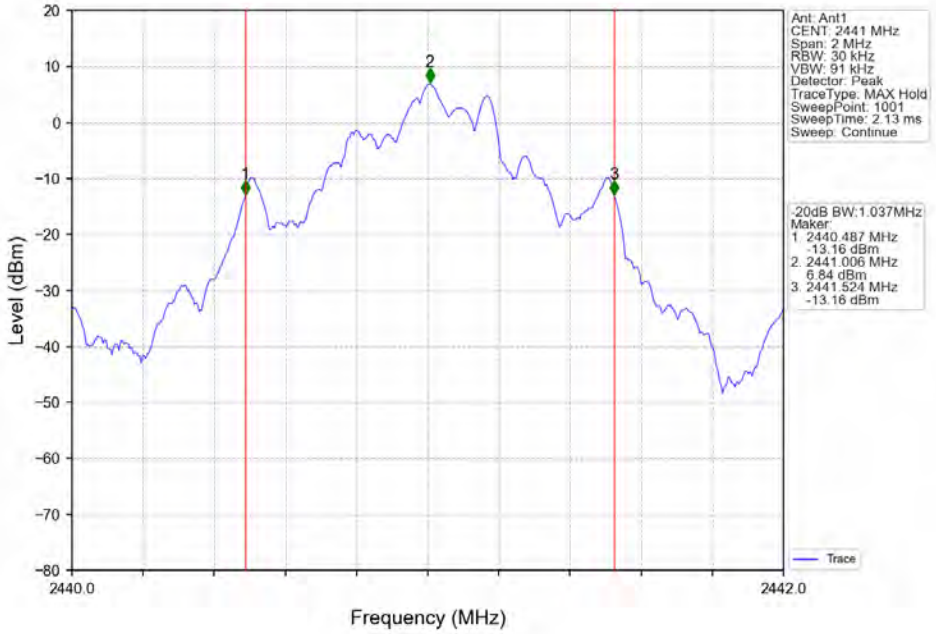
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

1.2.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



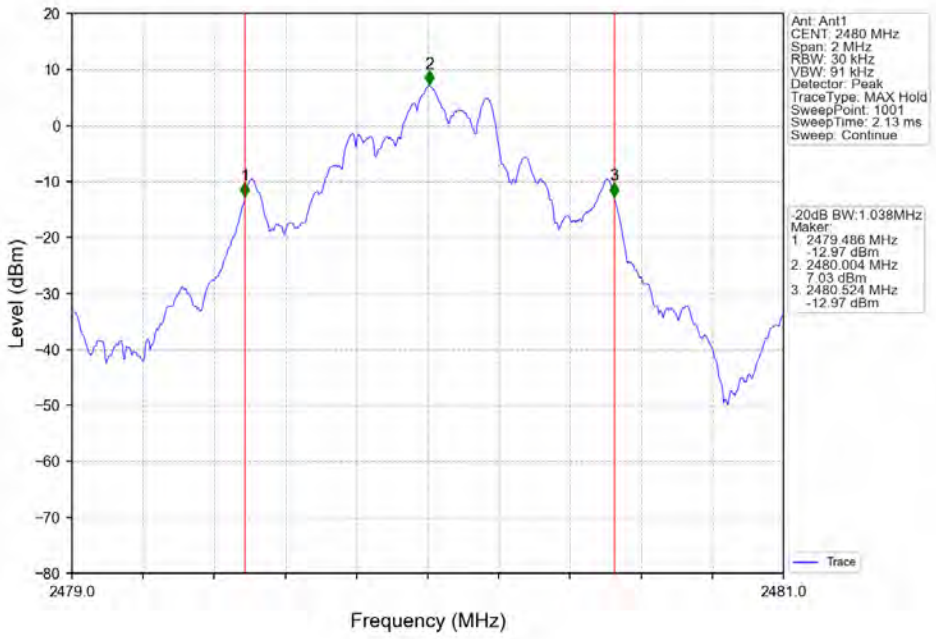
GFSK_DH5_MCH_2441MHz_Ant1_NTNV



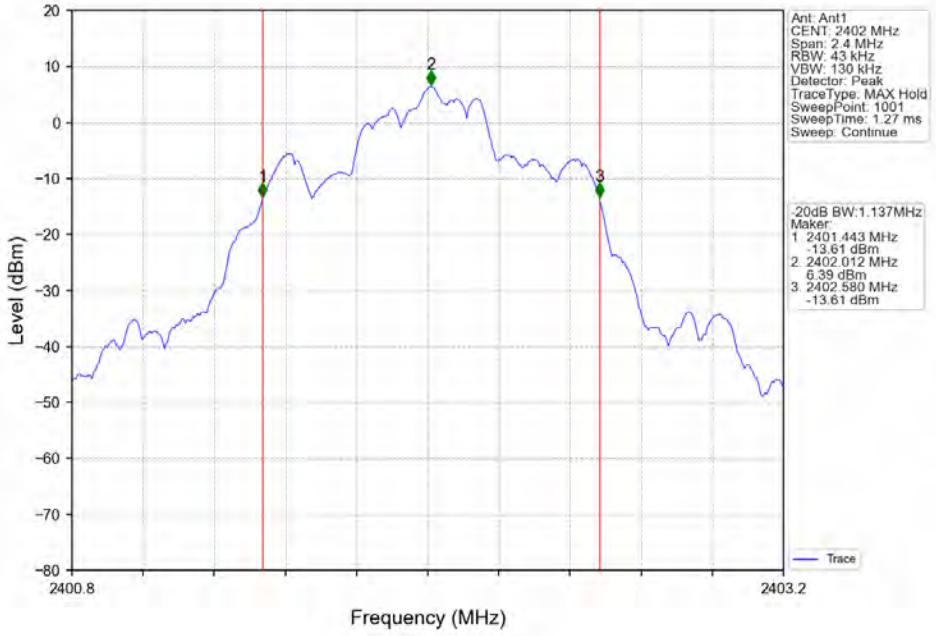
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HCH_2480MHz_Ant1_NTNV

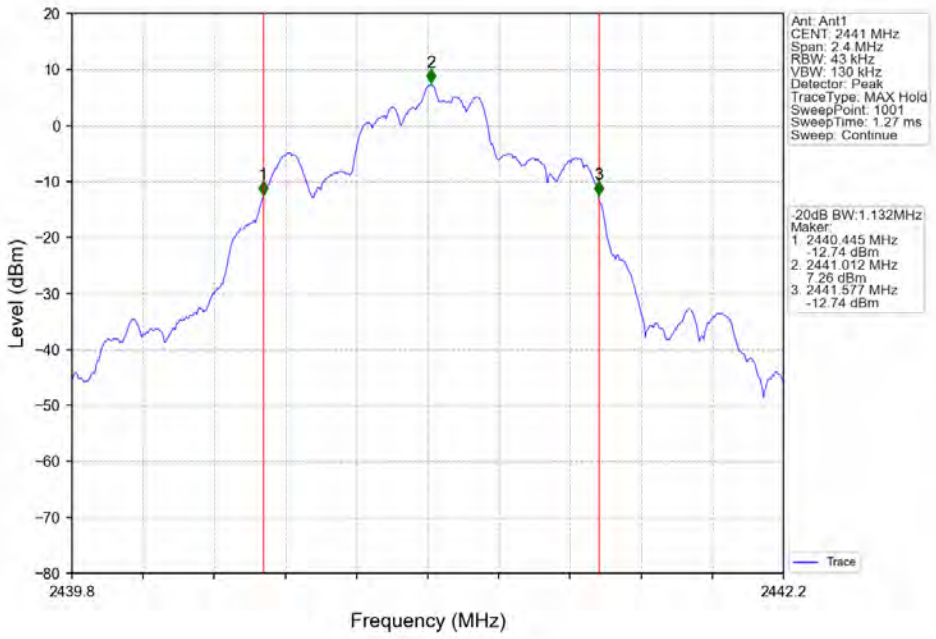


Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV

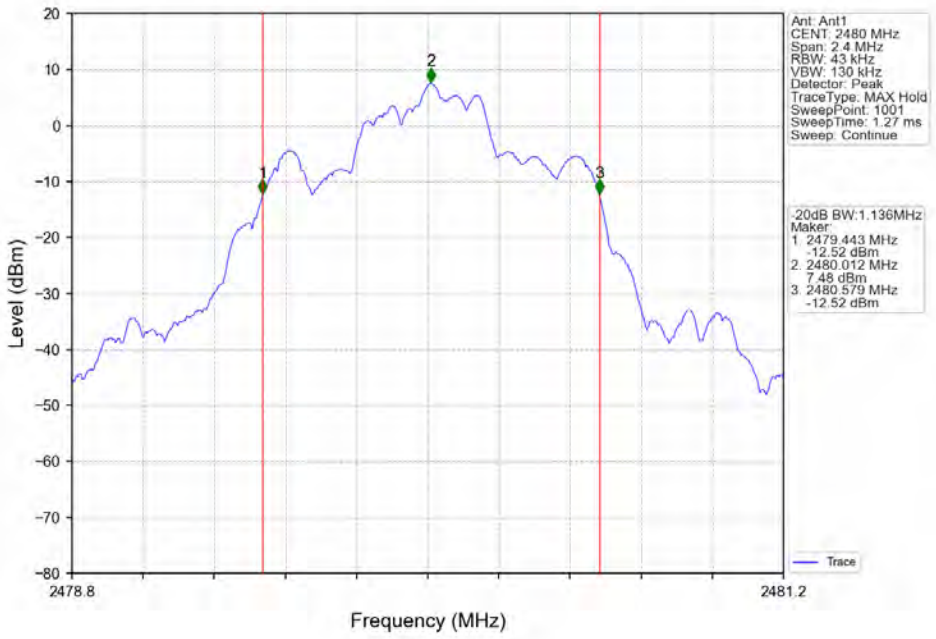


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



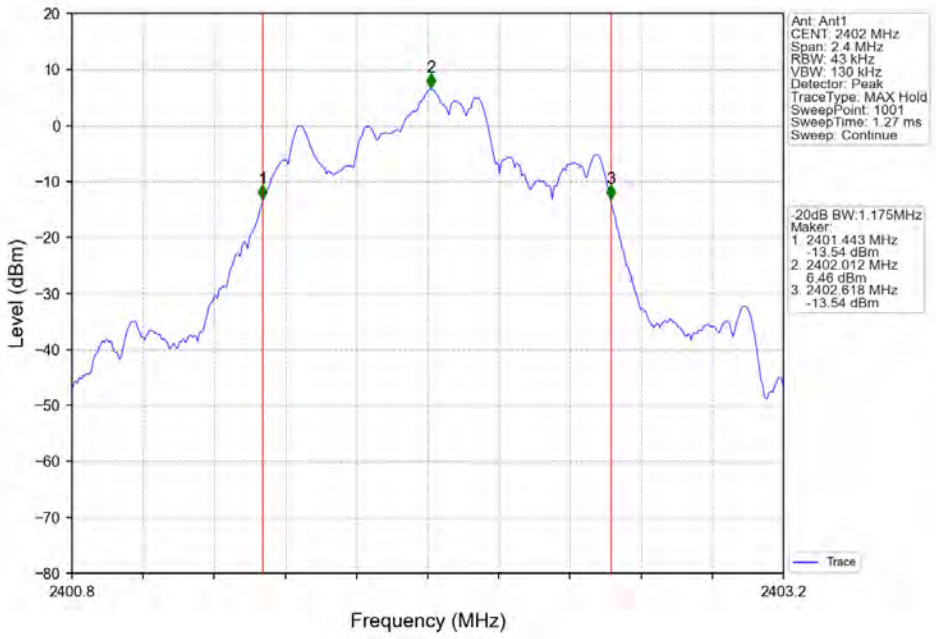
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



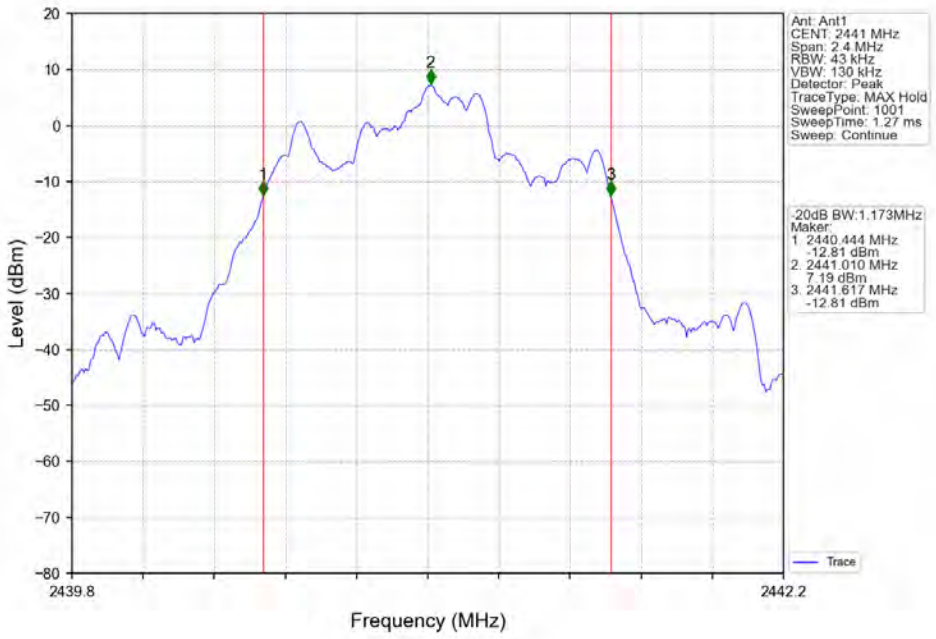
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



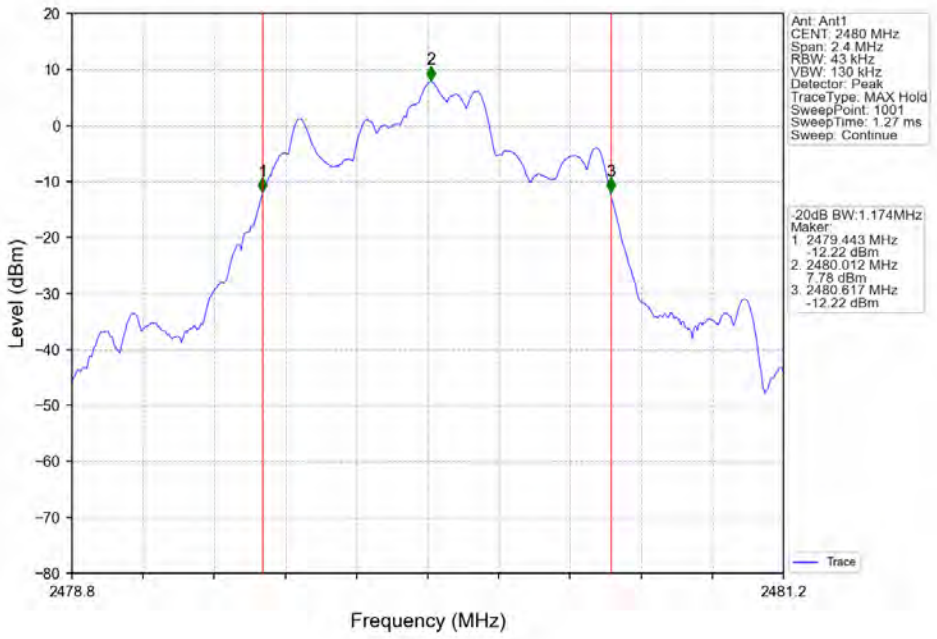
8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



2. Maximum Conducted Output Power

2.1 Power

2.1.1 Test Result

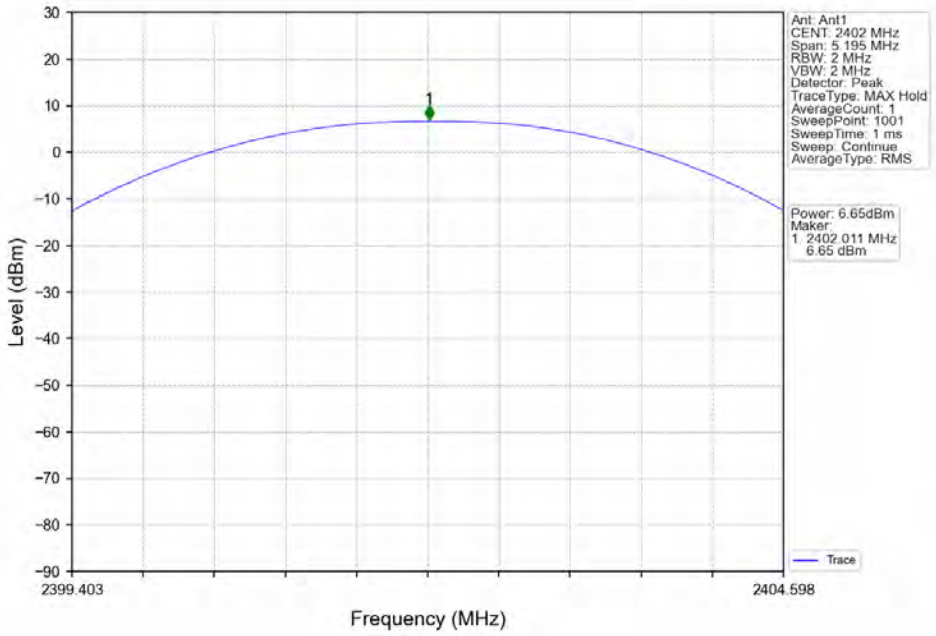
Mode	TX Type	Frequency (MHz)	Packet Type	Maximum Peak Conducted Output Power (dBm)		Verdict
				ANT1	Limit	
GFSK	SISO	2402	DH5	6.65	<=20.97	Pass
		2441	DH5	7.26	<=20.97	Pass
		2480	DH5	7.41	<=20.97	Pass
Pi/4DQPSK	SISO	2402	2DH5	6.54	<=20.97	Pass
		2441	2DH5	7.47	<=20.97	Pass
		2480	2DH5	7.46	<=20.97	Pass
8DPSK	SISO	2402	3DH5	6.36	<=20.97	Pass
		2441	3DH5	7.24	<=20.97	Pass
		2480	3DH5	7.48	<=20.97	Pass
Note1: Antenna Gain: Ant1: 1.79dBi;						

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

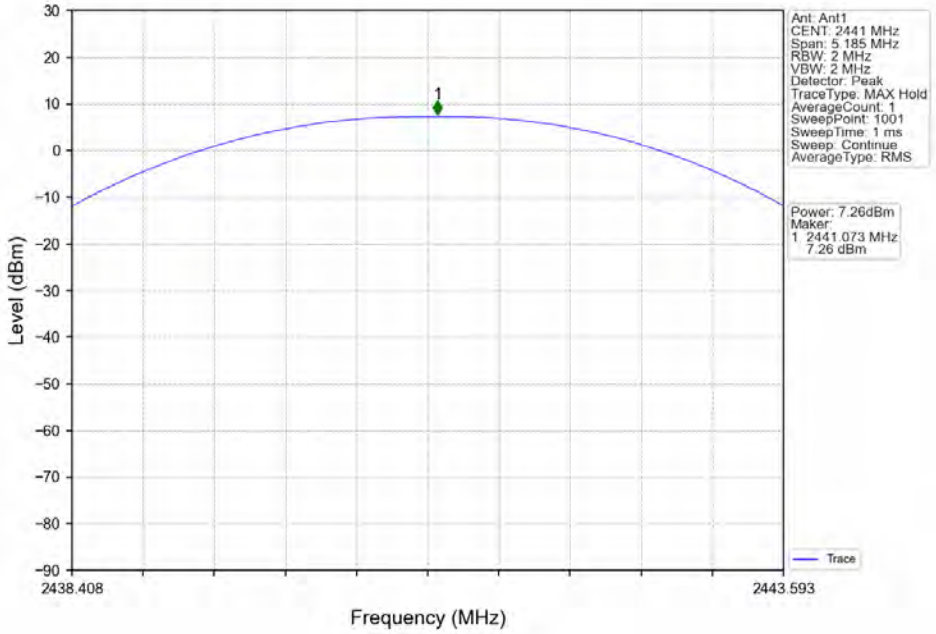
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

2.1.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



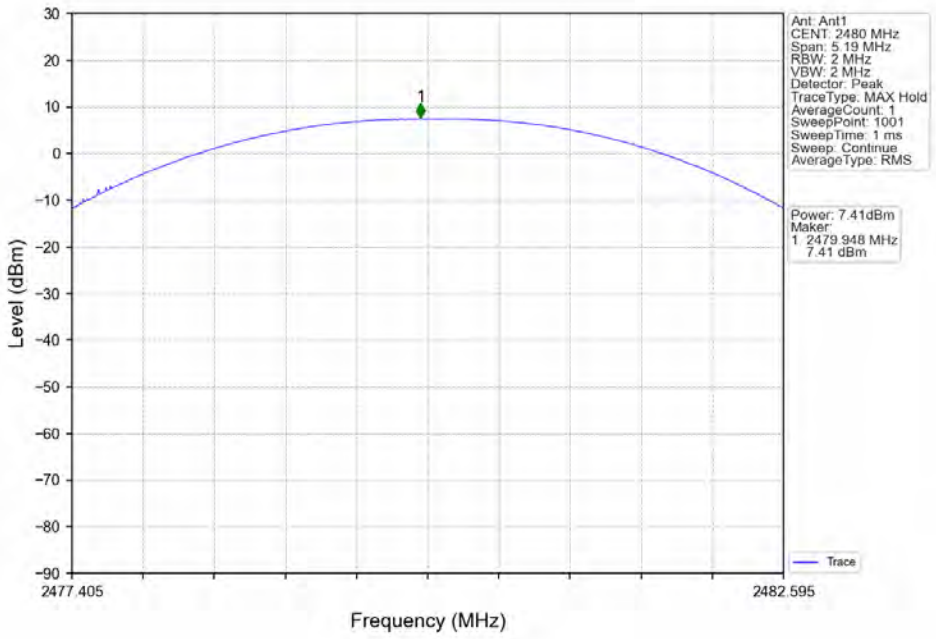
GFSK_DH5_MCH_2441MHz_Ant1_NTNV



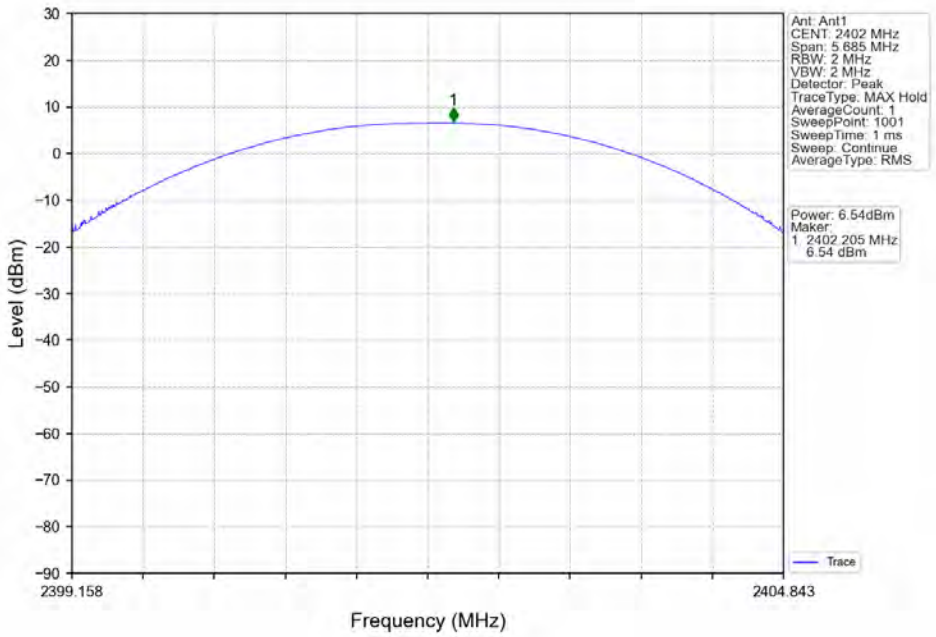
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HCH_2480MHz_Ant1_NTNV



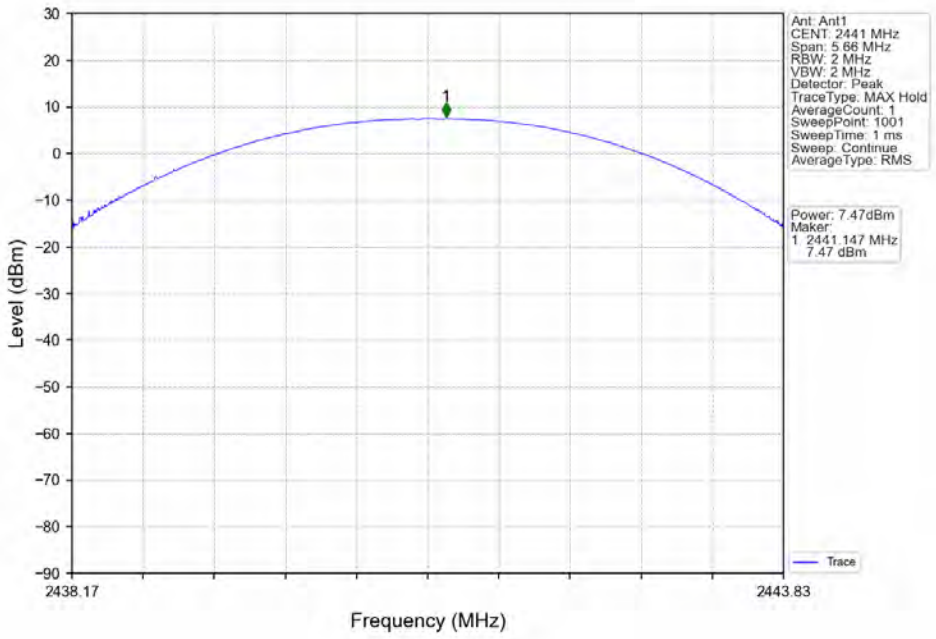
Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



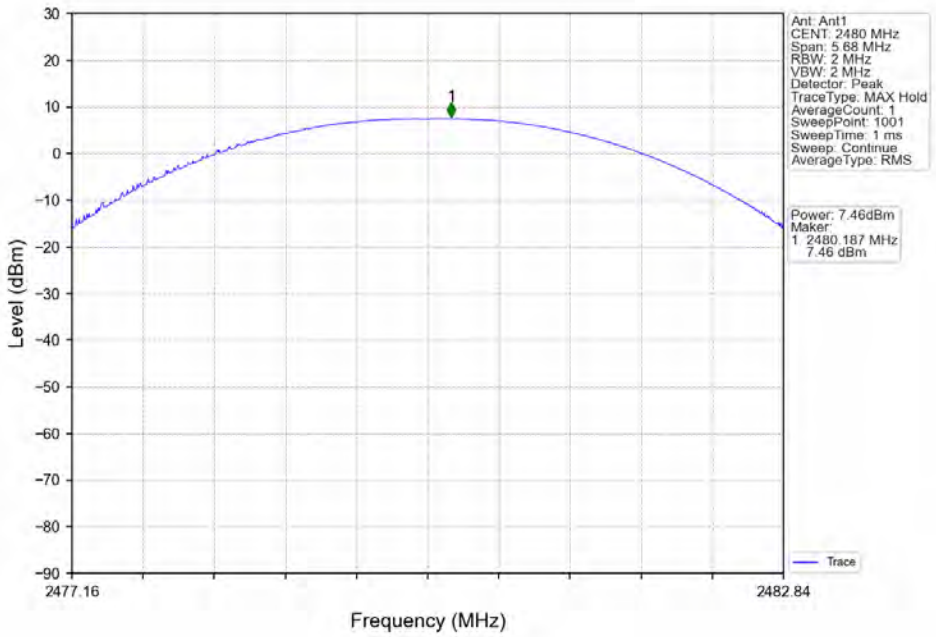
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



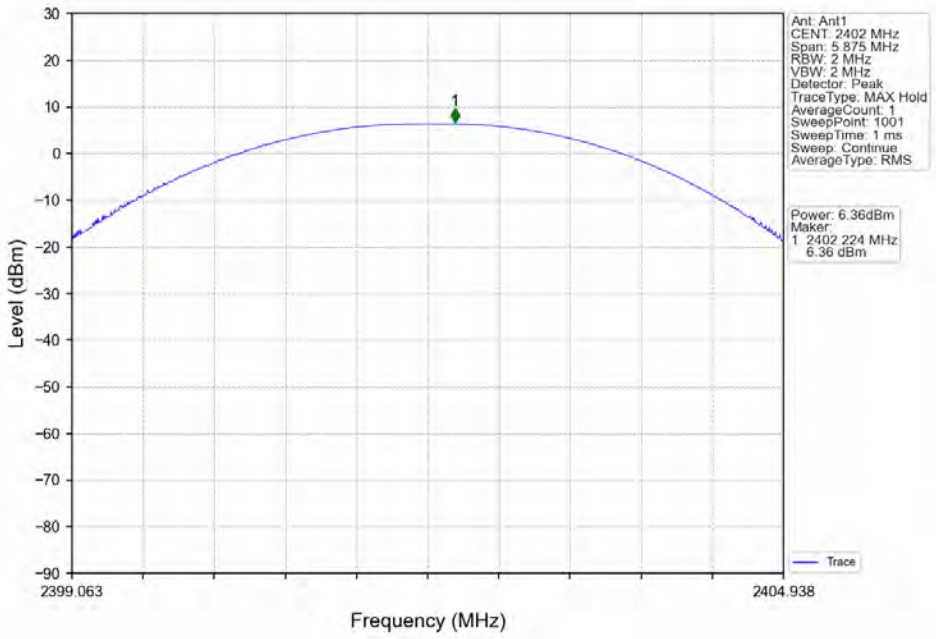
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



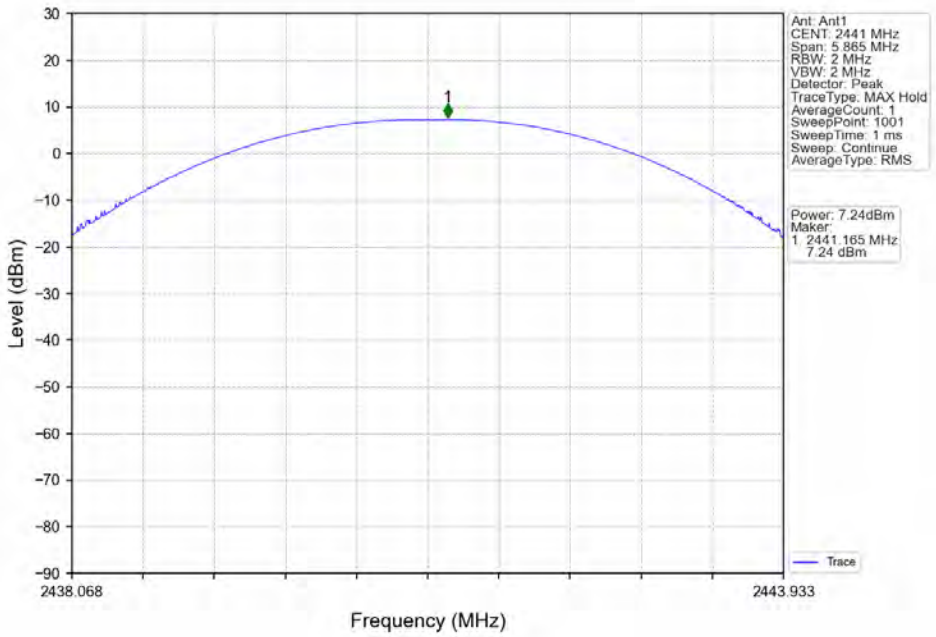
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



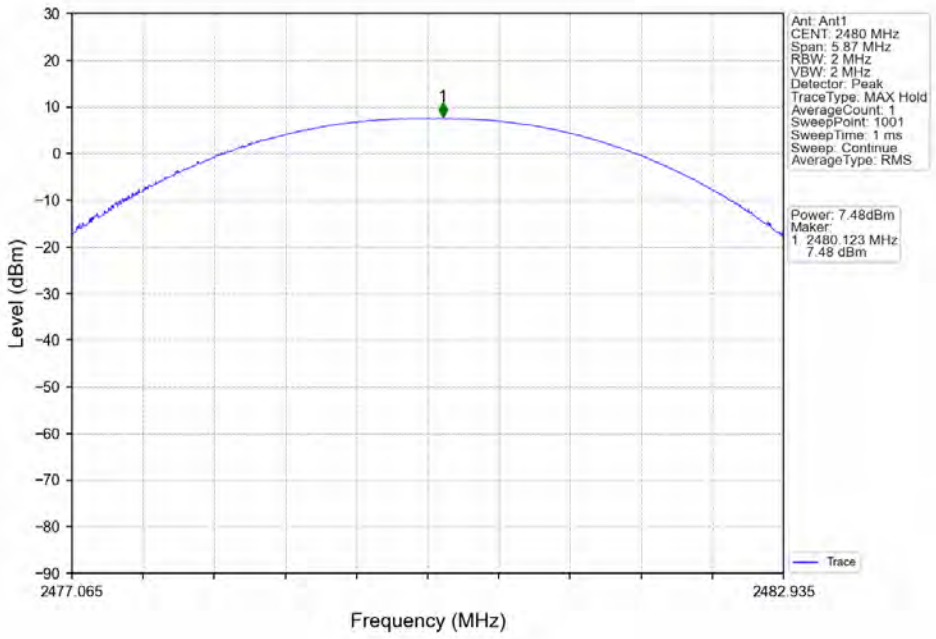
8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



3. Carrier Frequency Separation

3.1 Ant1

3.1.1 Test Result

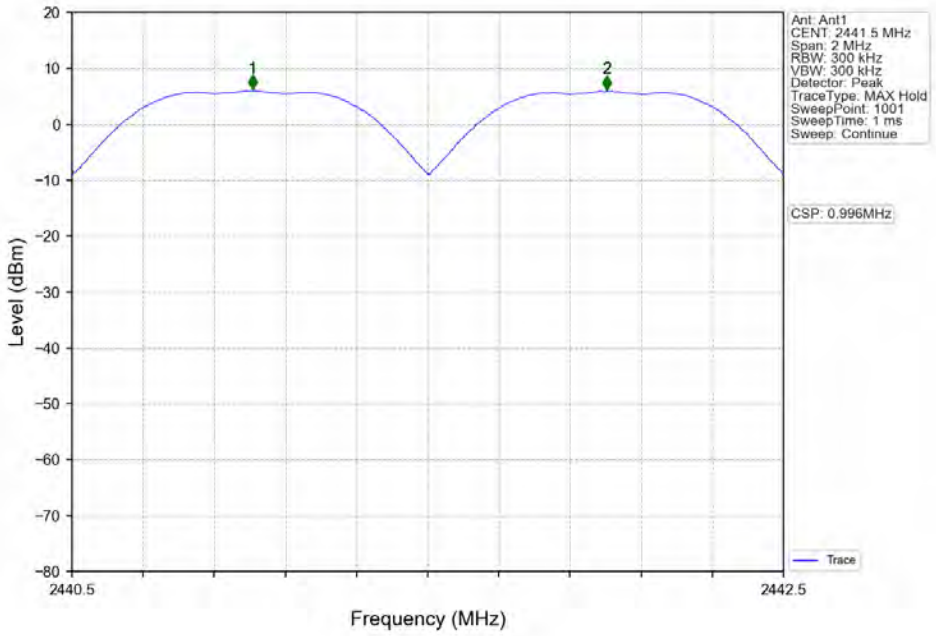
Ant1							
Mode	TX Type	Frequency (MHz)	Packet Type	Channel Separation (MHz)	20dB Bandwidth (MHz)	Limit (MHz)	Verdict
GFSK	SISO	HOPP	DH5	0.996	1.039	>=0.693	Pass
Pi/4DQPSK	SISO	HOPP	2DH5	1.001	1.137	>=0.758	Pass
8DPSK	SISO	HOPP	3DH5	0.986	1.175	>=0.783	Pass

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

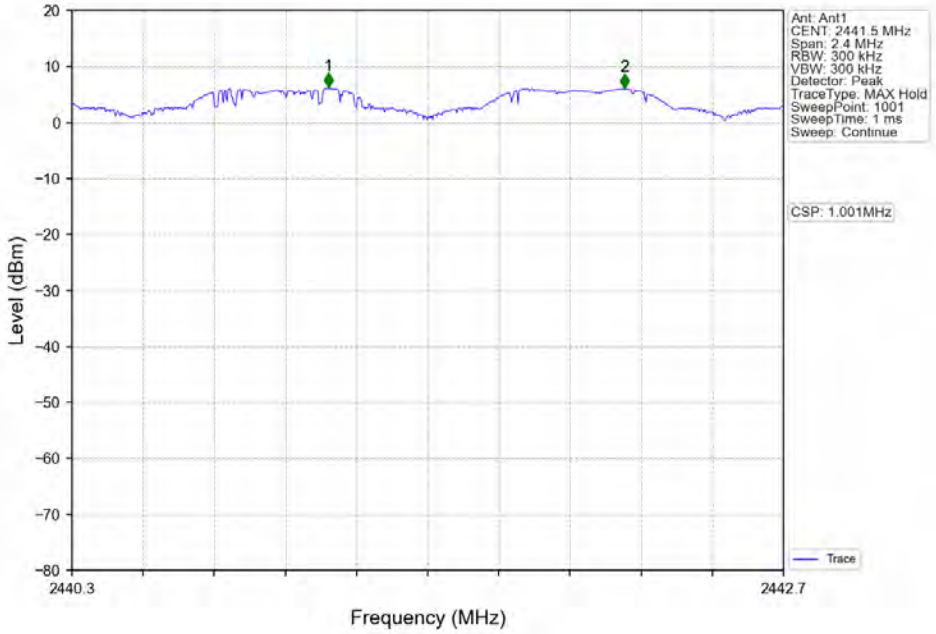
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

3.1.2 Test Graph

GFSK_DH5_HOPP_Ant1_NTNV



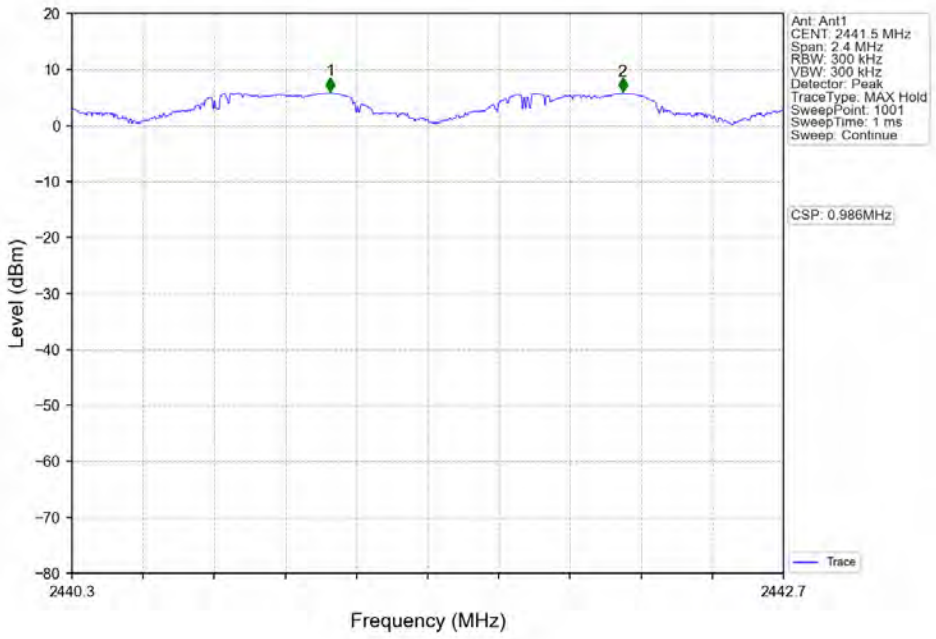
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HOPP_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

4. Number of Hopping Frequencies

4.1 HoppNum

4.1.1 Test Result

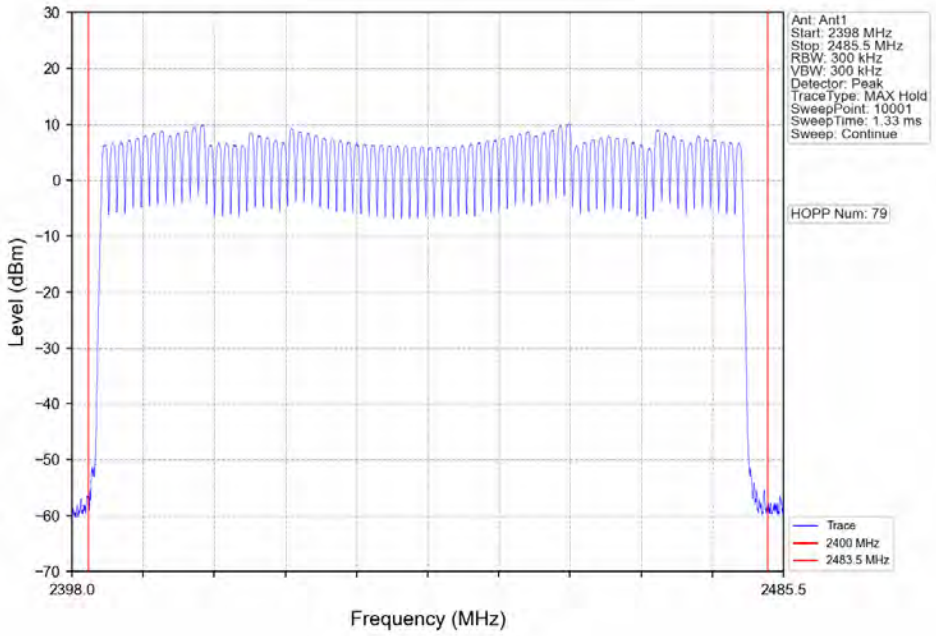
Mode	TX Type	Frequency (MHz)	Packet Type	Num of Hopping Frequencies		Verdict
				ANT1	Limit	
GFSK	SISO	HOPP	DH5	79	>=15	Pass
Pi/4DQPSK	SISO	HOPP	2DH5	79	>=15	Pass
8DPSK	SISO	HOPP	3DH5	79	>=15	Pass

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

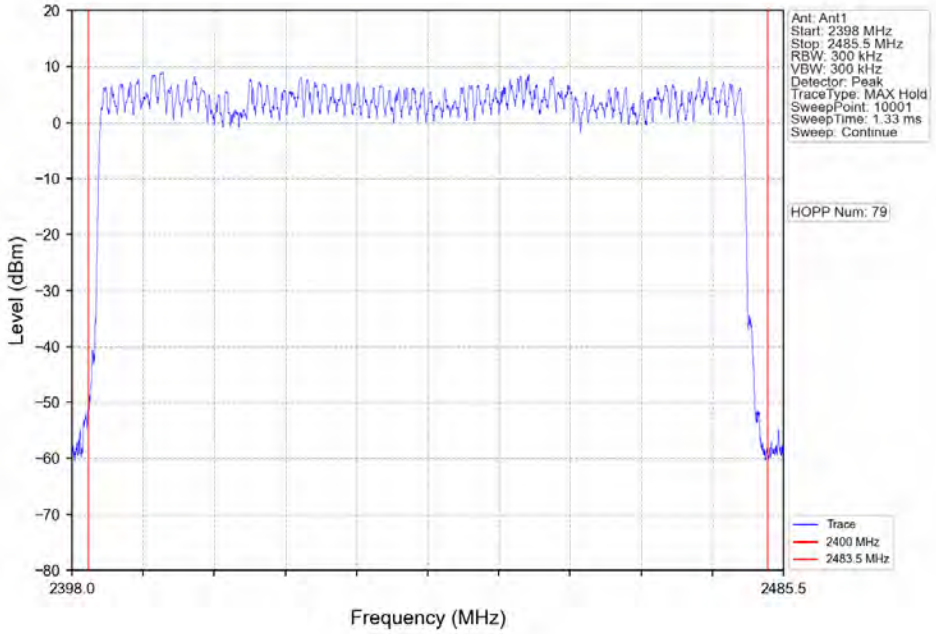
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

4.1.2 Test Graph

GFSK_DH5_HOPP_Ant1_NTNV



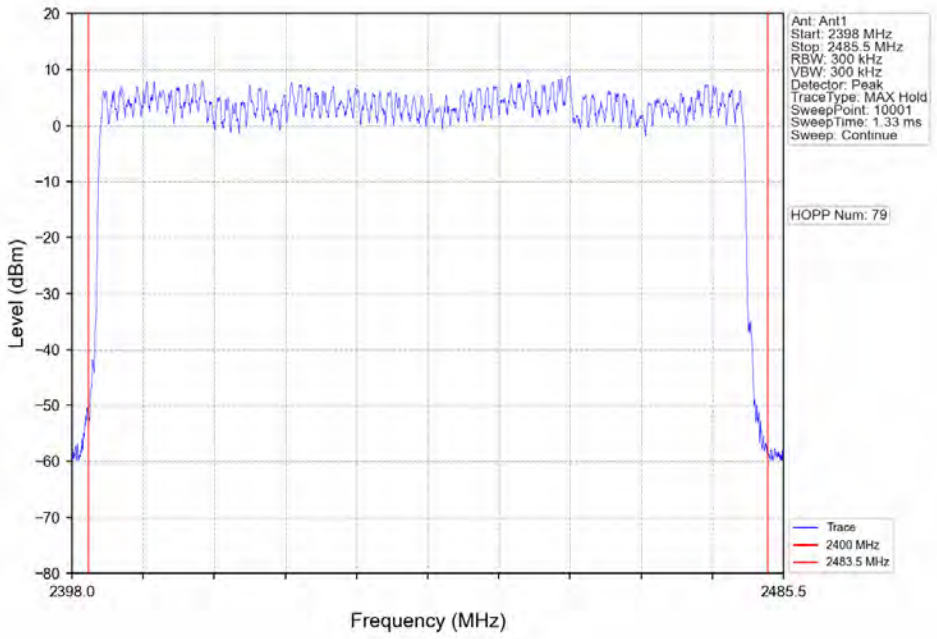
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HOPP_Ant1_NTNV



5. Time of Occupancy (Dwell Time)

5.1 Ant1

5.1.1 Test Result

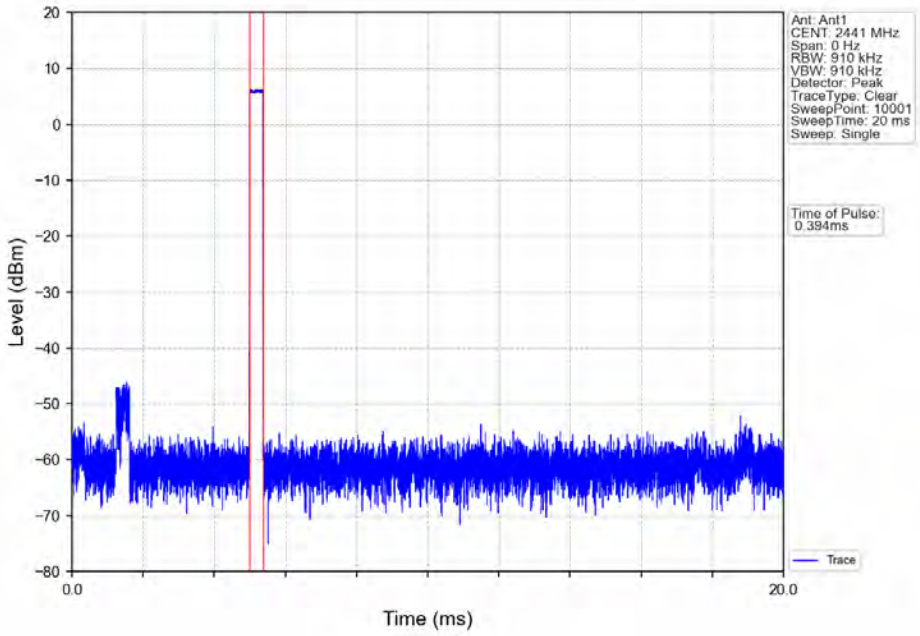
Ant1									
Mode	TX Type	Frequency (MHz)	Packet Type	Duration of Single Pulse (ms)	Observation Period (s)	Num of Pulse in Observation Period	Dwell Time (ms)	Limit (ms)	Verdict
GFSK	SISO	HOPP	DH1	0.394	31.600	305	120.170	<=400	Pass
			DH3	1.650	31.600	160	264.000	<=400	Pass
			DH5	2.898	31.600	109	315.882	<=400	Pass
Pi/4DQPSK	SISO	HOPP	2DH1	0.388	31.600	316	122.608	<=400	Pass
			2DH3	1.640	31.600	161	264.040	<=400	Pass
			2DH5	2.902	31.600	94	272.788	<=400	Pass
8DPSK	SISO	HOPP	3DH1	0.400	31.600	320	128.000	<=400	Pass
			3DH3	1.652	31.600	160	264.320	<=400	Pass
			3DH5	2.902	31.600	98	284.396	<=400	Pass

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

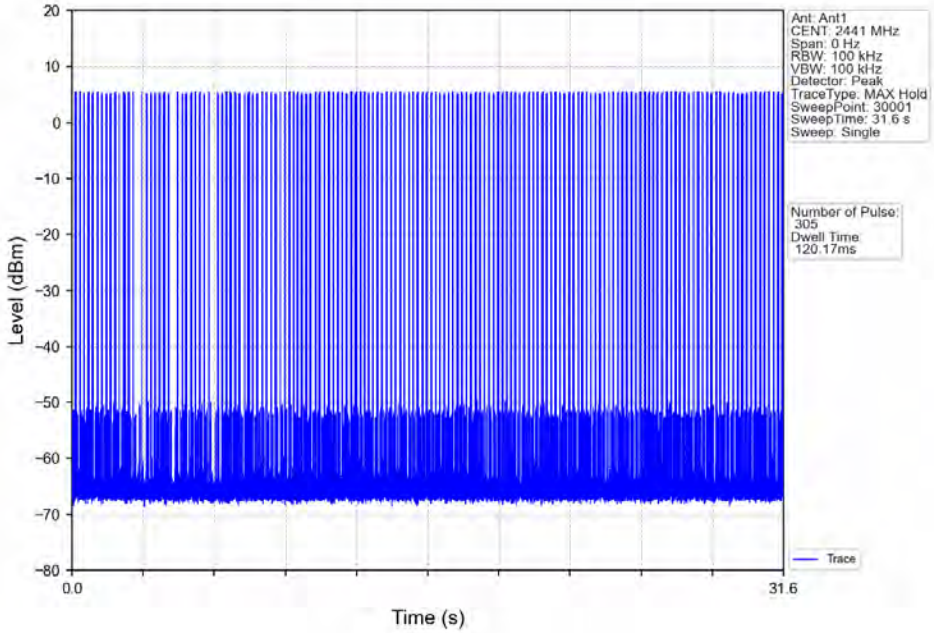
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

5.1.2 Test Graph

GFSK_DH1_HOPP_Ant1_NTNV



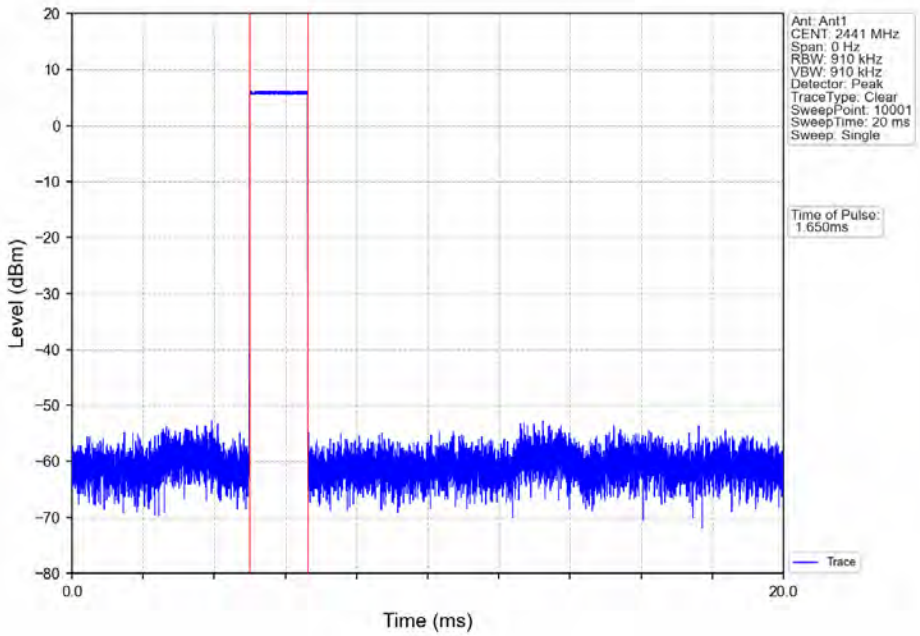
GFSK_DH1_HOPP_Ant1_NTNV



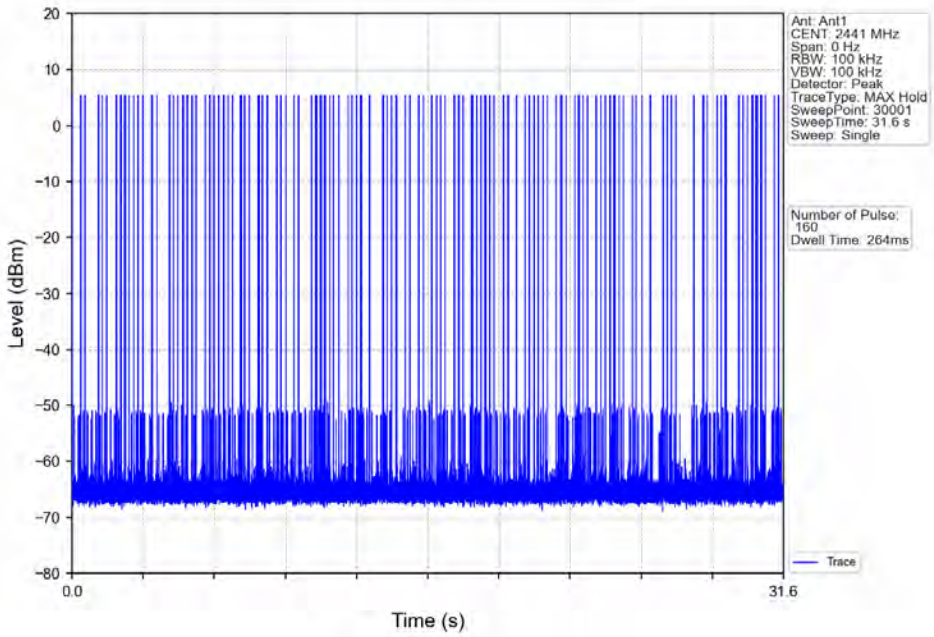
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH3_HOPP_Ant1_NTNV

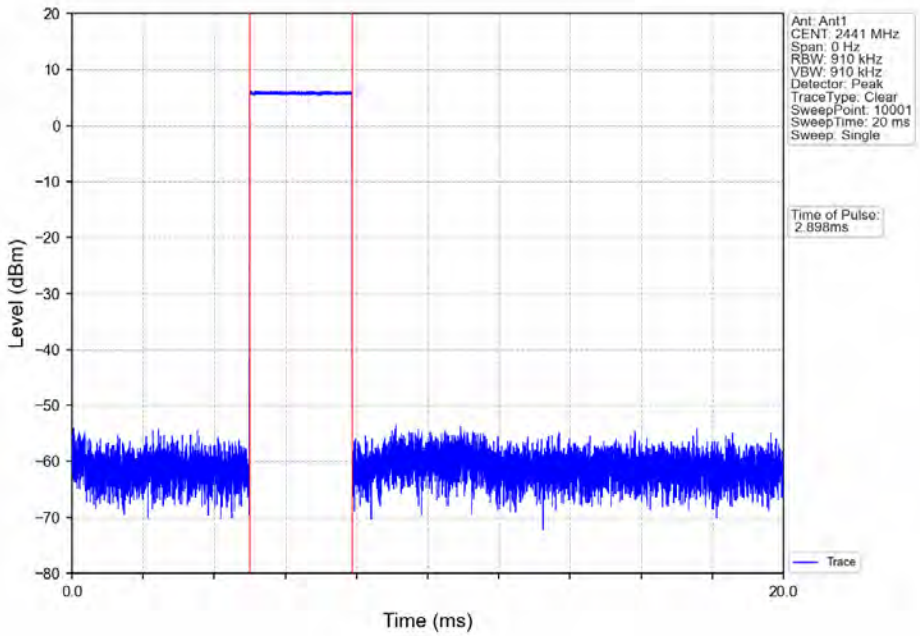


GFSK_DH3_HOPP_Ant1_NTNV

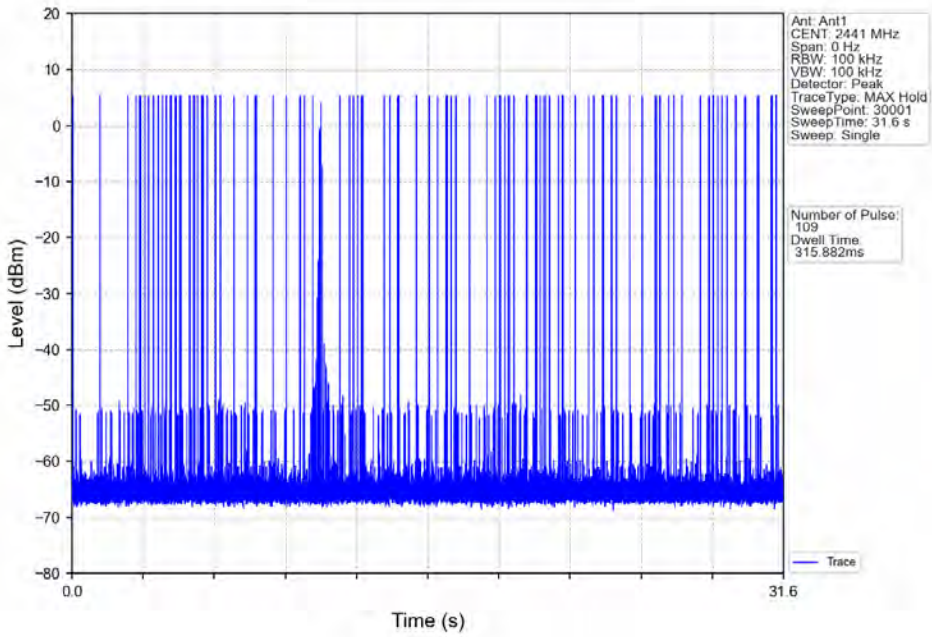


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HOPP_Ant1_NTNV

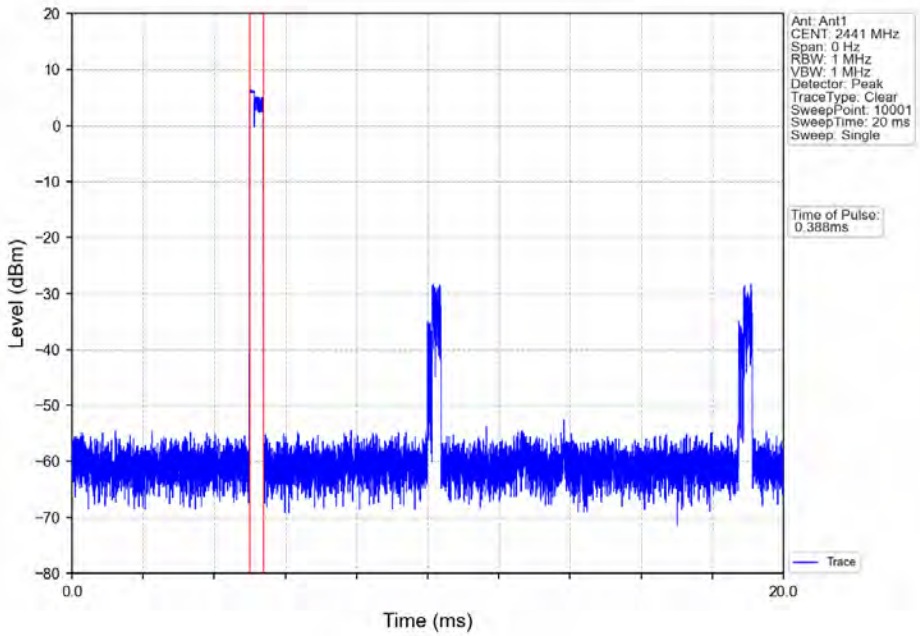


GFSK_DH5_HOPP_Ant1_NTNV

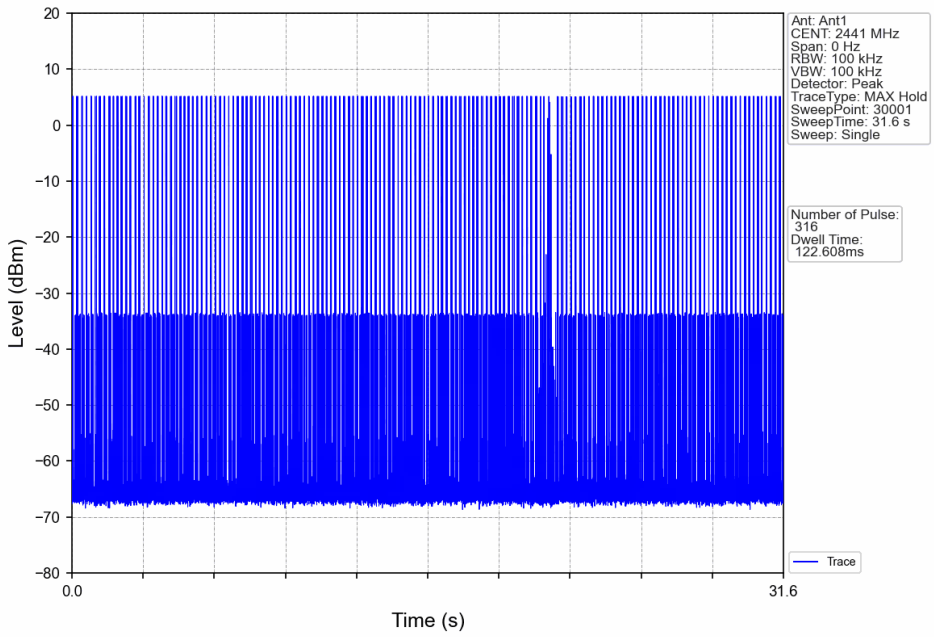


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH1_HOPP_Ant1_NTNV



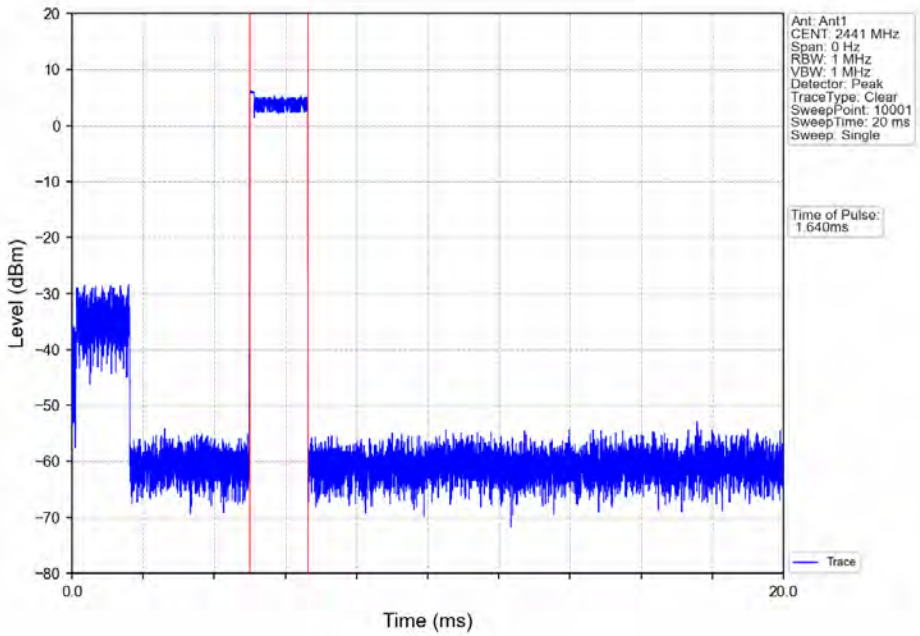
Pi/4DQPSK_2DH1_HOPP_Ant1_NTNV



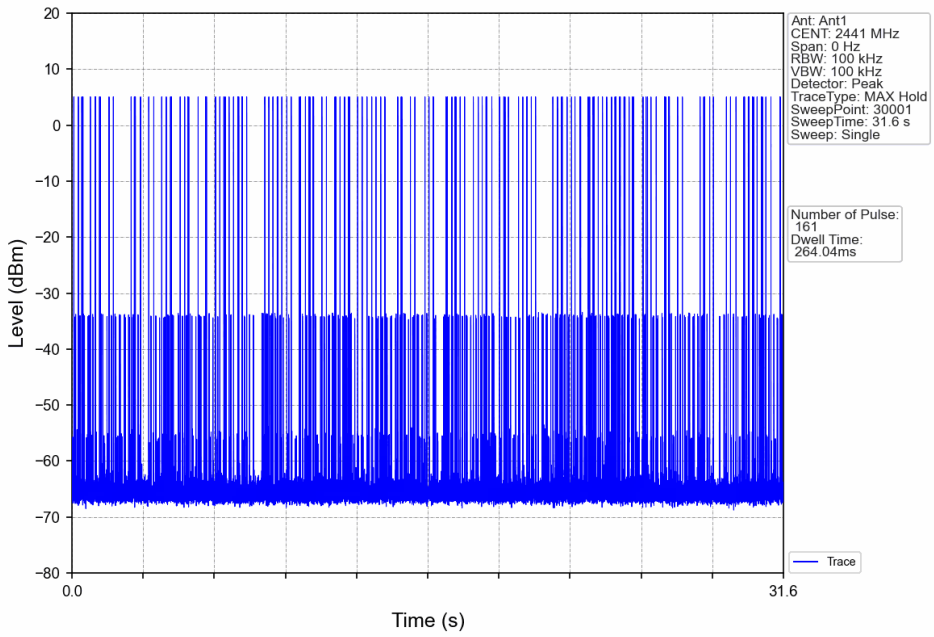
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH3_HOPP_Ant1_NTNV



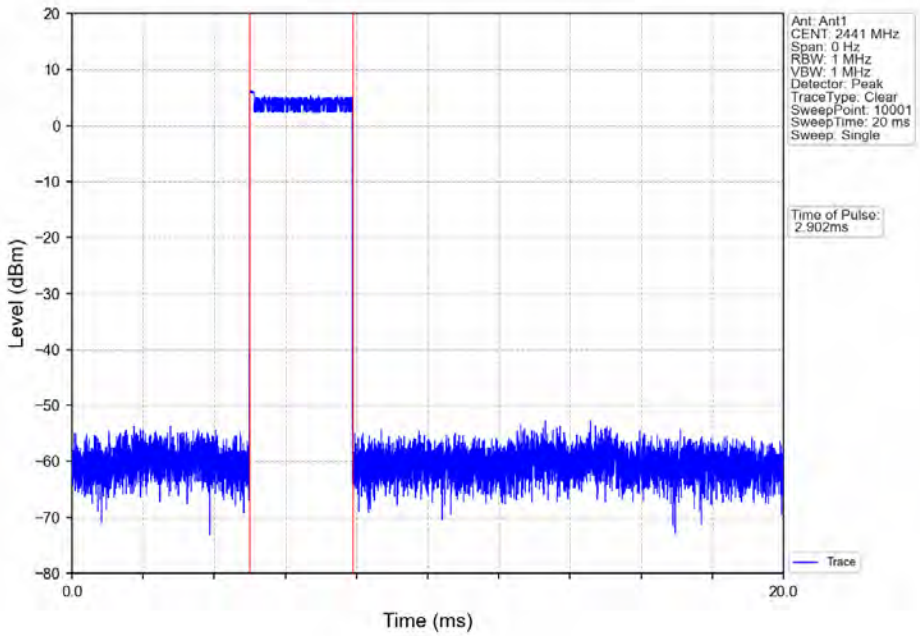
Pi/4DQPSK_2DH3_HOPP_Ant1_NTNV



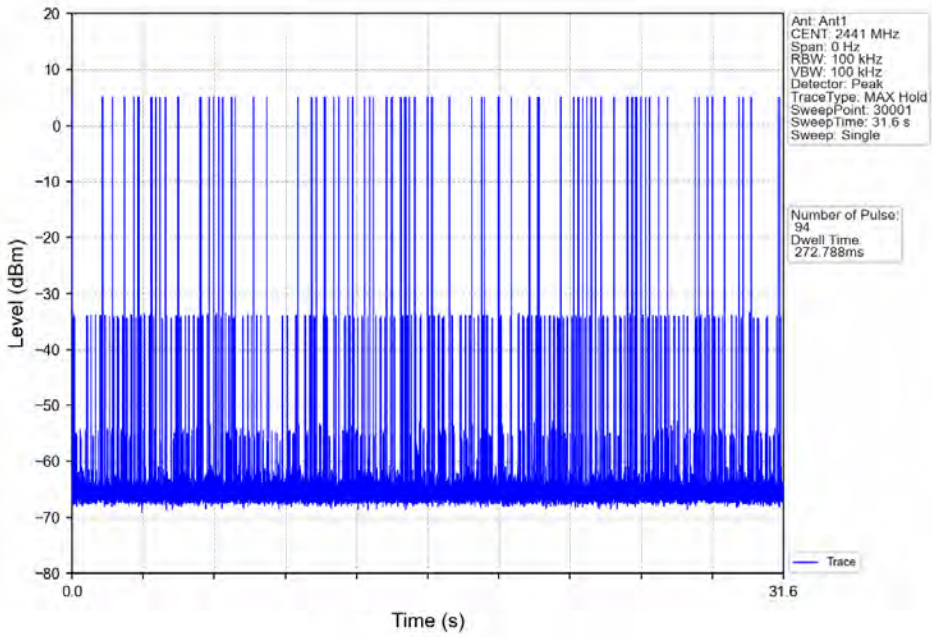
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV

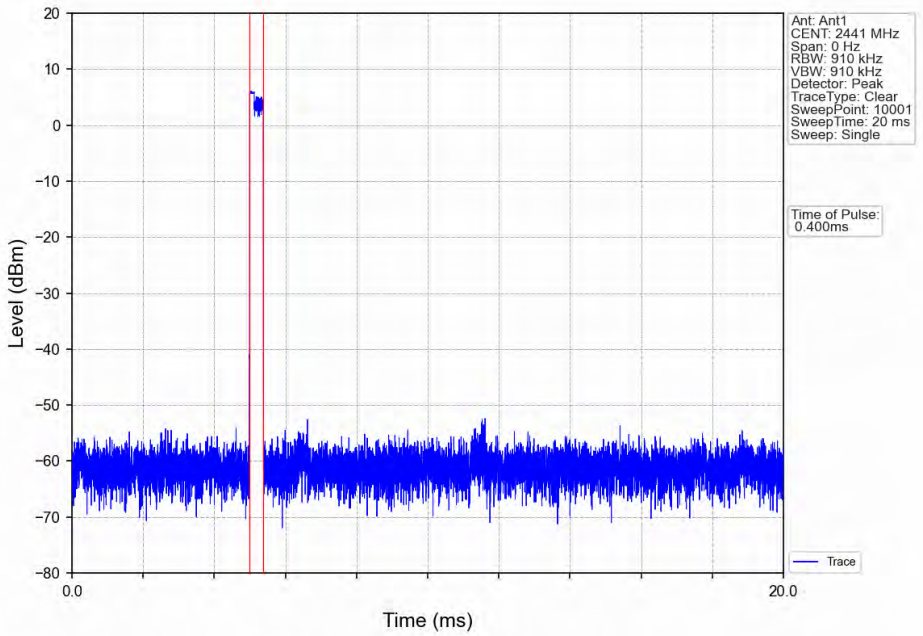


Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV

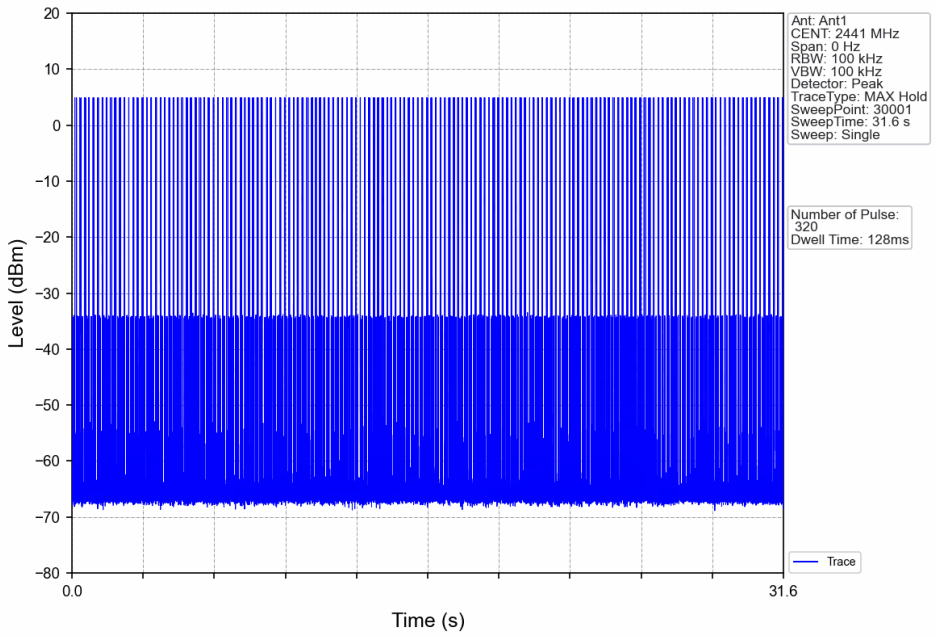


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH1_HOPP_Ant1_NTNV



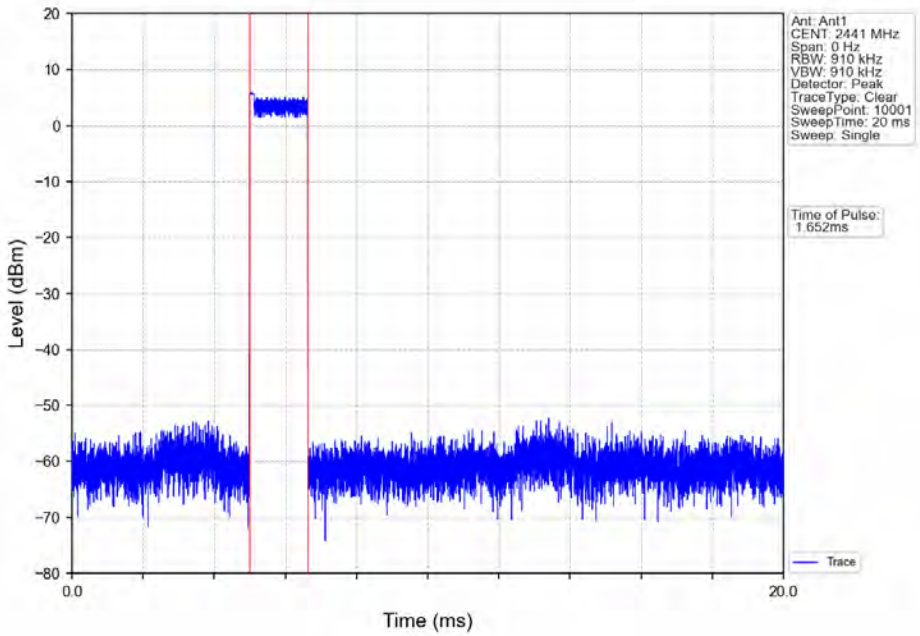
8DPSK_3DH1_HOPP_Ant1_NTNV



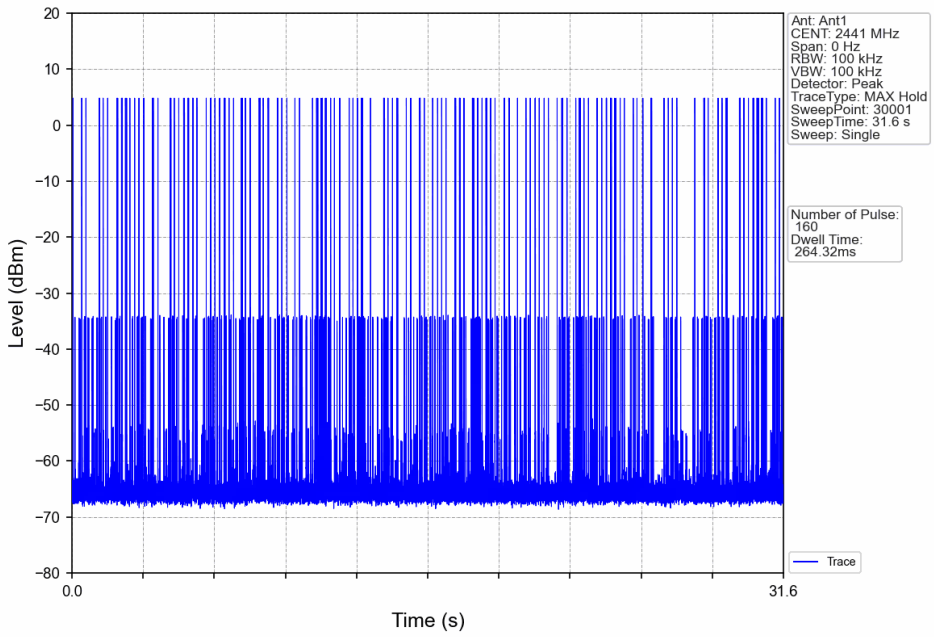
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH3_HOPP_Ant1_NTNV

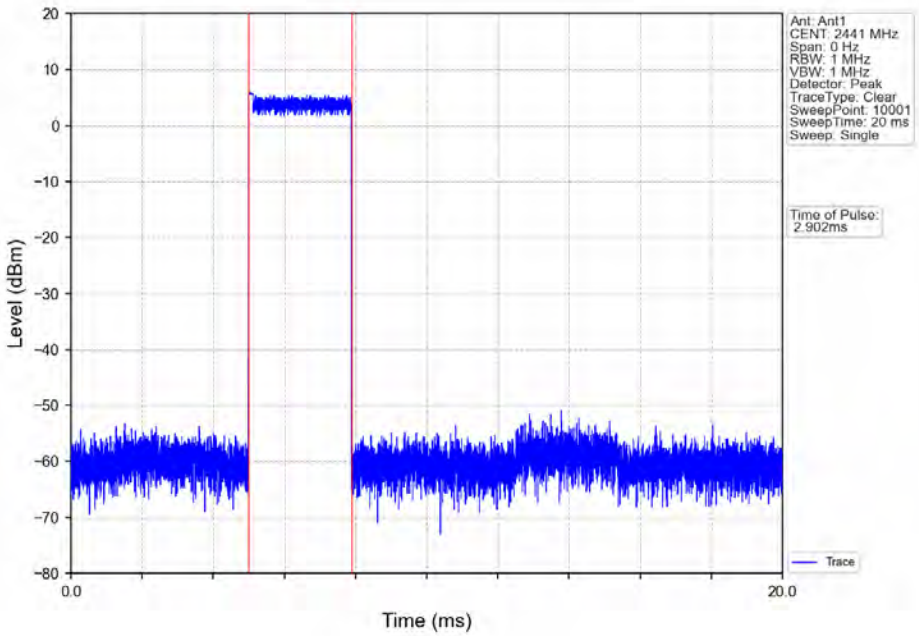


8DPSK_3DH3_HOPP_Ant1_NTNV

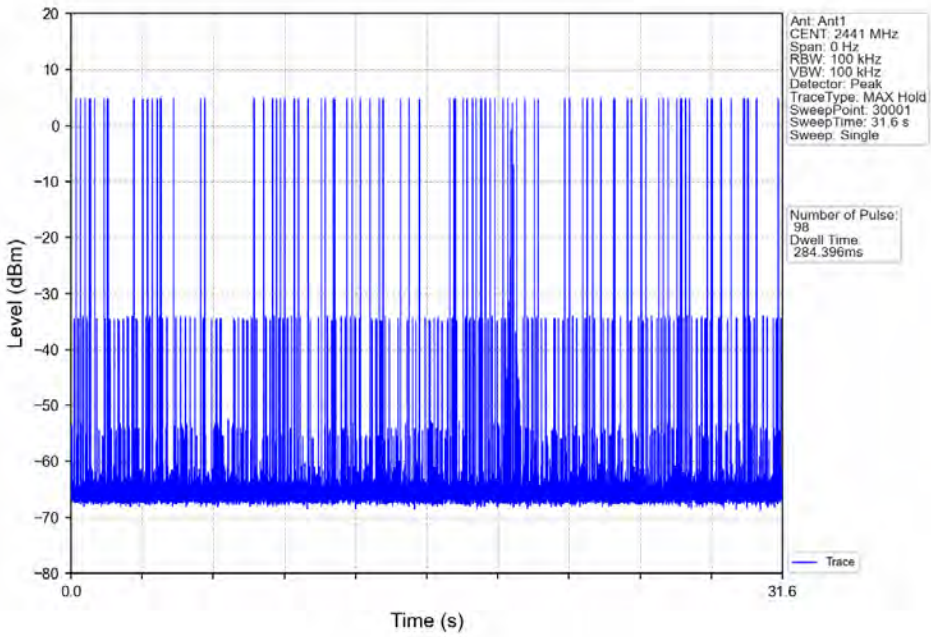


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HOPP_Ant1_NTNV



8DPSK_3DH5_HOPP_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6. Unwanted Emissions In Non-restricted Frequency Bands

6.1 Ref

6.1.1 Test Result

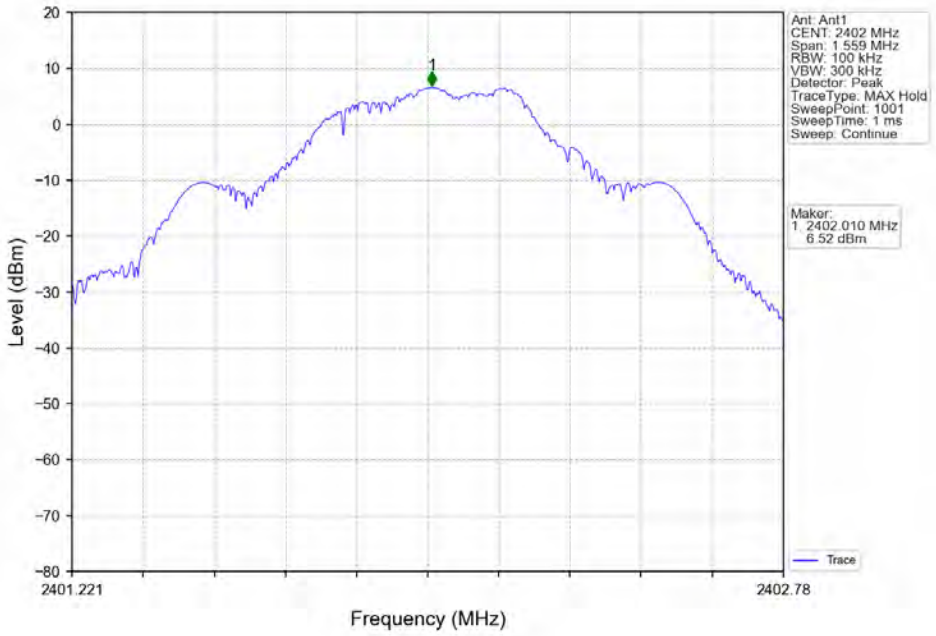
Mode	TX Type	Frequency (MHz)	Packet Type	ANT	Level of Reference (dBm)
GFSK	SISO	2402	DH5	1	6.52
		2441	DH5	1	7.01
		2480	DH5	1	7.04
Pi/4DQPSK	SISO	2402	2DH5	1	6.28
		2441	2DH5	1	6.72
		2480	2DH5	1	7.65
8DPSK	SISO	2402	3DH5	1	6.21
		2441	3DH5	1	6.92
		2480	3DH5	1	7.44
Note1: Refer to FCC Part 15.247 (d) and ANSI C63.10-2013, the channel contains the maximum PSD level was used to establish the reference level.					

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

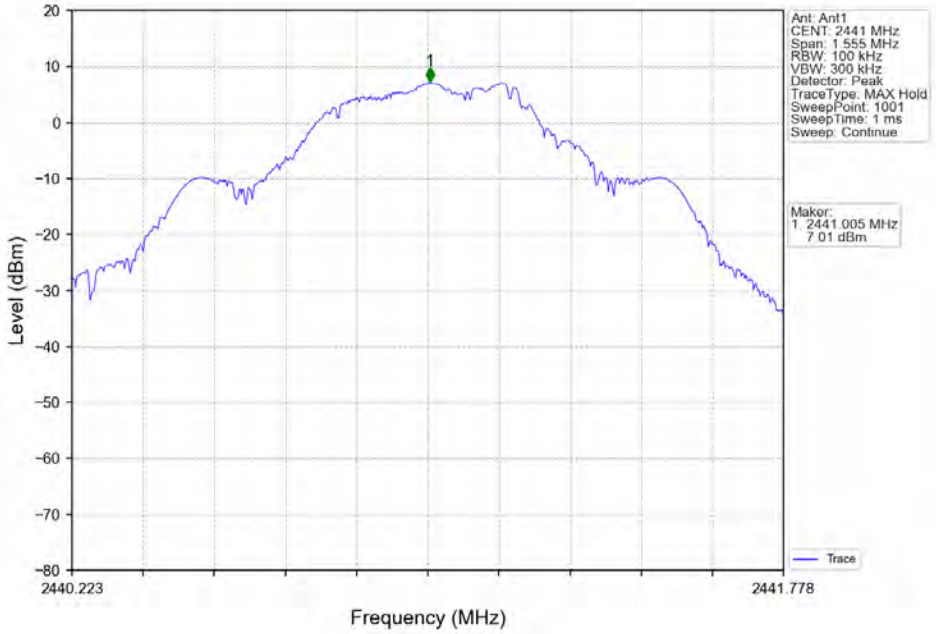
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.1.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV



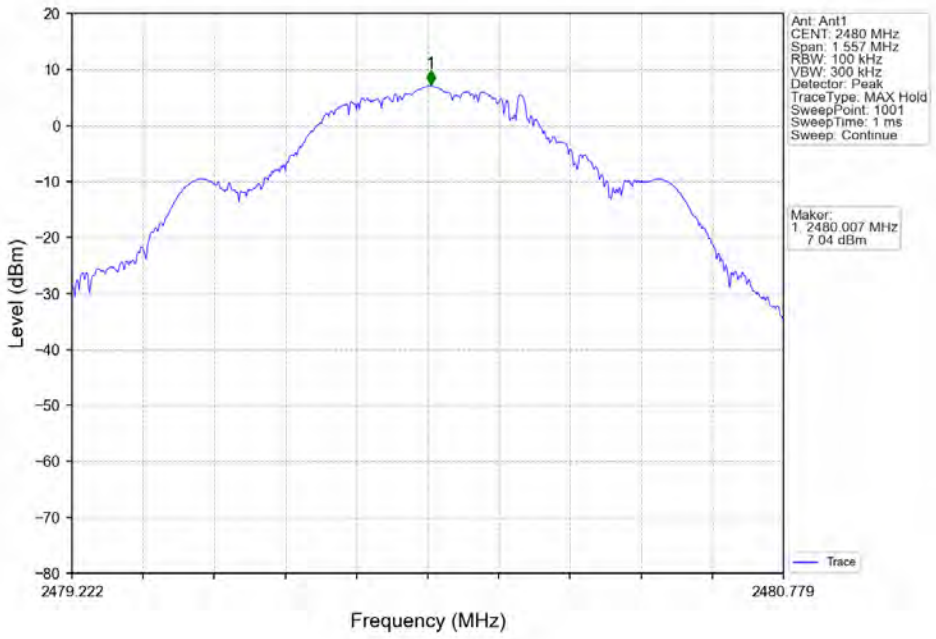
GFSK_DH5_MCH_2441MHz_Ant1_NTNV



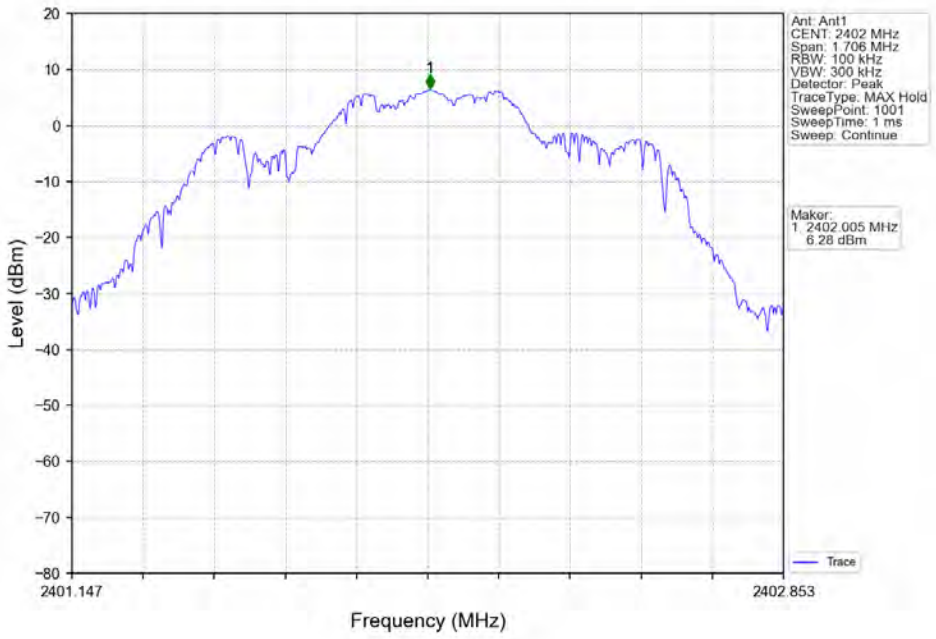
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HCH_2480MHz_Ant1_NTNV



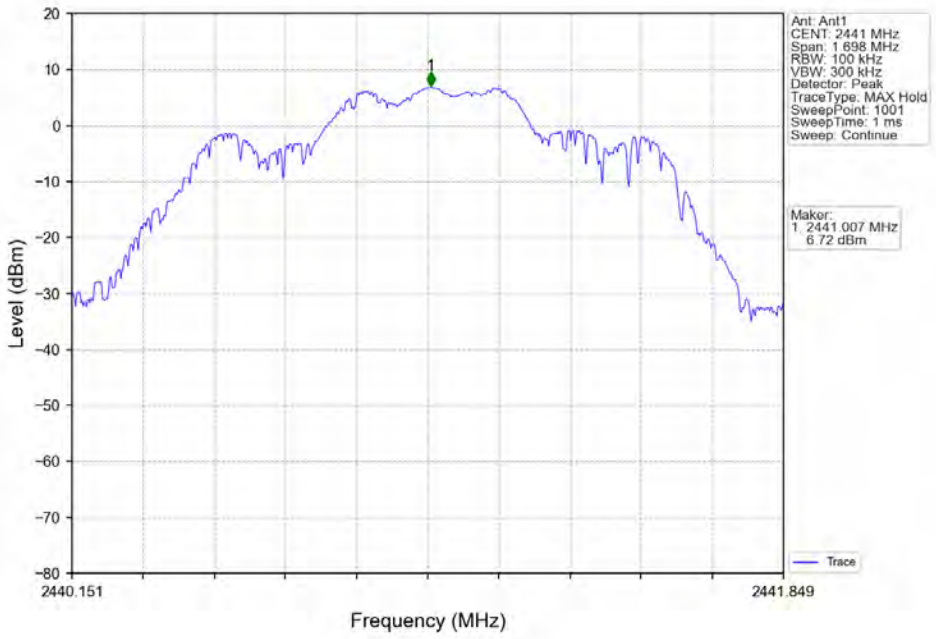
Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



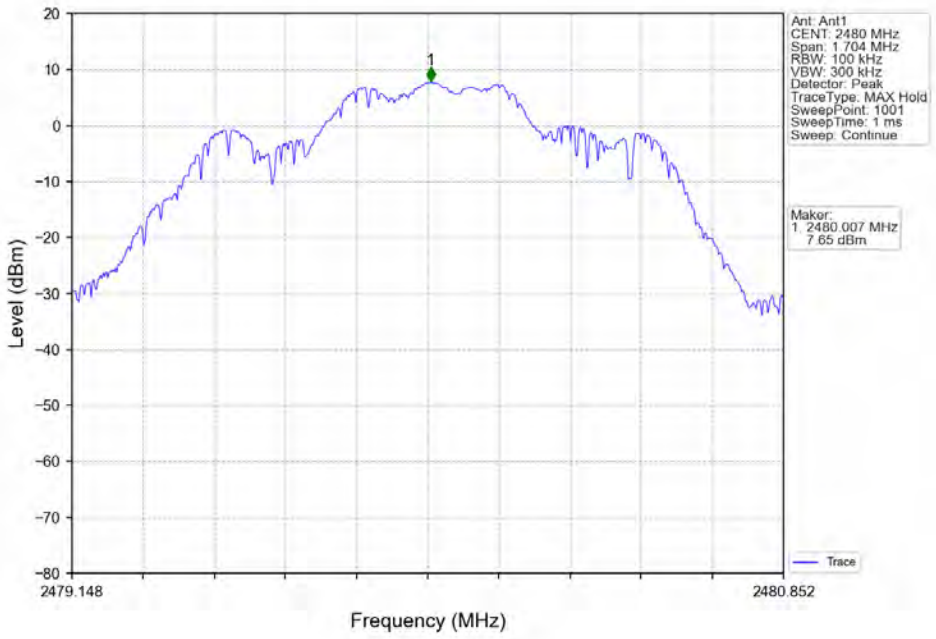
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



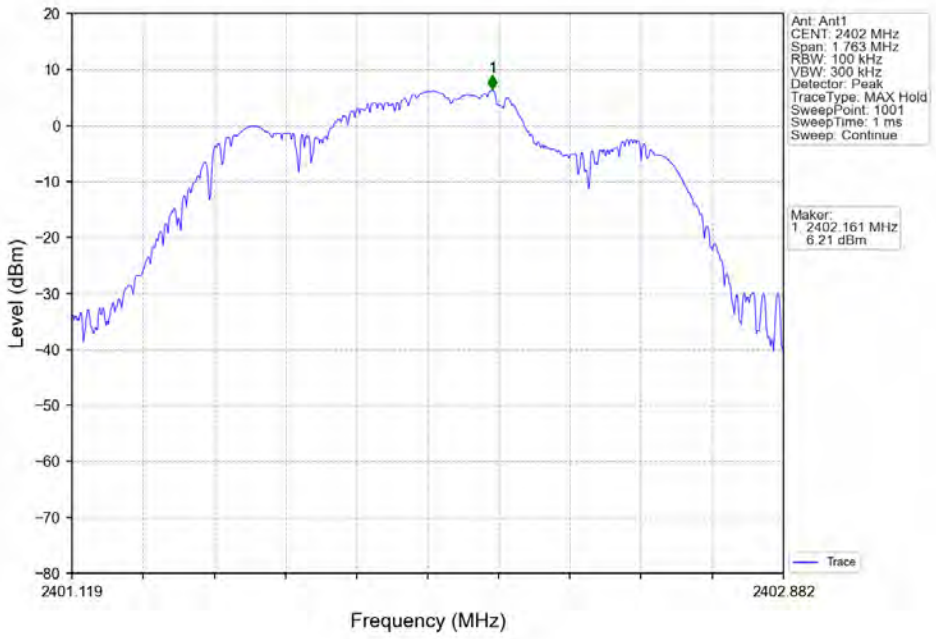
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



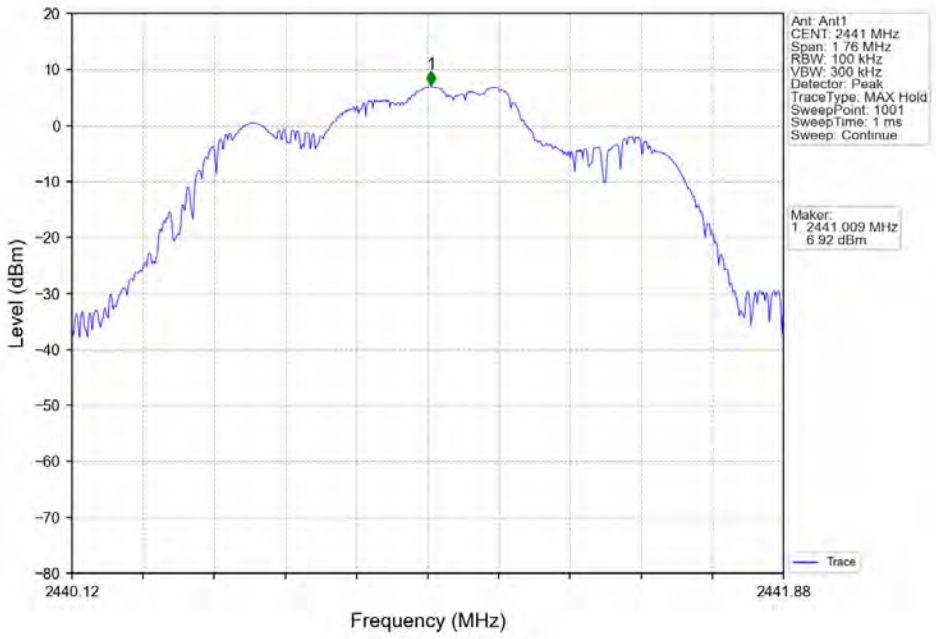
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



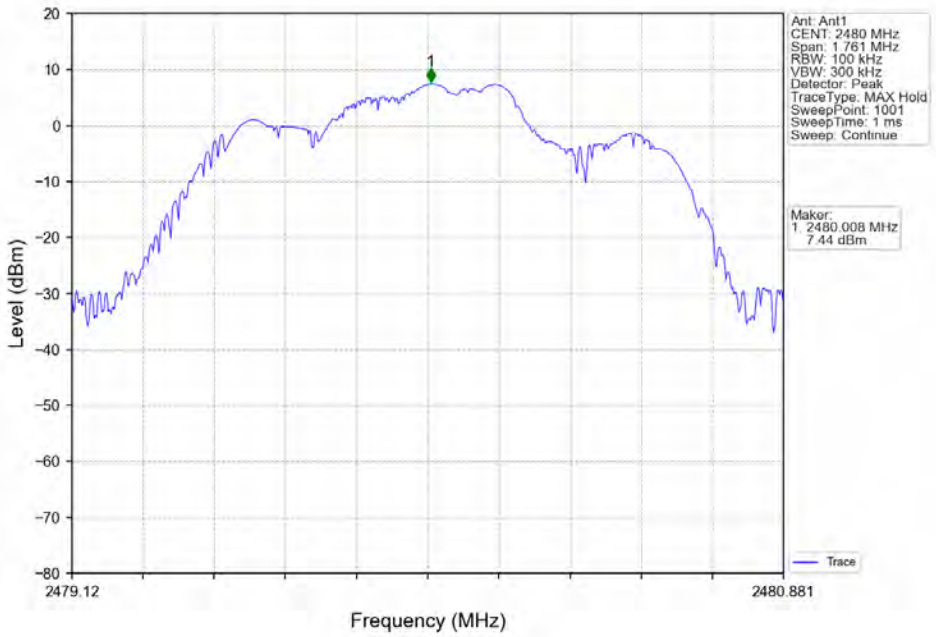
8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.2 CSE

6.2.1 Test Result

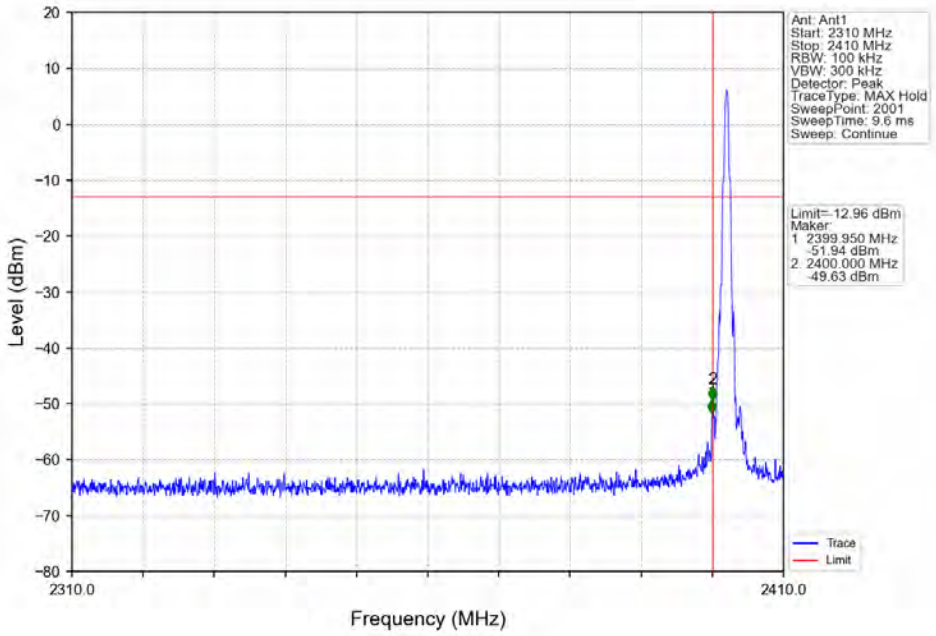
Mode	TX Type	Frequency (MHz)	Packet Type	ANT	Level of Reference (dBm)	Limit (dBm)	Verdict
GFSK	SISO	2402	DH5	1	7.04	-12.96	Pass
		2441	DH5	1	7.04	-12.96	Pass
		2480	DH5	1	7.04	-12.96	Pass
		HOPP	DH5	1	7.04	-12.96	Pass
					7.04	-12.96	Pass
Pi/4DQPSK	SISO	2402	2DH5	1	7.65	-12.35	Pass
		2441	2DH5	1	7.65	-12.35	Pass
		2480	2DH5	1	7.65	-12.35	Pass
		HOPP	2DH5	1	7.65	-12.35	Pass
					7.65	-12.35	Pass
8DPSK	SISO	2402	3DH5	1	7.44	-12.56	Pass
		2441	3DH5	1	7.44	-12.56	Pass
		2480	3DH5	1	7.44	-12.56	Pass
		HOPP	3DH5	1	7.44	-12.56	Pass
					7.44	-12.56	Pass
Note1: Refer to FCC Part 15.247 (d) and ANSI C63.10-2013, the channel contains the maximum PSD level was used to establish the reference level.							

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

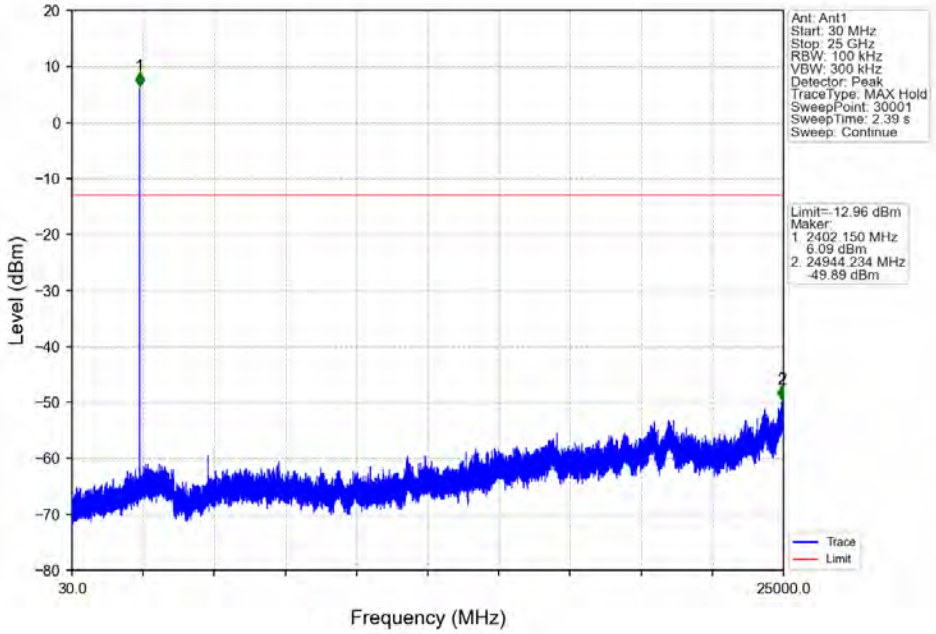
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

6.2.2 Test Graph

GFSK_DH5_LCH_2402MHz_Ant1_NTNV

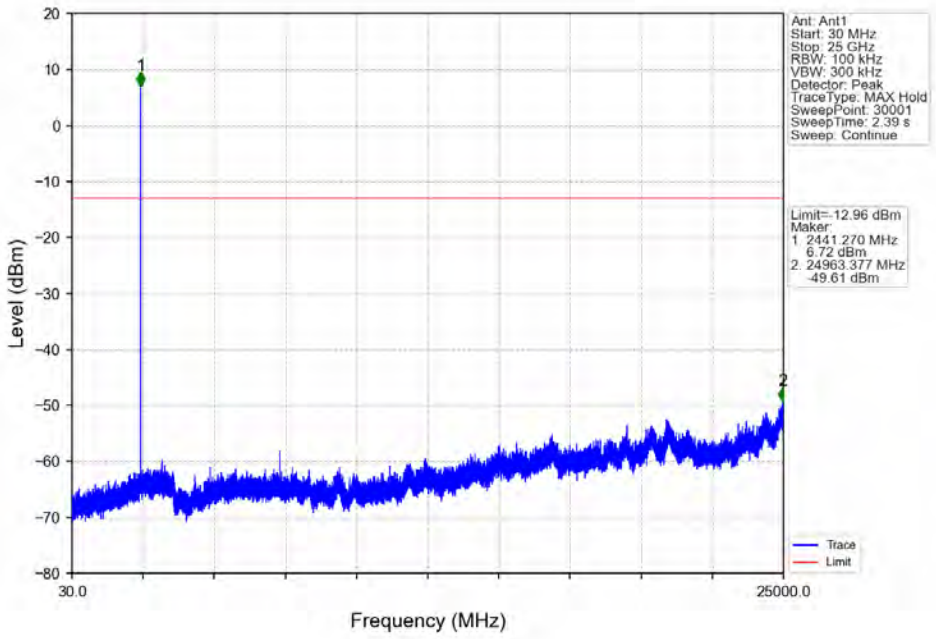


GFSK_DH5_LCH_2402MHz_Ant1_NTNV

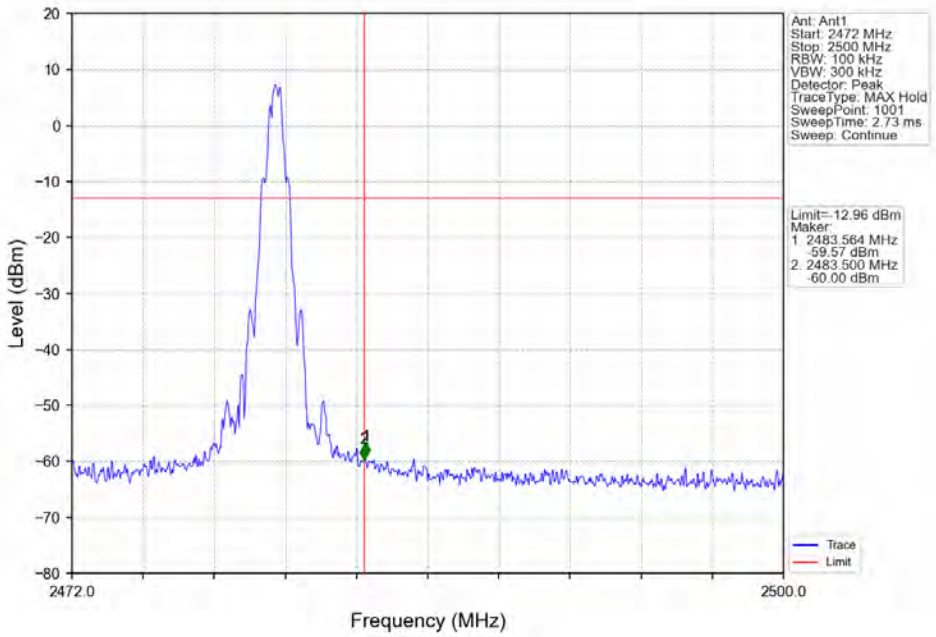


Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_MCH_2441MHz_Ant1_NTNV



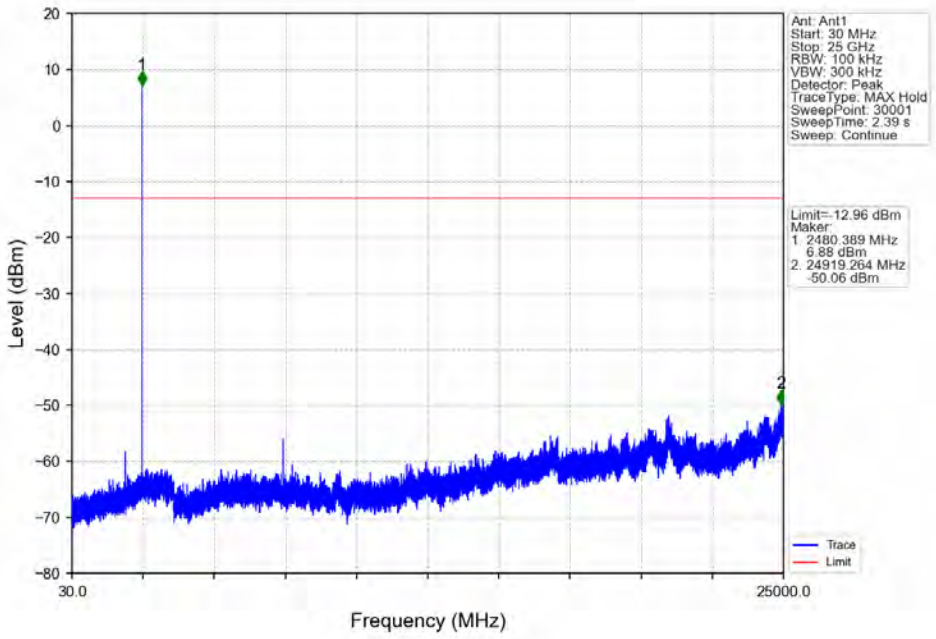
GFSK_DH5_HCH_2480MHz_Ant1_NTNV



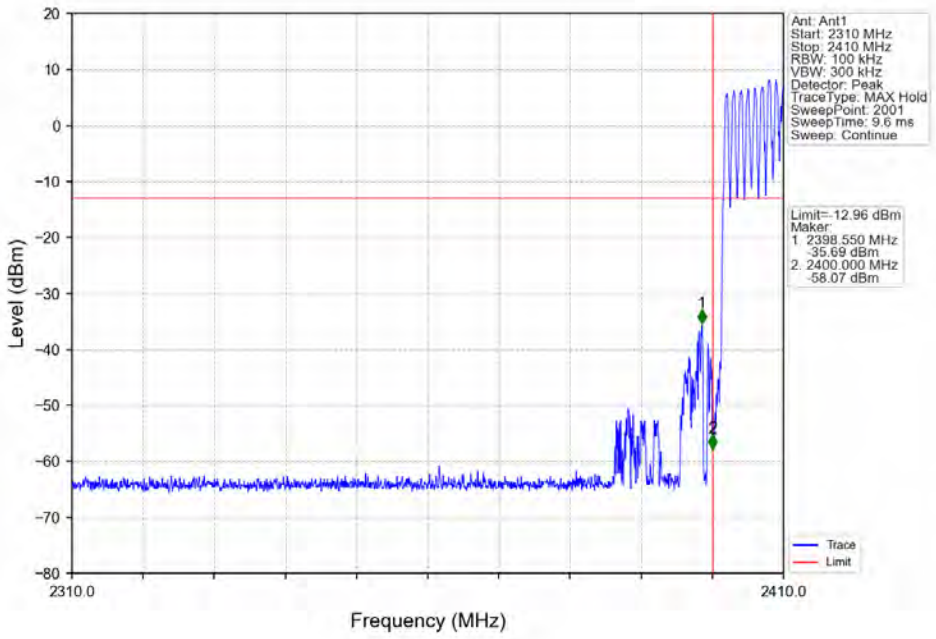
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HCH_2480MHz_Ant1_NTNV



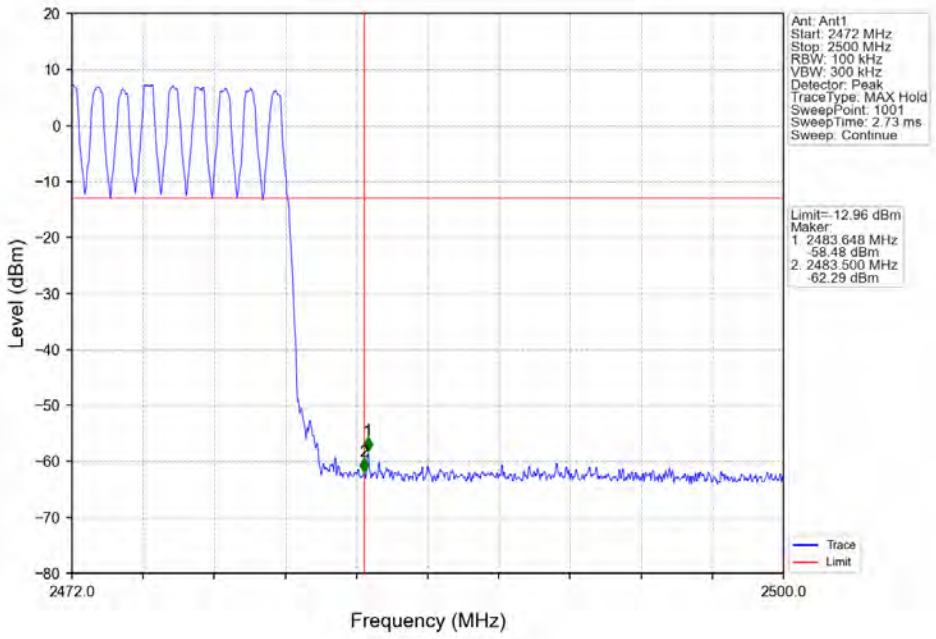
GFSK_DH5_HOPP_Ant1_NTNV



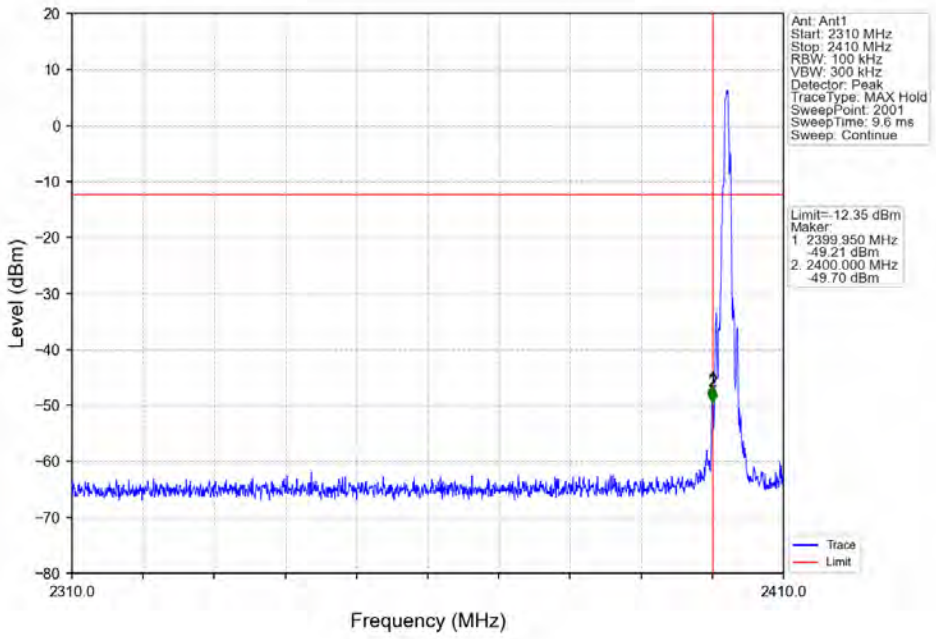
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

GFSK_DH5_HOPP_Ant1_NTNV



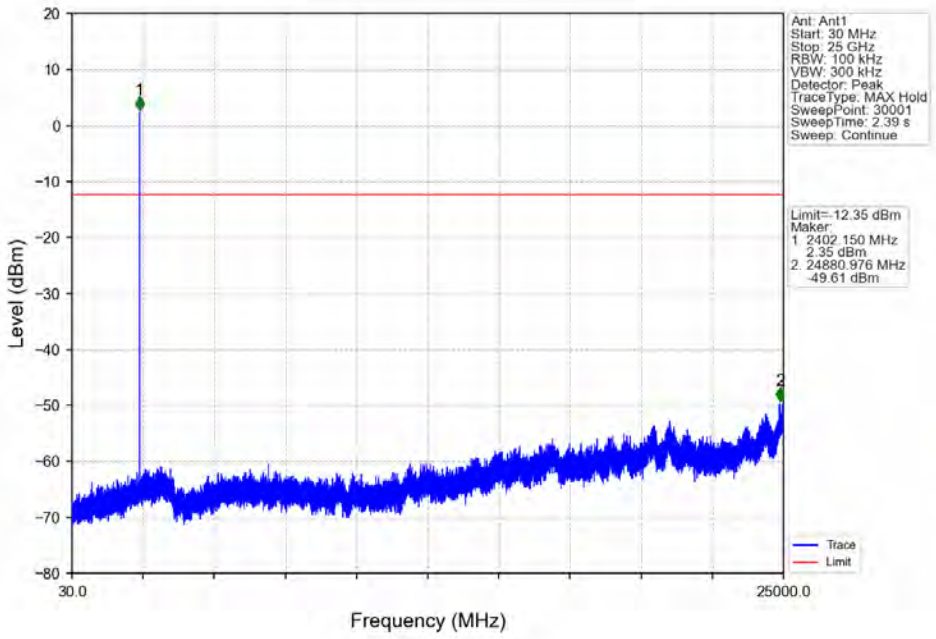
Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



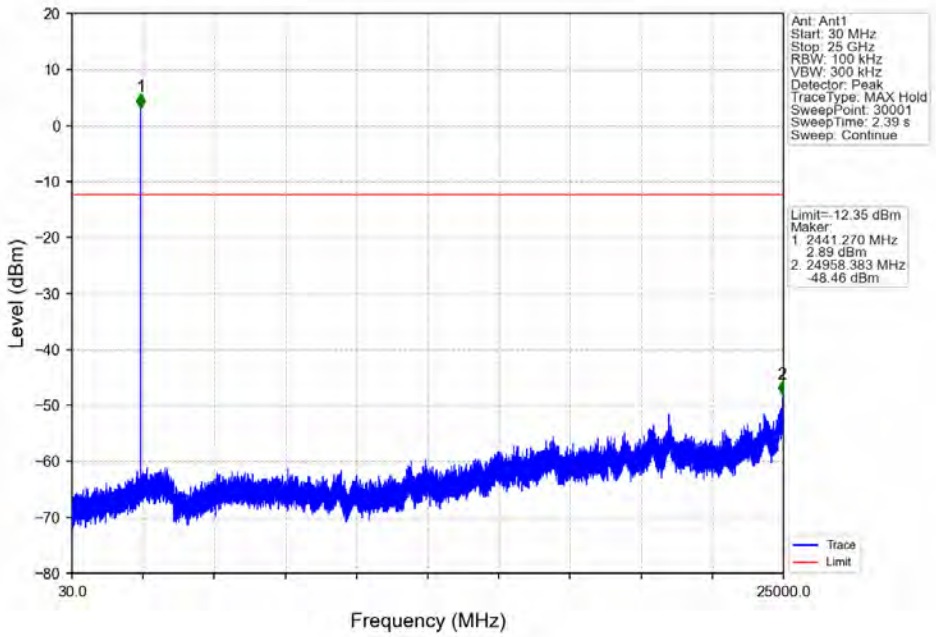
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_LCH_2402MHz_Ant1_NTNV



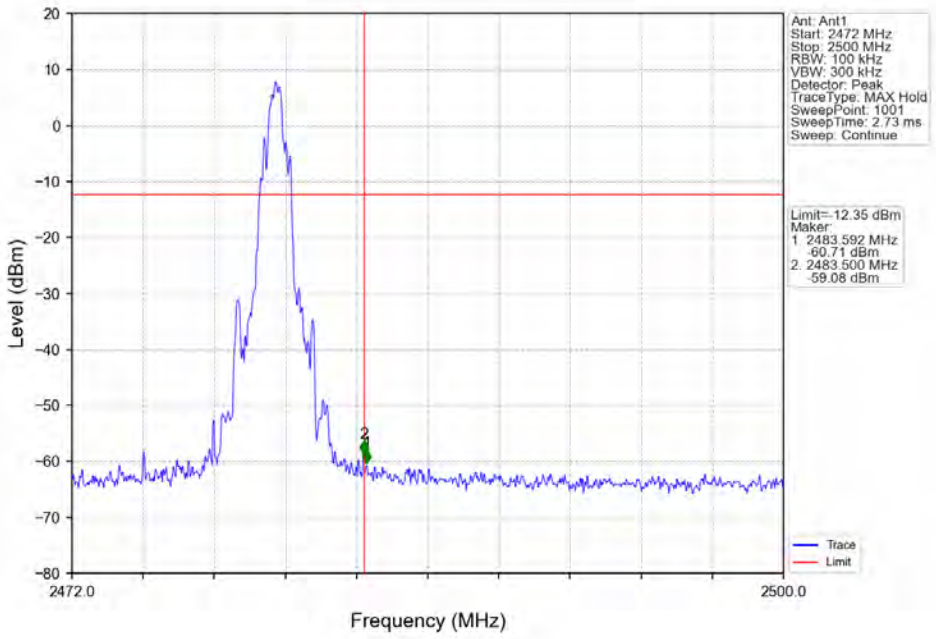
Pi/4DQPSK_2DH5_MCH_2441MHz_Ant1_NTNV



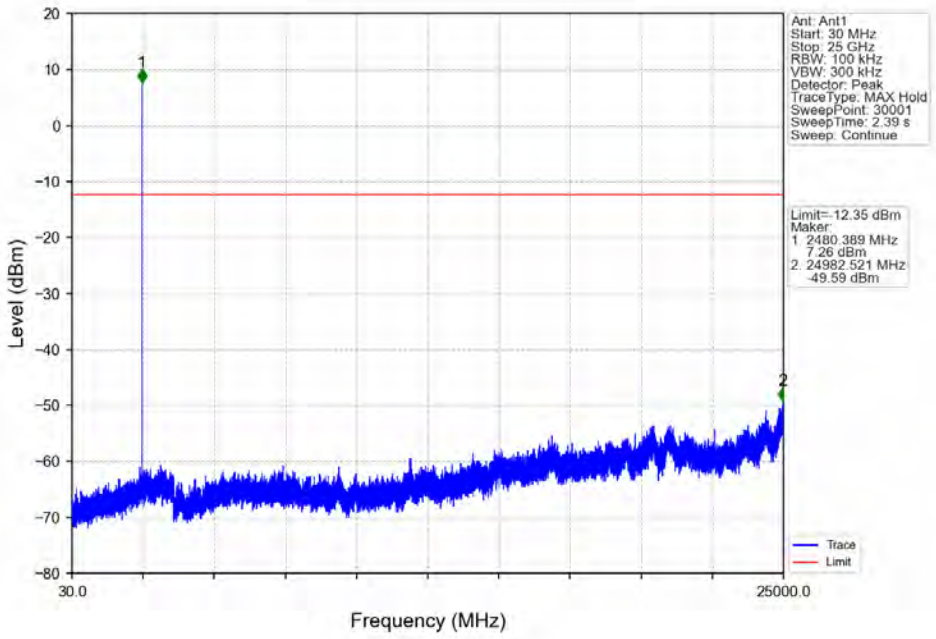
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



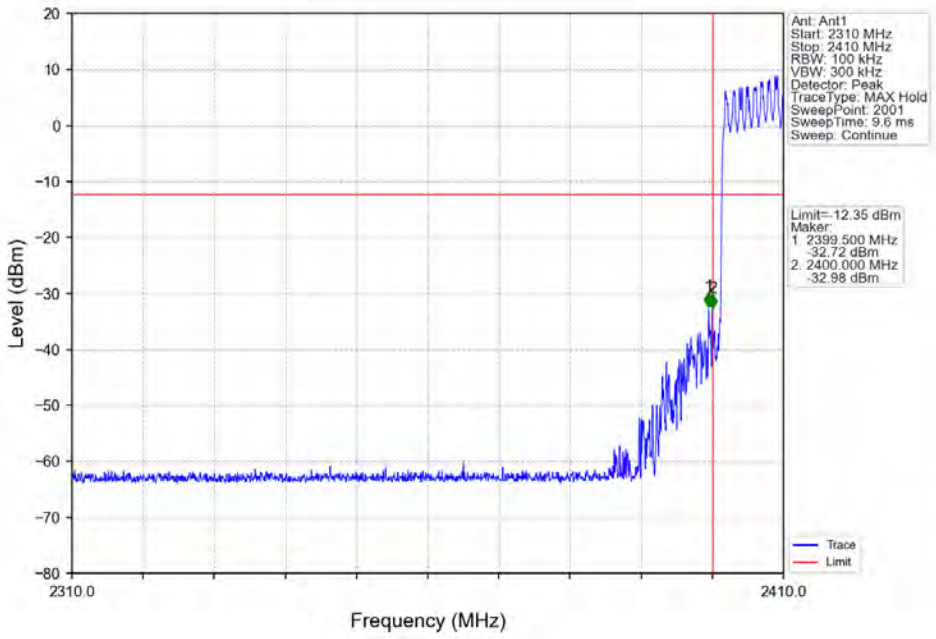
Pi/4DQPSK_2DH5_HCH_2480MHz_Ant1_NTNV



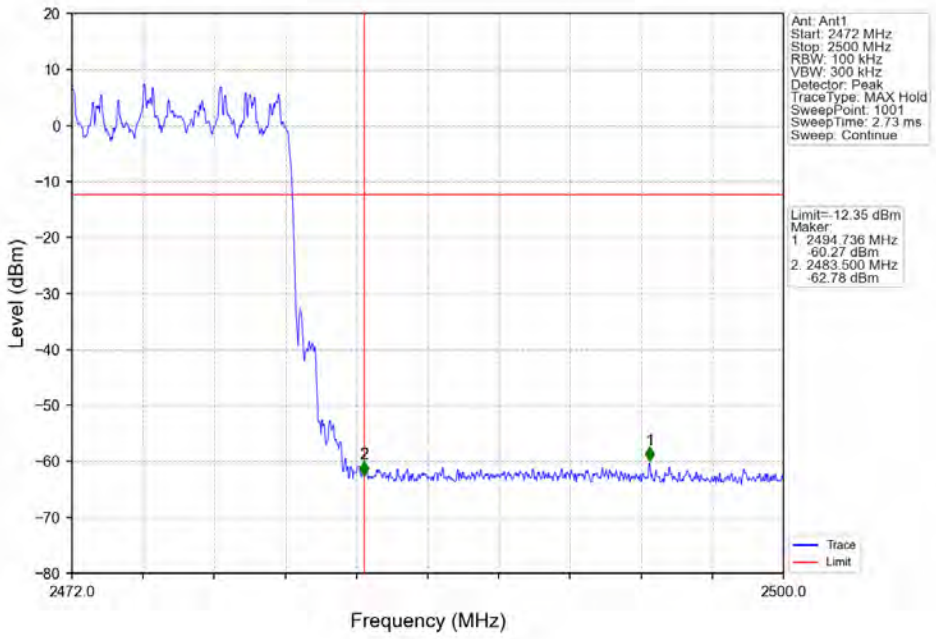
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



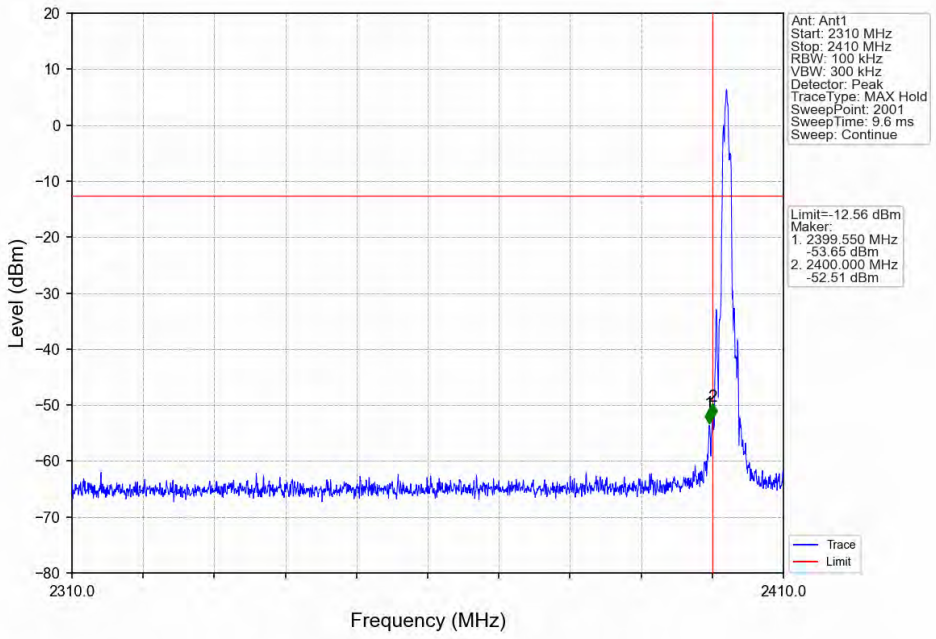
Pi/4DQPSK_2DH5_HOPP_Ant1_NTNV



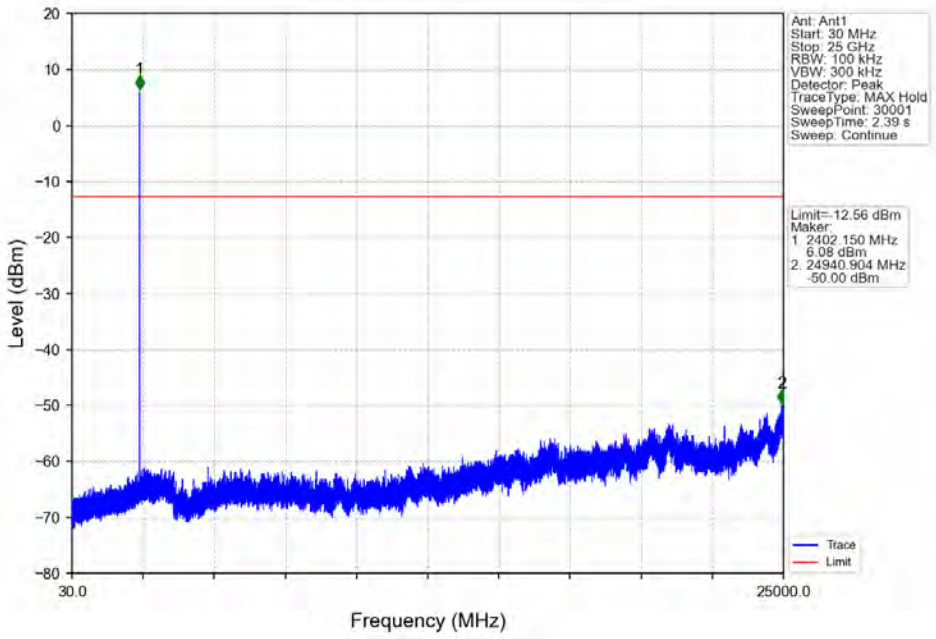
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



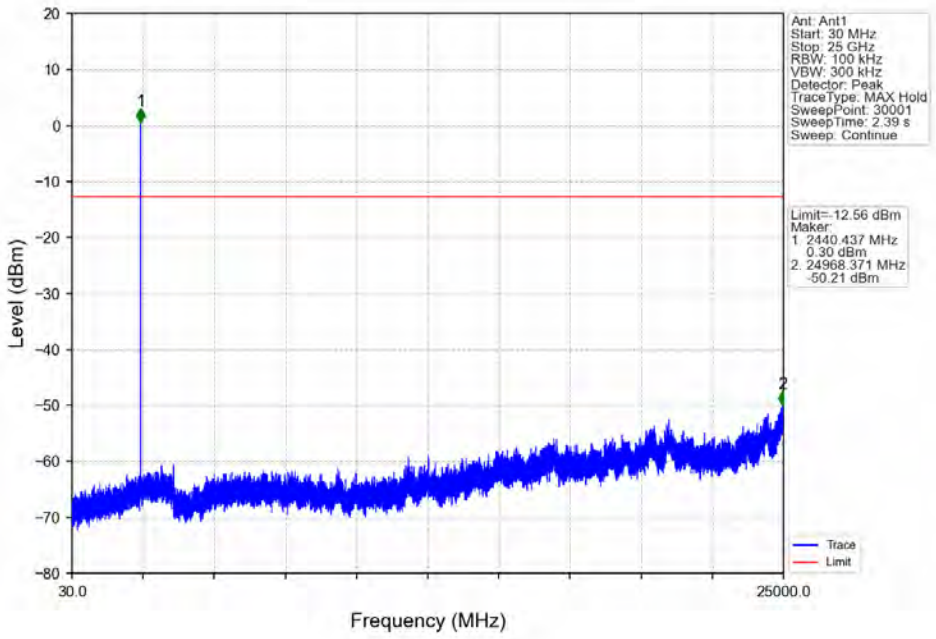
8DPSK_3DH5_LCH_2402MHz_Ant1_NTNV



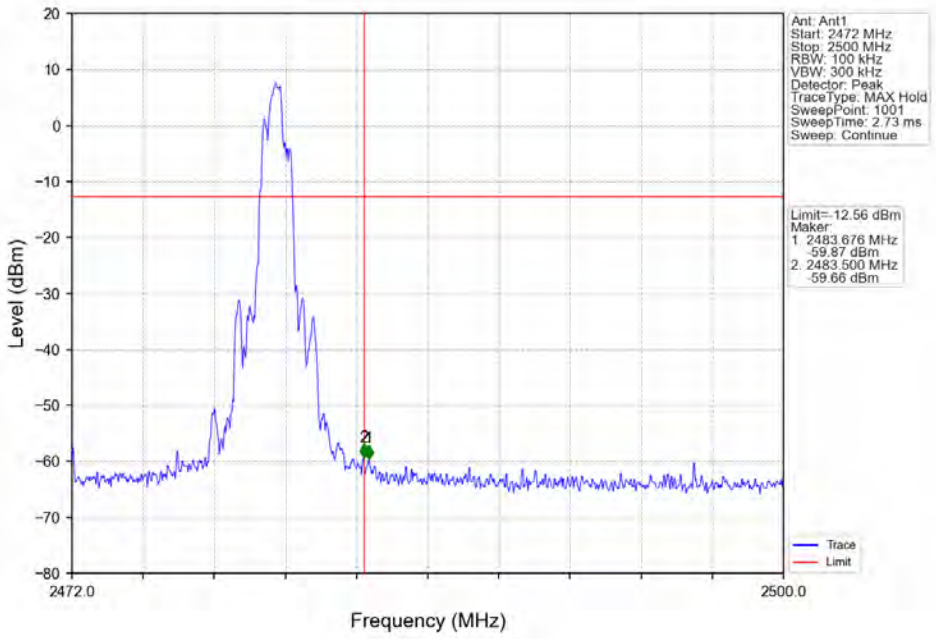
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_MCH_2441MHz_Ant1_NTNV



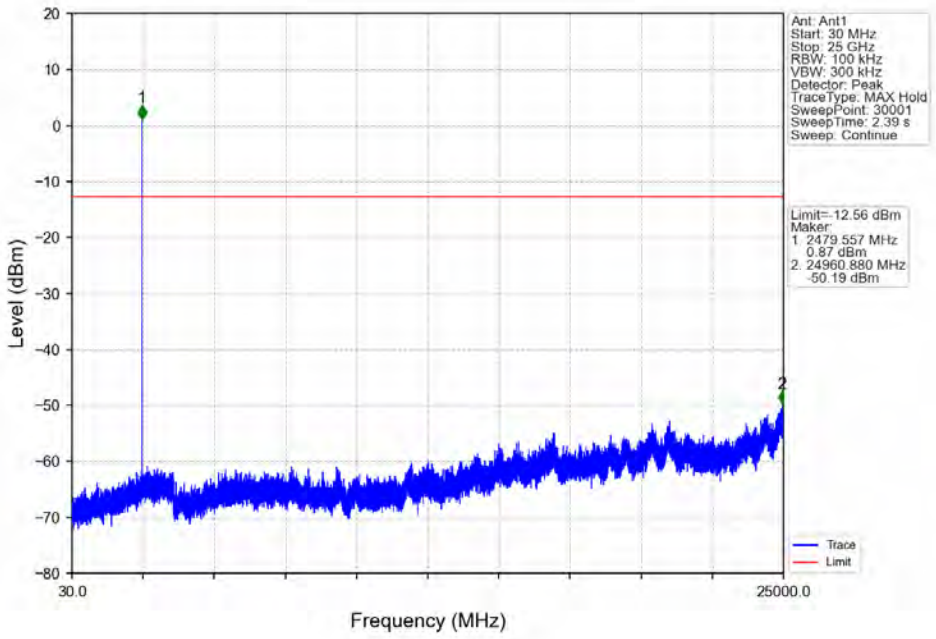
8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



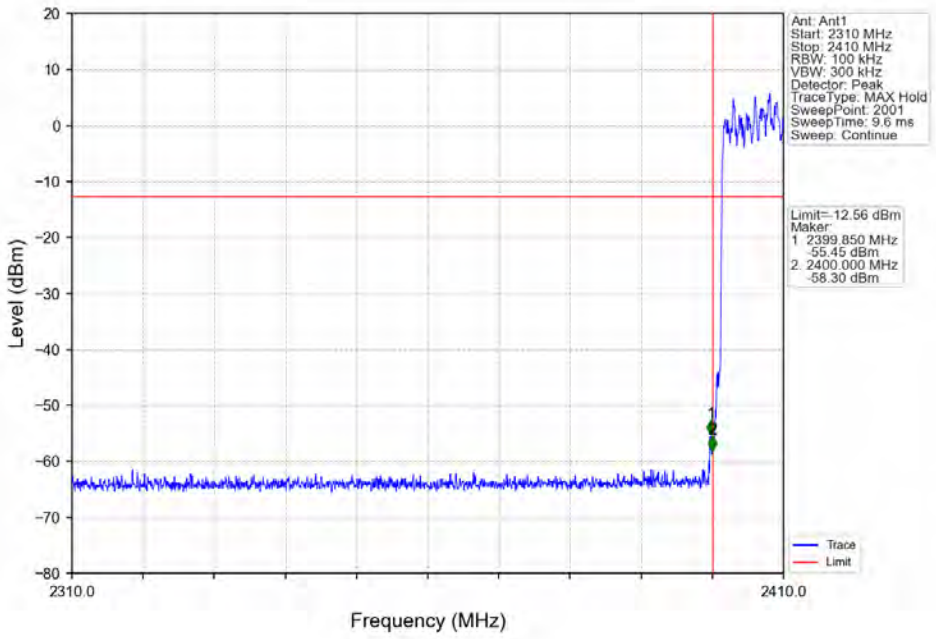
Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HCH_2480MHz_Ant1_NTNV



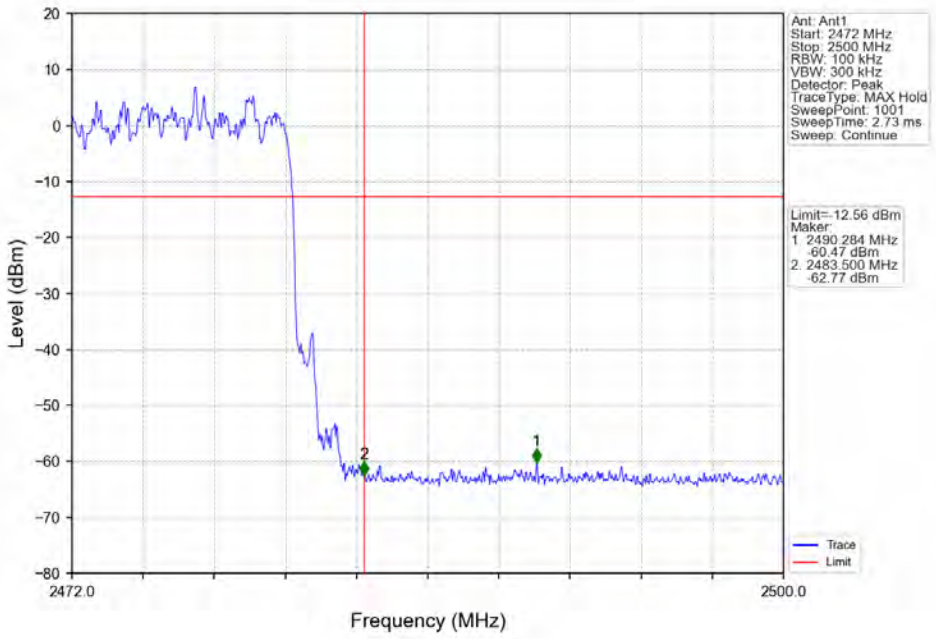
8DPSK_3DH5_HOPP_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

8DPSK_3DH5_HOPP_Ant1_NTNV



Total or partial reproduction of this document without permission of the Laboratory is not allowed.
BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

7. Form731

7.1 Form731

7.1.1 Test Result

Lower Freq (MHz)	High Freq (MHz)	MAX Power (W)	MAX Power (dBm)
2402	2480	0.0056	7.48

Total or partial reproduction of this document without permission of the Laboratory is not allowed.

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

BTF Testing Lab (Shenzhen) Co., Ltd.

F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

www.btf-lab.com

-- END OF REPORT --

Total or partial reproduction of this document without permission of the Laboratory is not allowed.